

A scanning electron micrograph (SEM) showing the fabrication of a superconducting quantum sensor. Two gold-colored micro-manipulators with sharp tips are positioned over a dark, patterned substrate. A bright, circular light spot is centered on the substrate, highlighting the area where the sensor is being fabricated. The substrate has a grid of small, dark rectangular features.

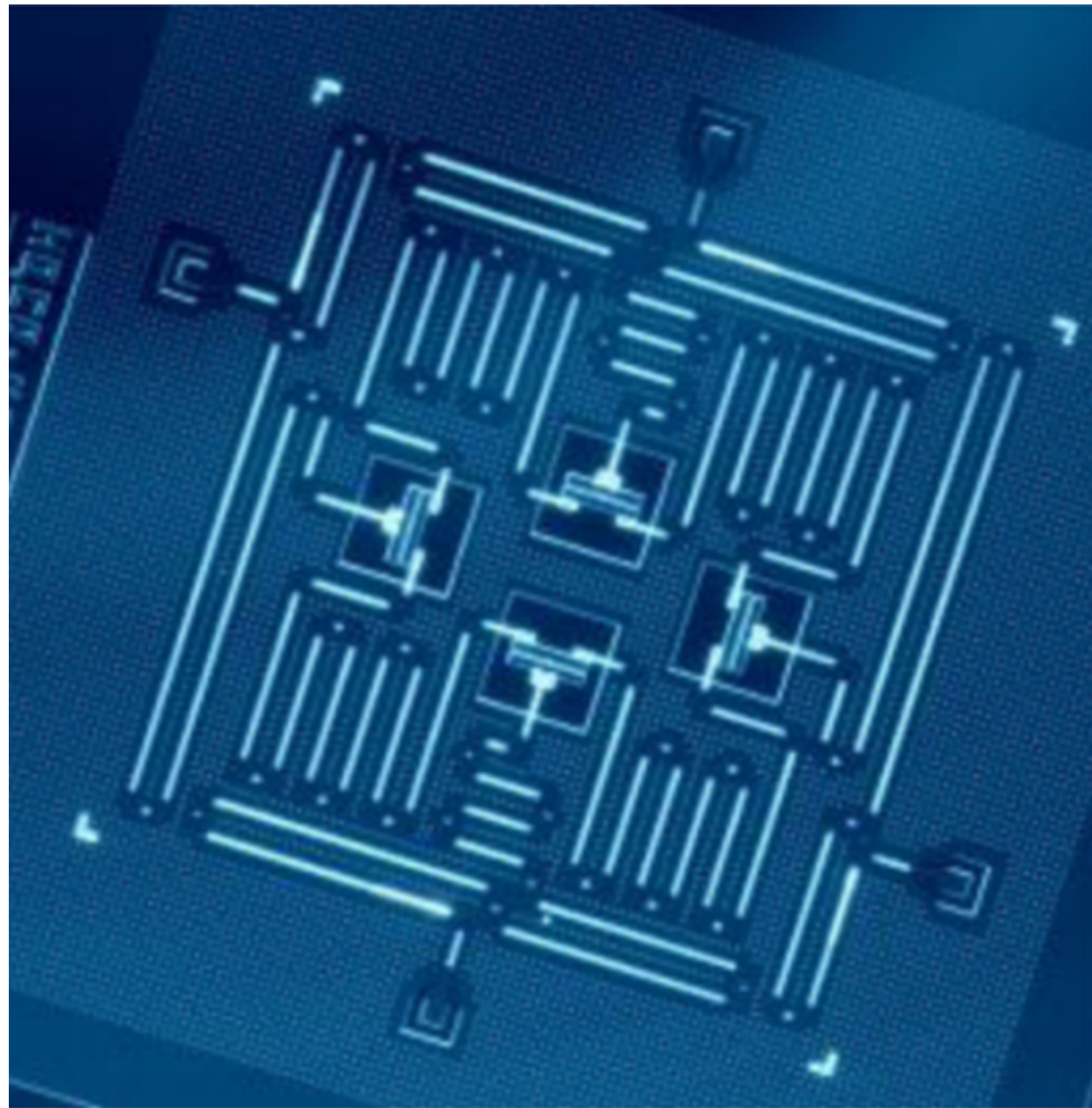
Fabrication of Superconducting Quantum Sensor

@KMI School 2024
Nagoya University/KMI

March 7th 2024
University of Tokyo/ICEPP
Tatsumi Nitta

Why superconducting qubits?

Superconducting Quantum Computer



- Large electric coupling
 - $10^6 \times$ atom
- Long coherence time
 - $O(100) \mu s$ or more
- non-demolition readout
- Low noise environment
 - mK temperature
 - EM/Magnetic shields

Quantum sensor

- Very sensitive to weak EM field
- Easy to do manipulate
- Drastically decrease uncertainty
- Low dark count

Superconducting qubit must be suitable as a sensor

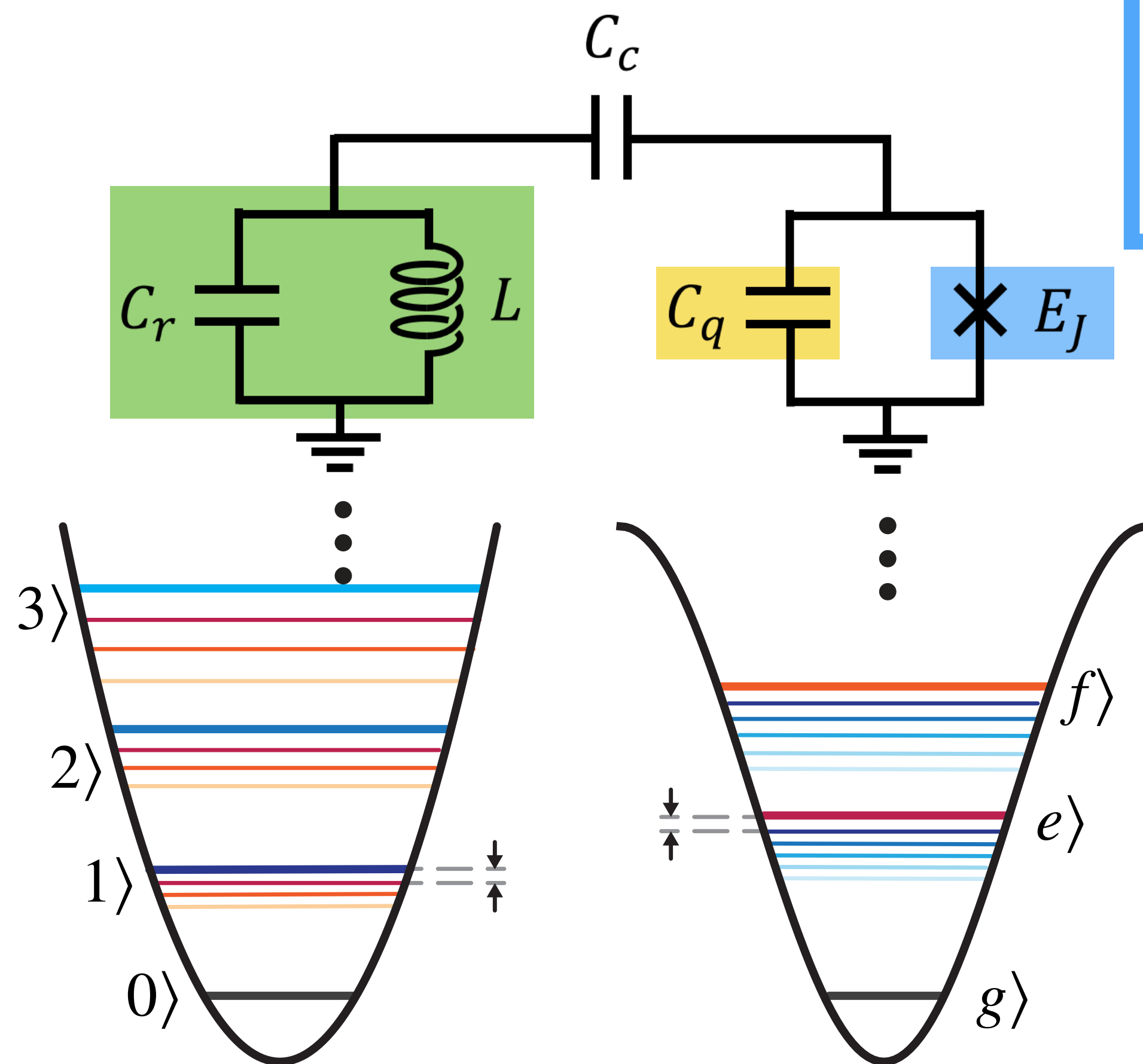
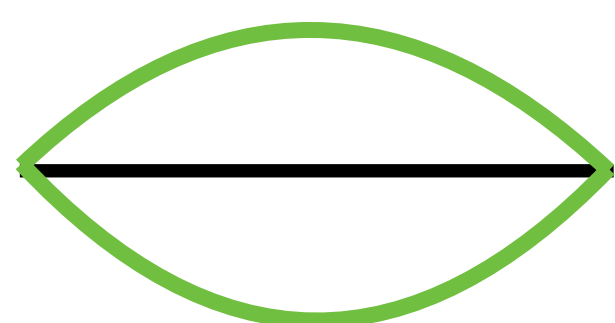
A qubit in a nutshell

Resonator

3D (cavity)

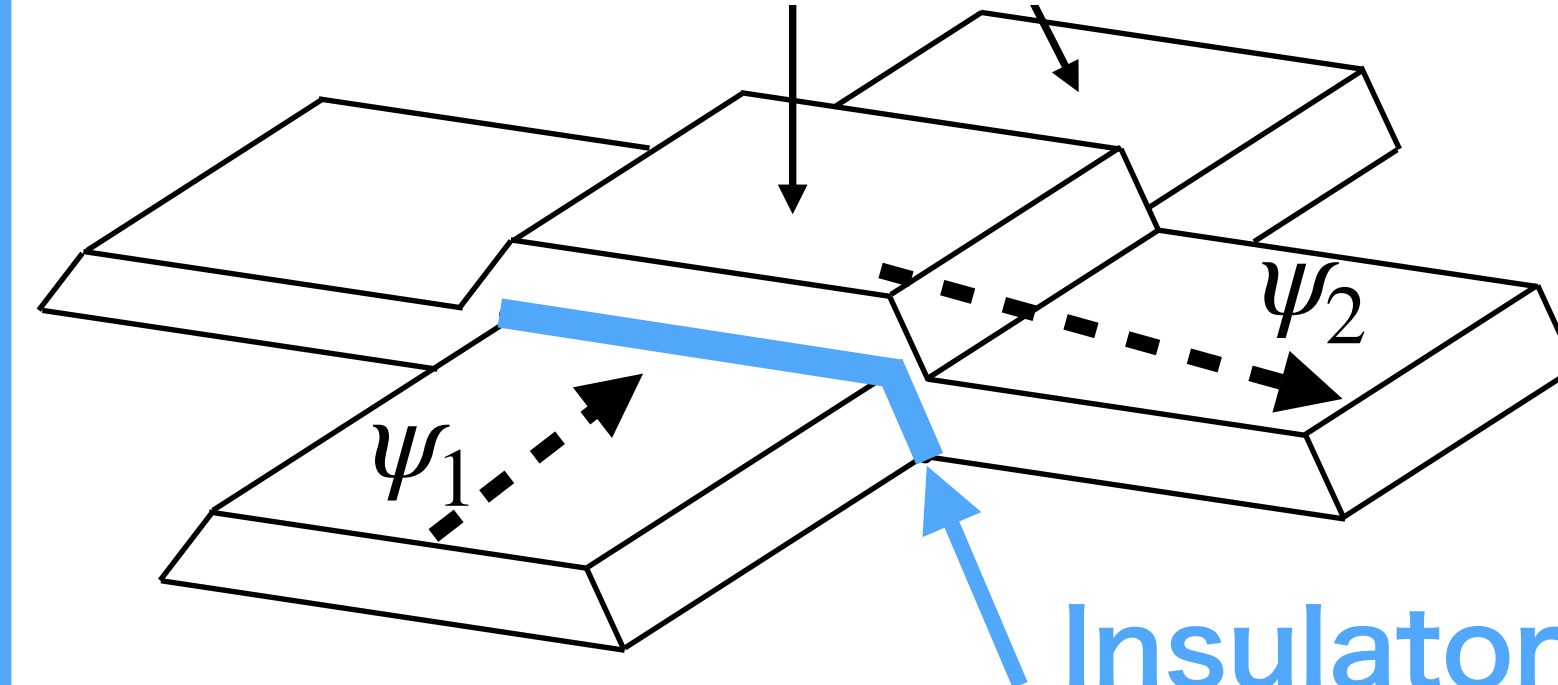


2D



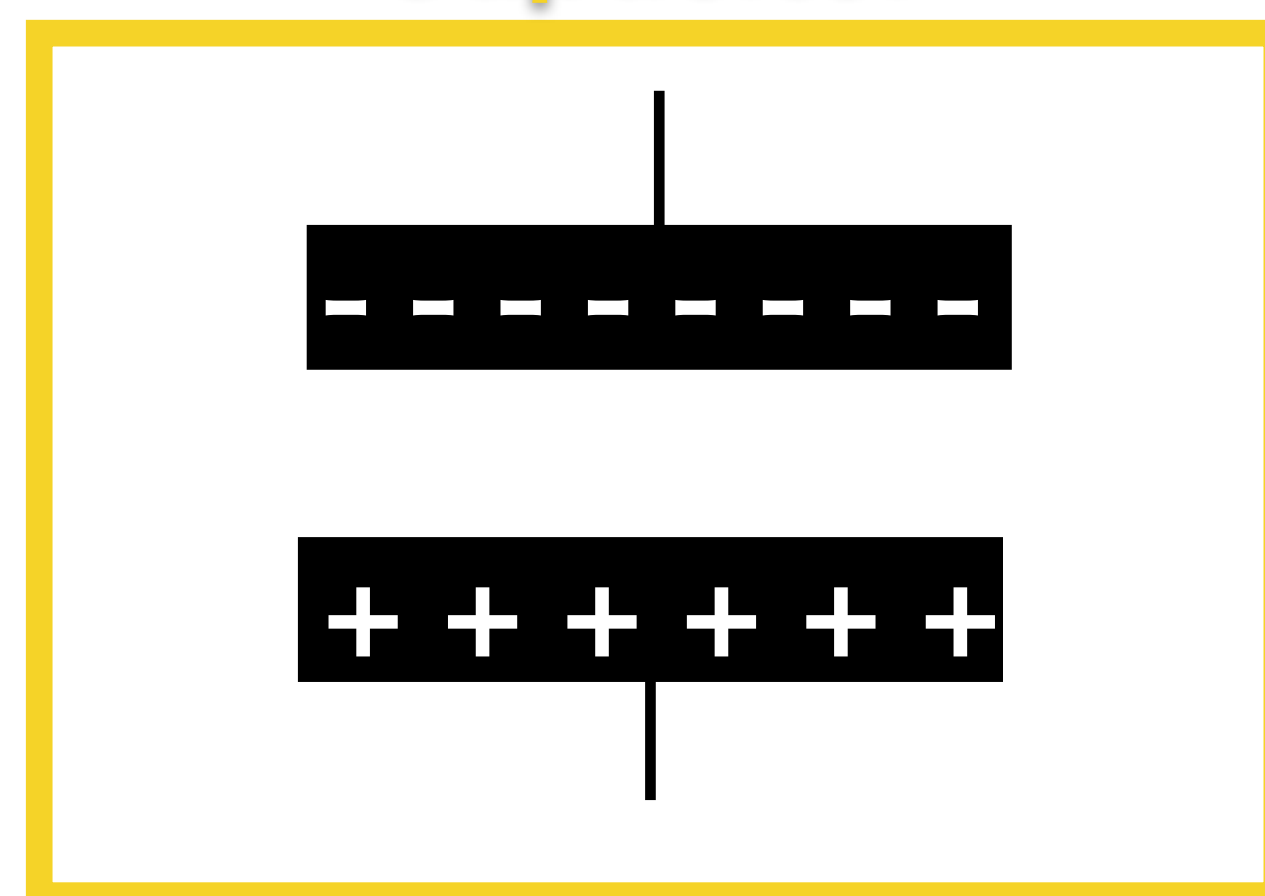
$$\mathcal{H} = \frac{\hbar}{2} \left(\omega_q + \frac{g^2}{\Delta} \right) \sigma_z + \hbar \left(\omega_c + \frac{g^2}{\Delta} \sigma_z \right) a^\dagger a$$

Superconductor

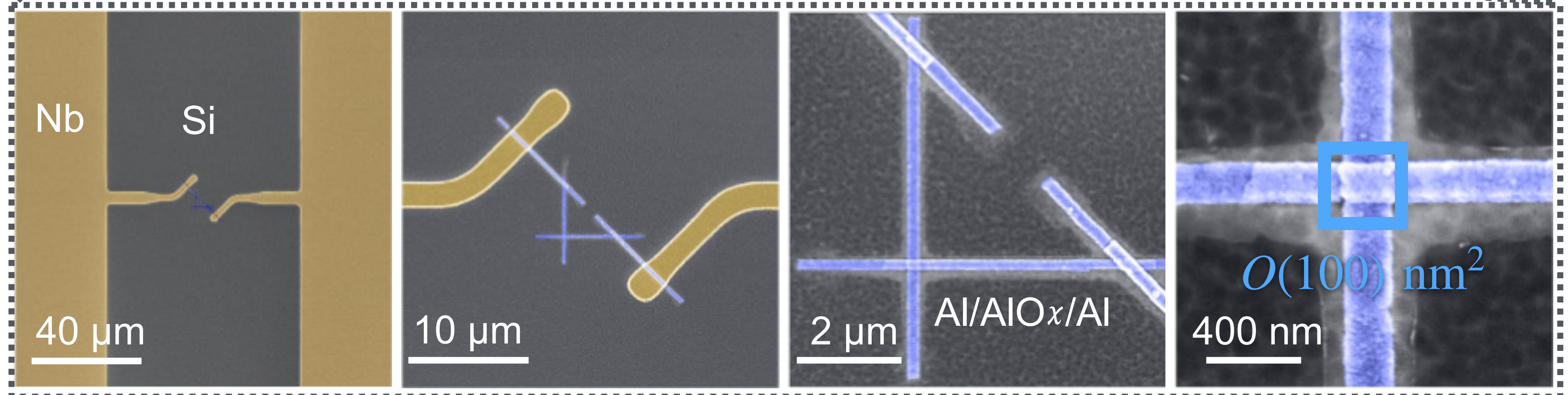
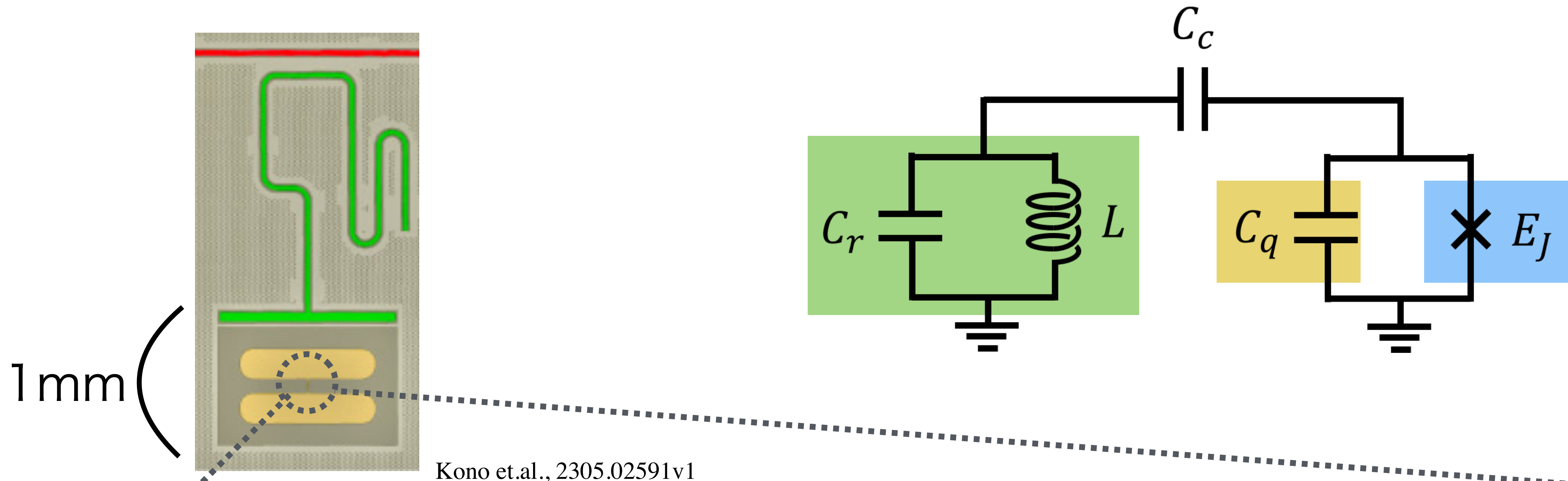


Josephson Junction (JJ)

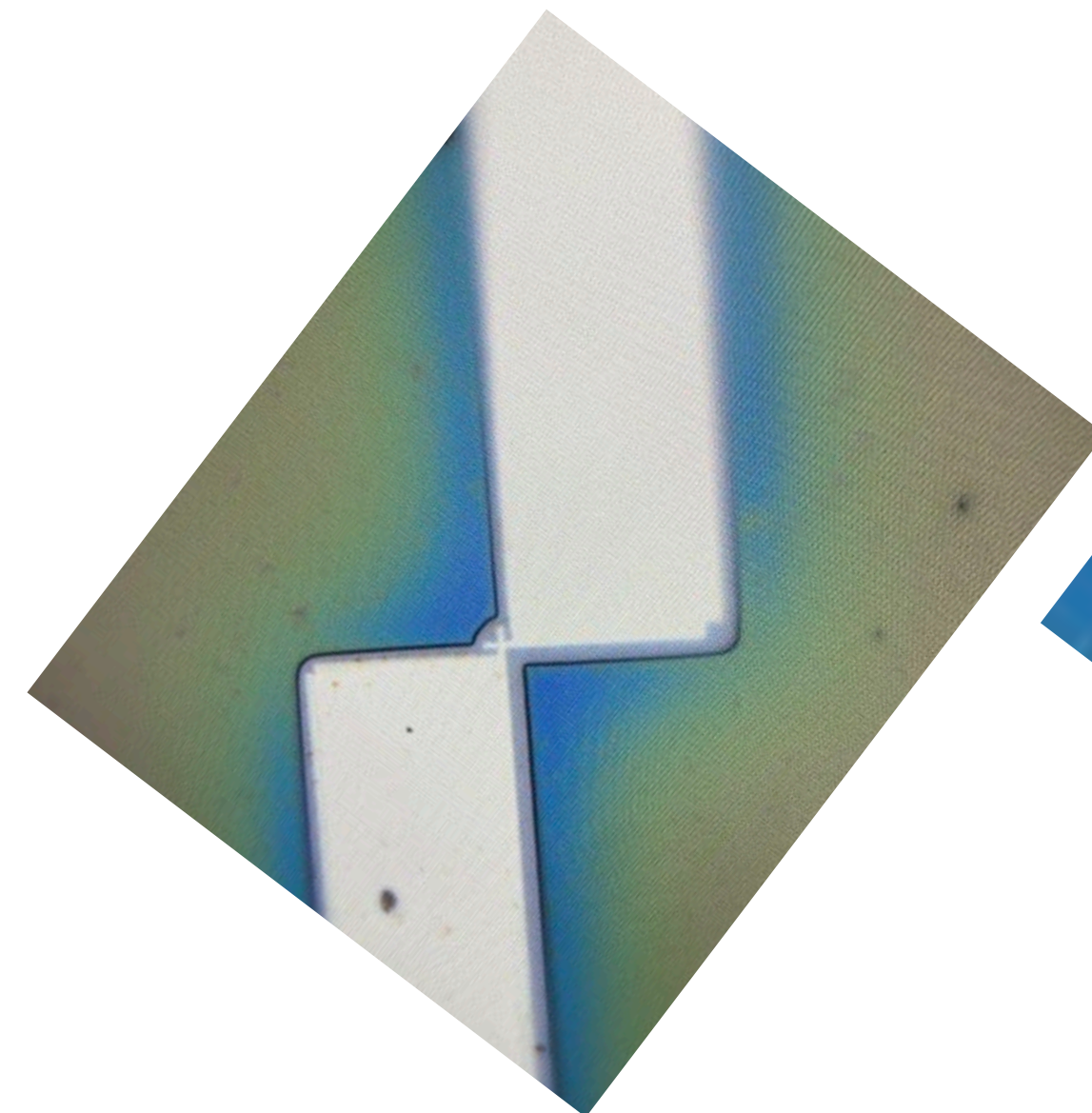
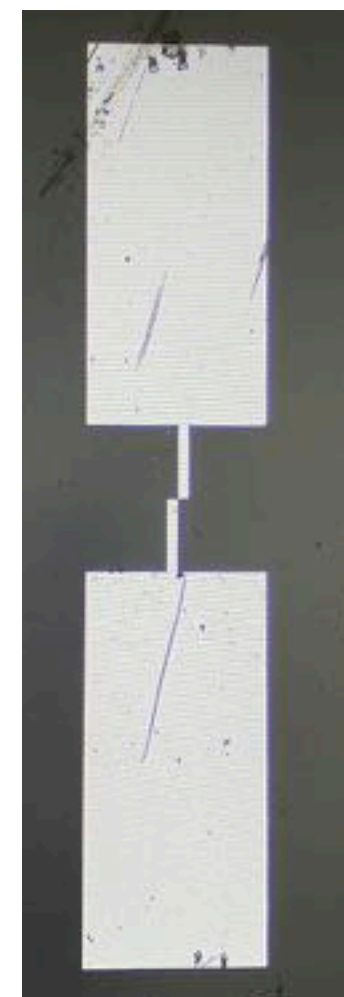
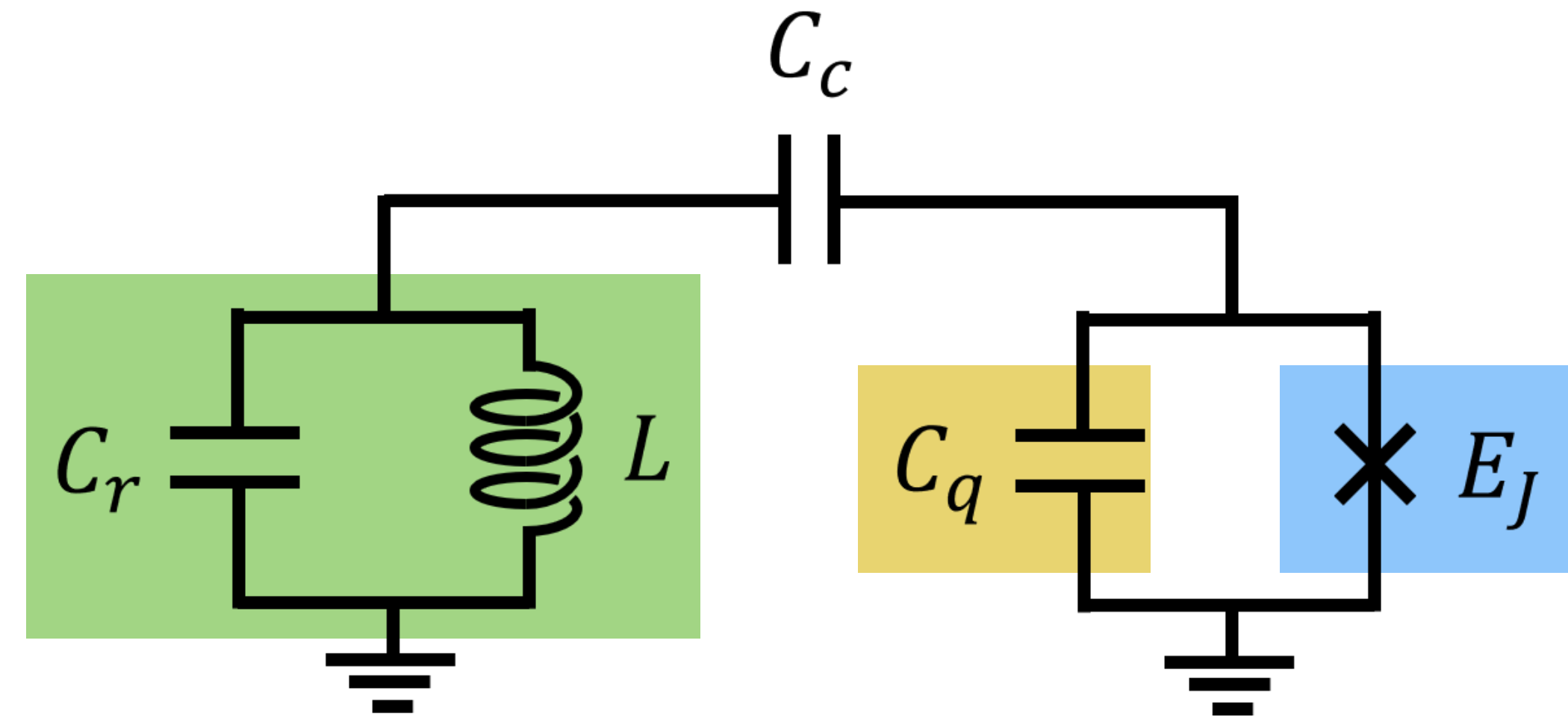
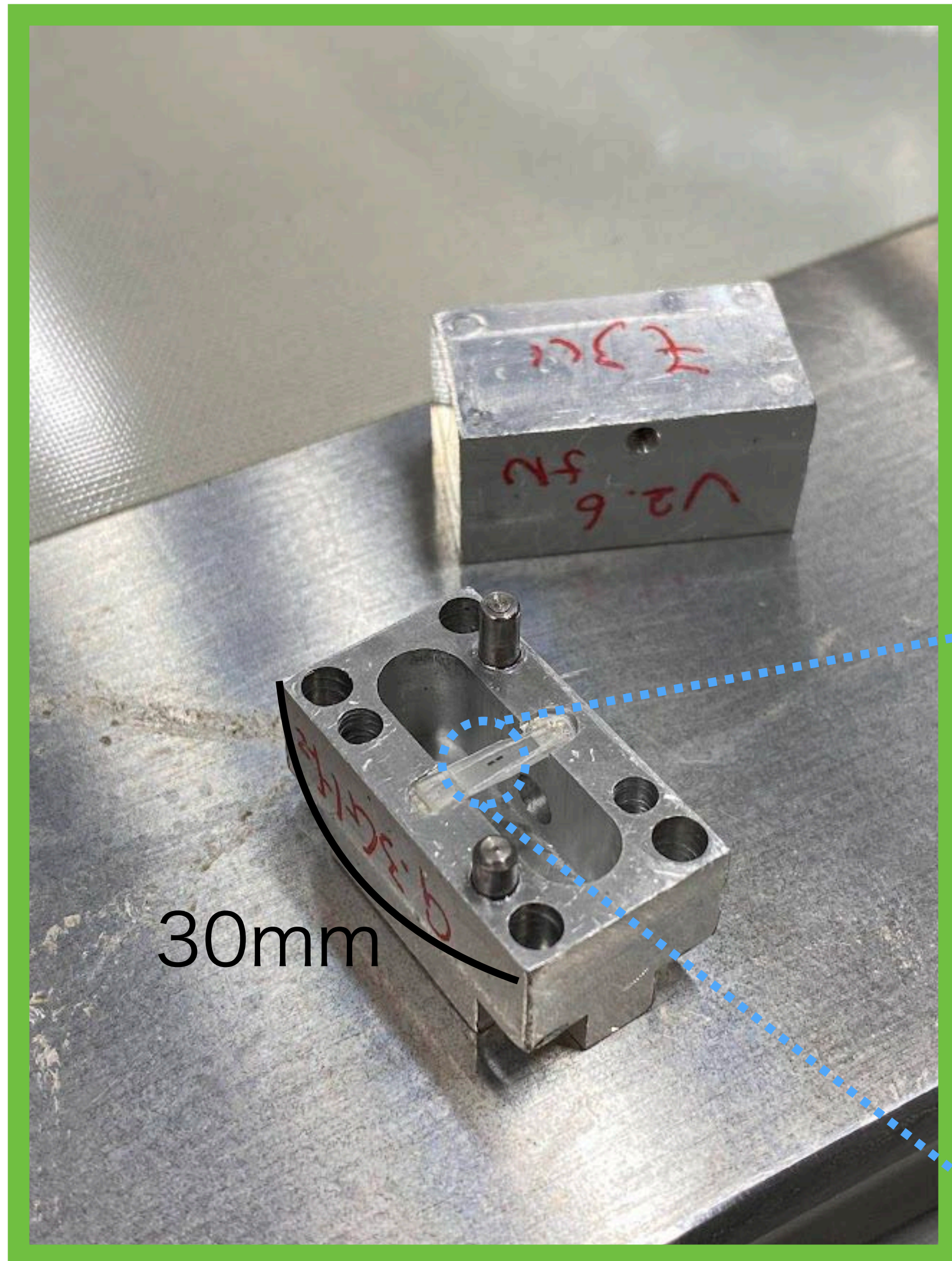
Capacitor



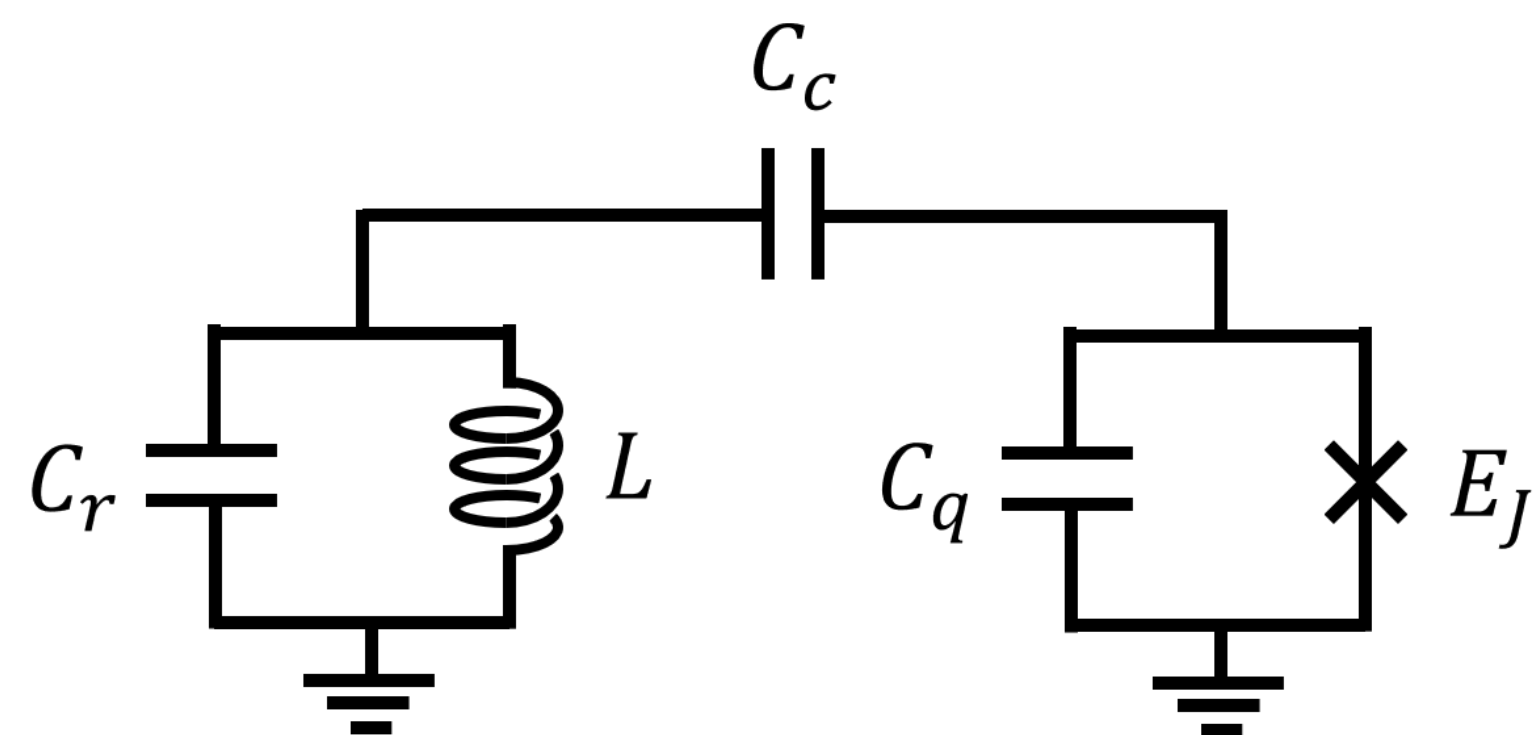
Physical design (2D Resonator)



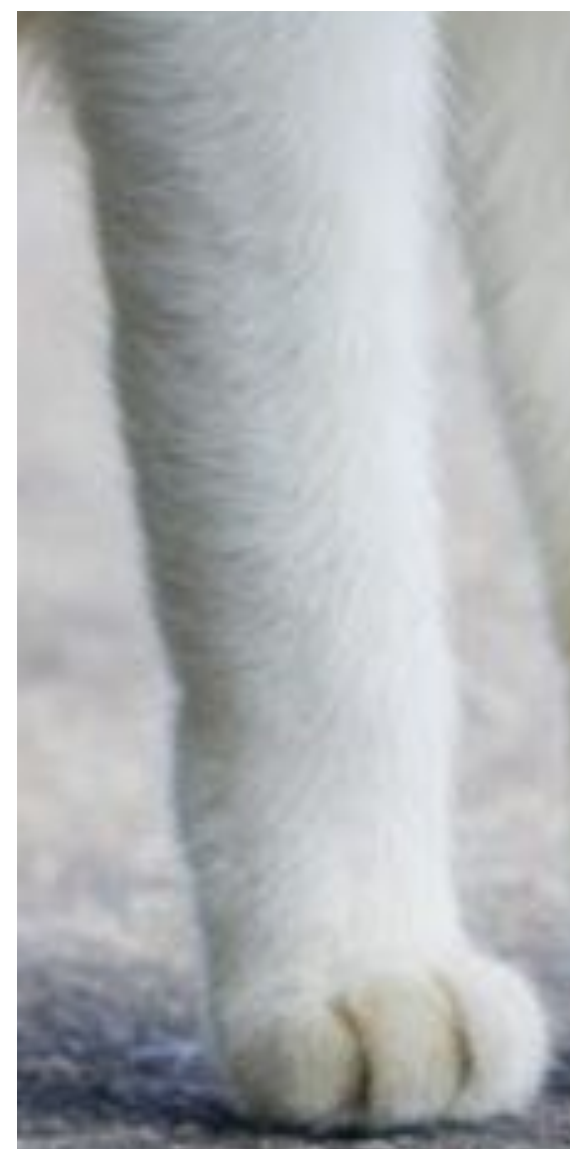
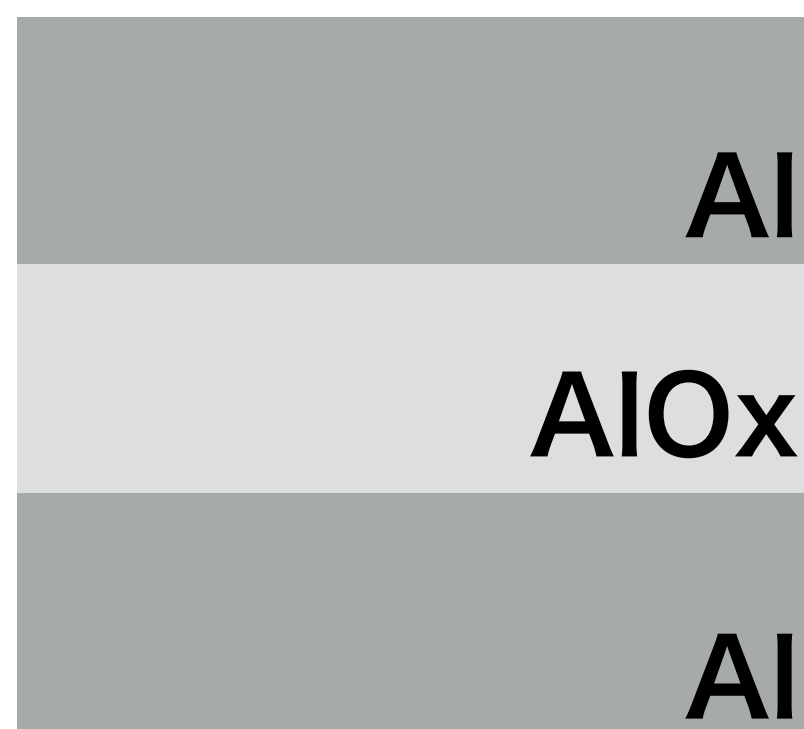
Physical design (3D Resonator)



Good qubit ~ Clean qubit



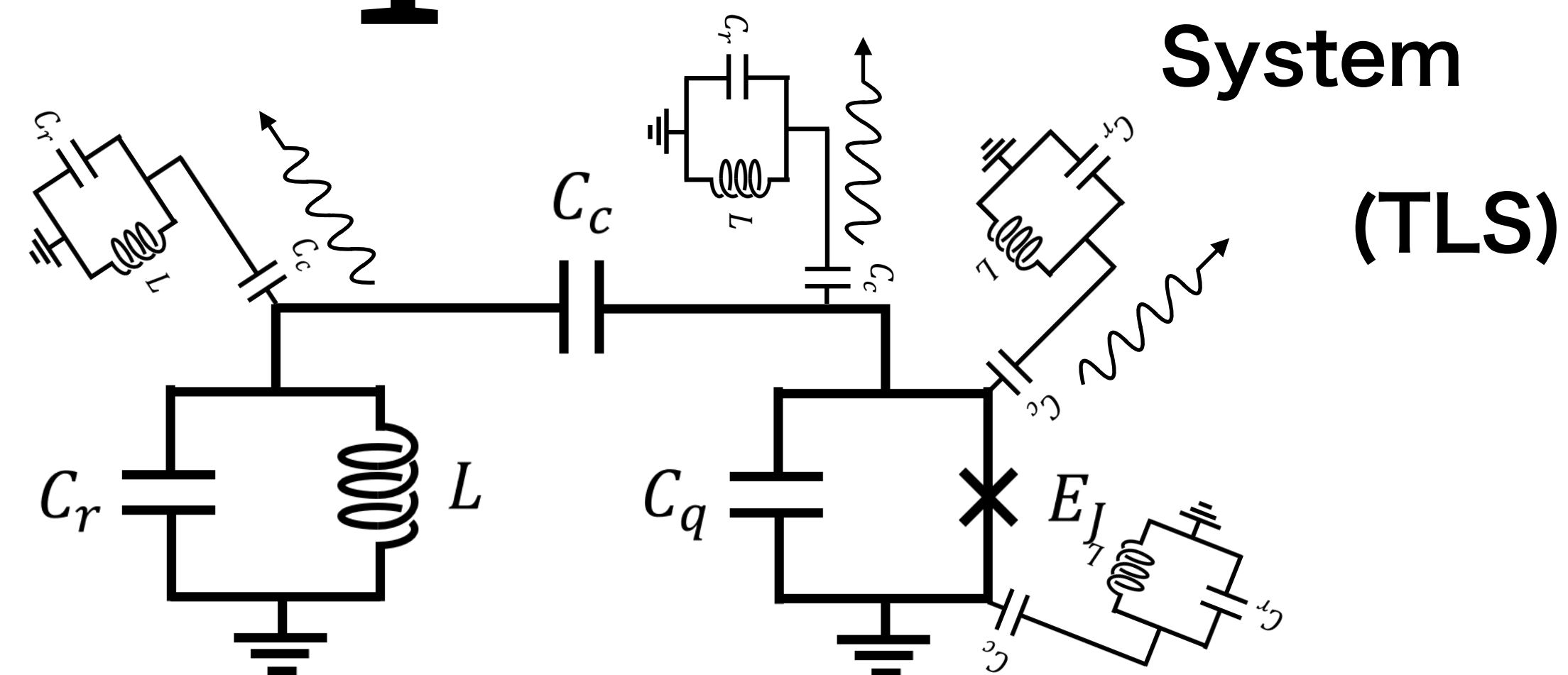
Cross-section
of JJ



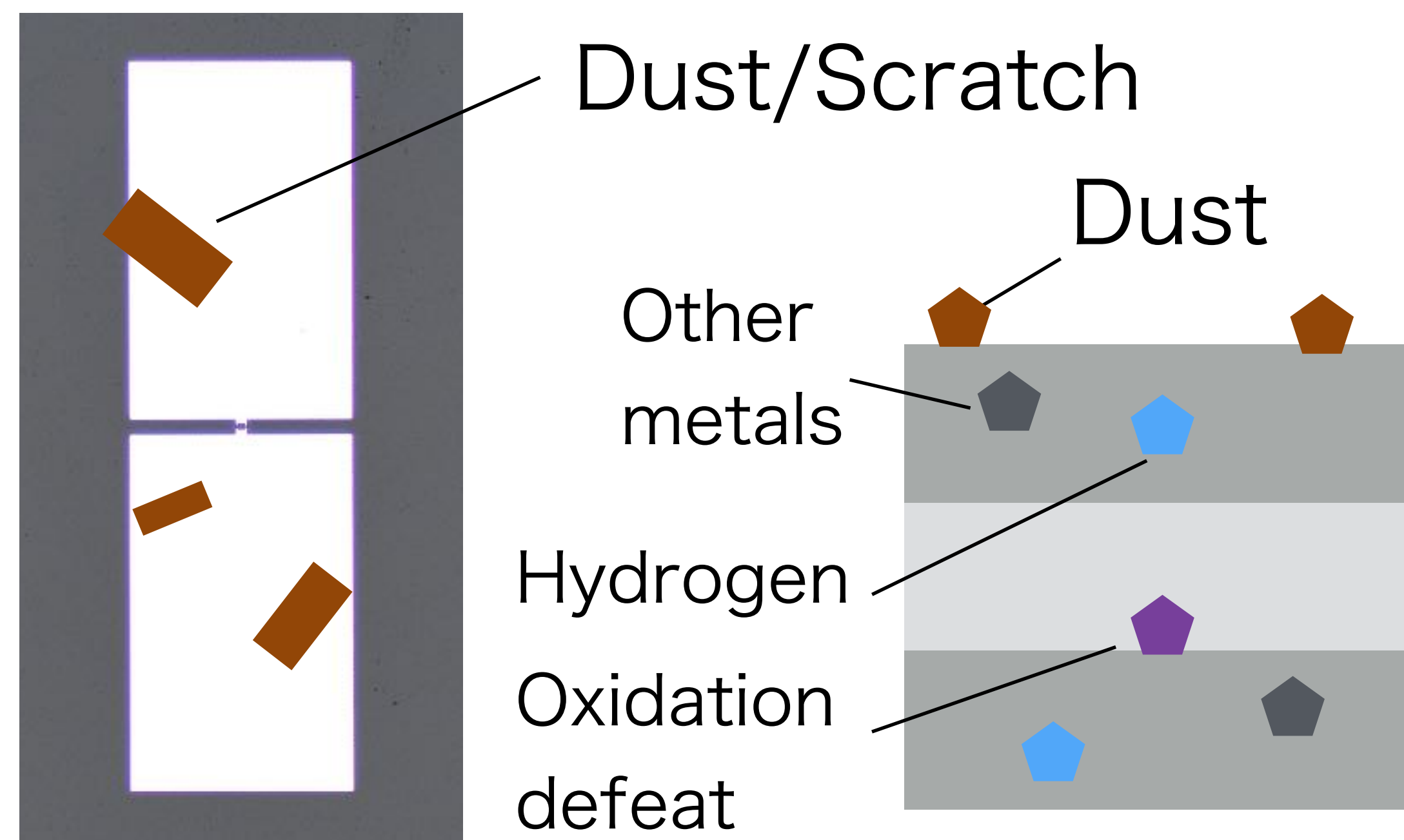
Dust
O (10) um



JJ
O (100) nm



Two Level
System
(TLS)



What environment you need?

Clean room



ISO Class 5 is fine
($<30 \times 5 \text{ um dusts/m}^3$)

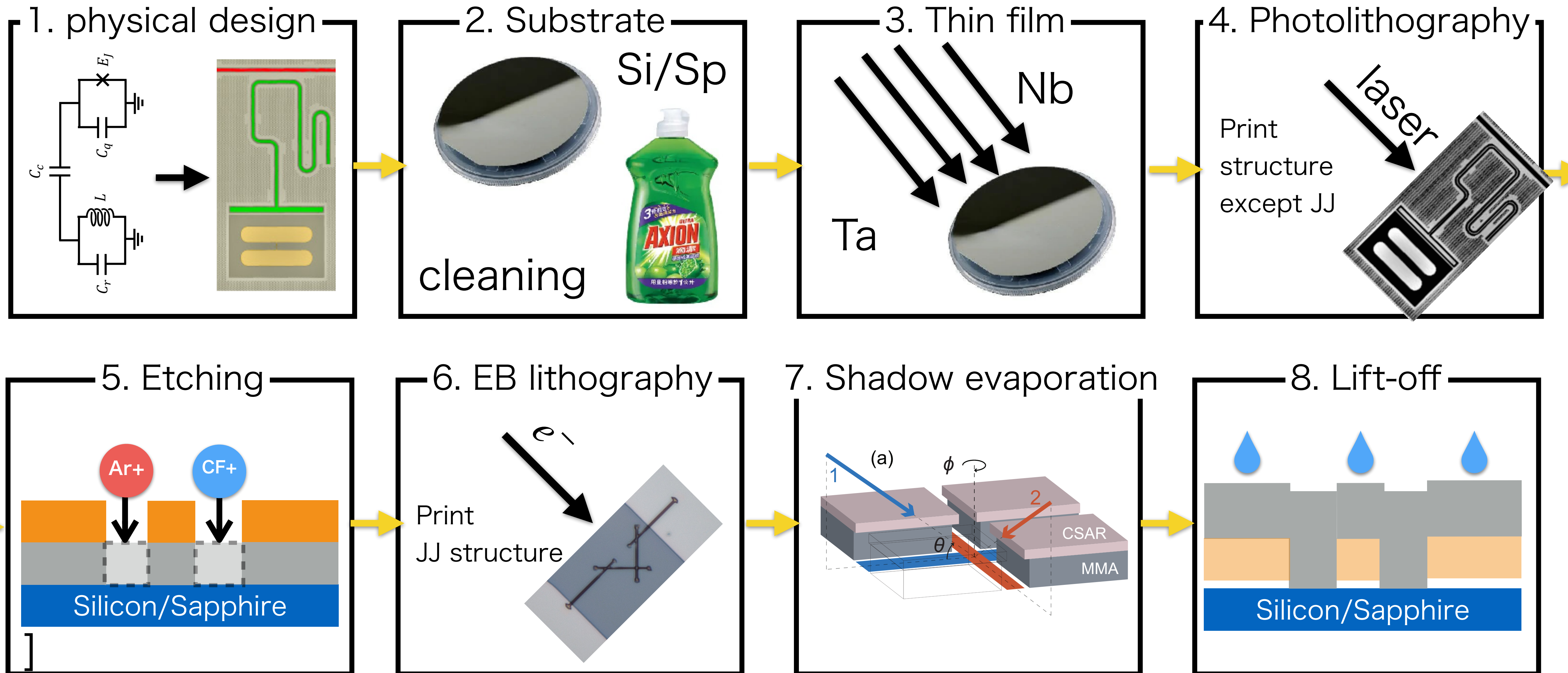
Equipments

- Sputter
- EB evaporator
- Chemical draft
- Photolithography
- EB lithography
- Plasma etcher etc...

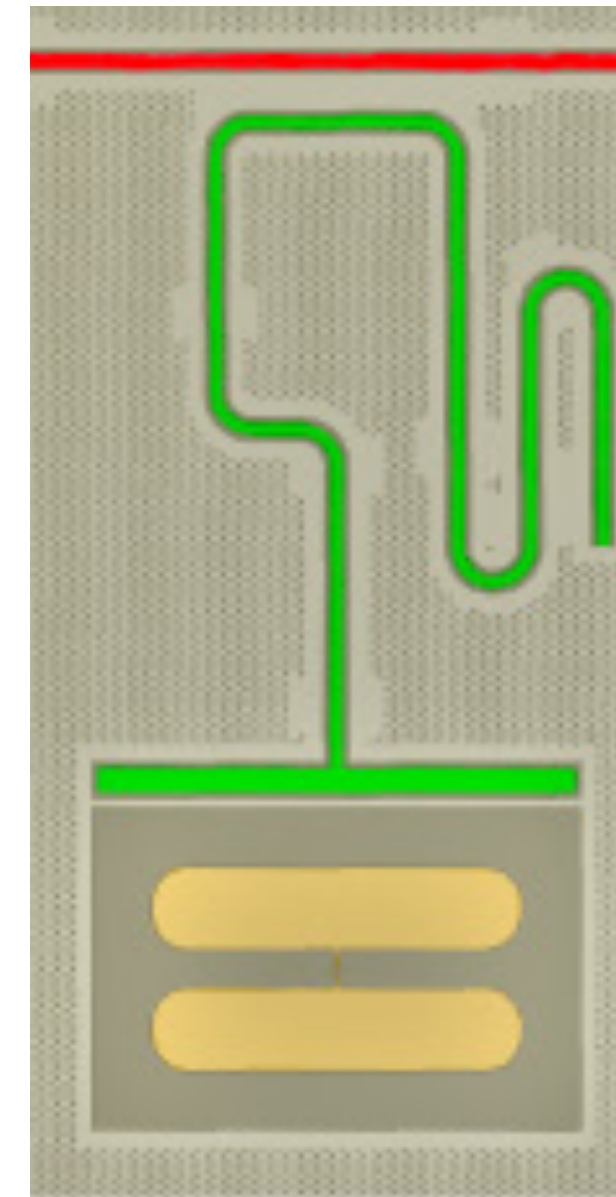
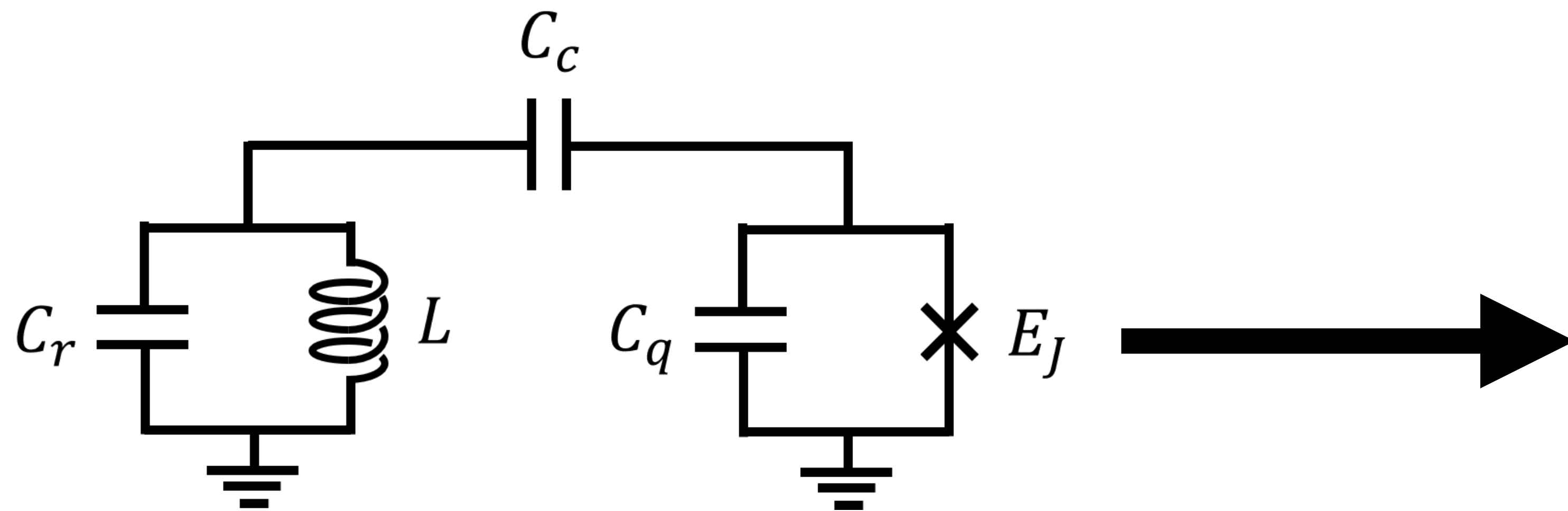
Deposition in high vacuum

$< 10^{-8} \text{ Pa}$ seems very important

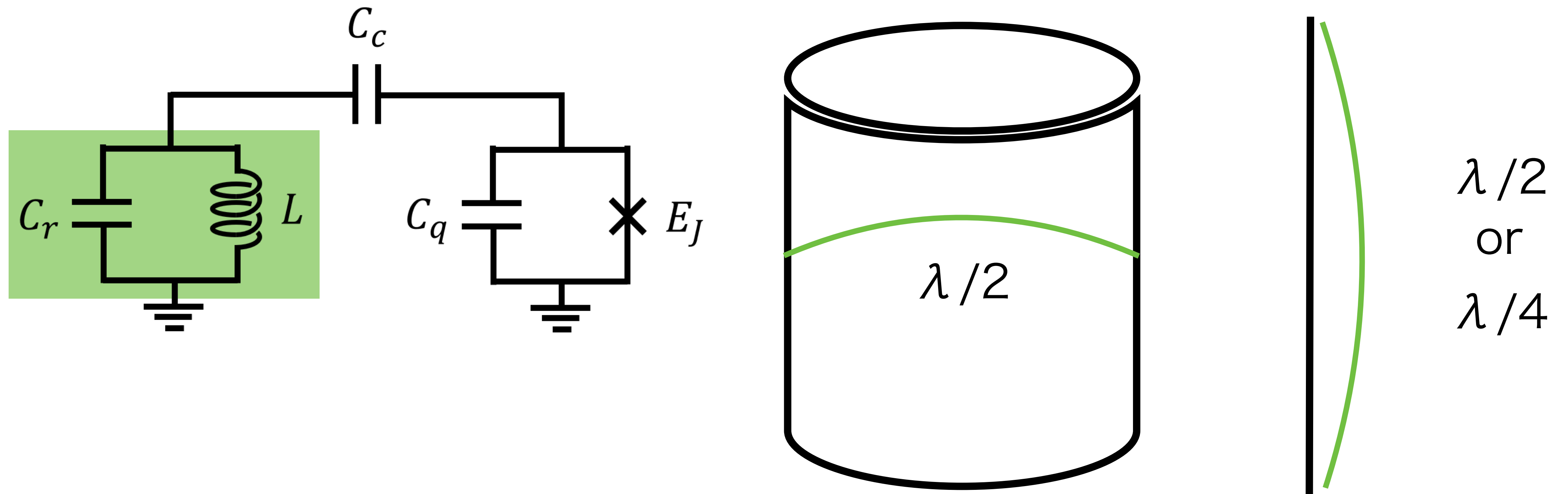
Standard Fabrication Process



1. Design



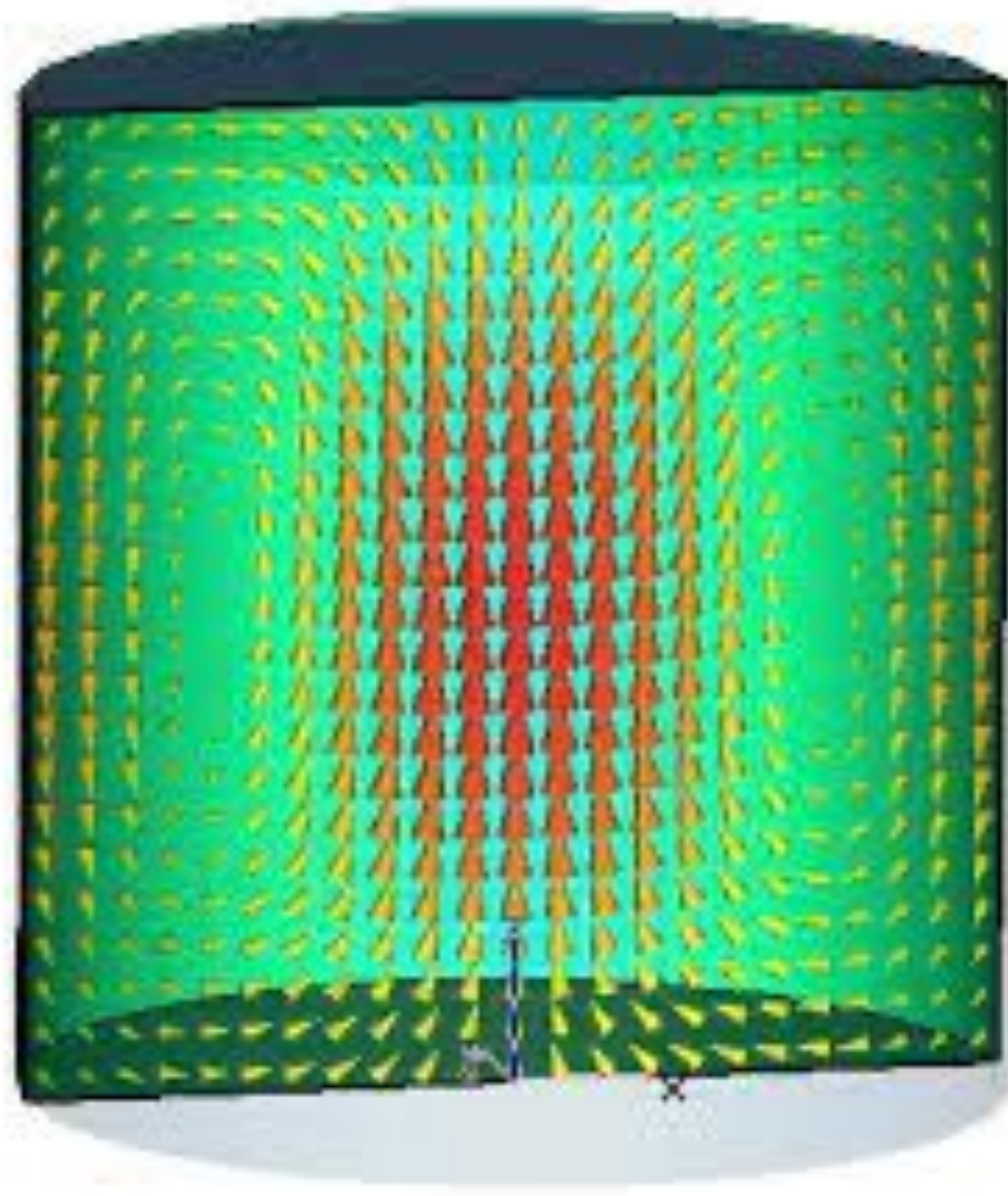
1. Design: Resonator



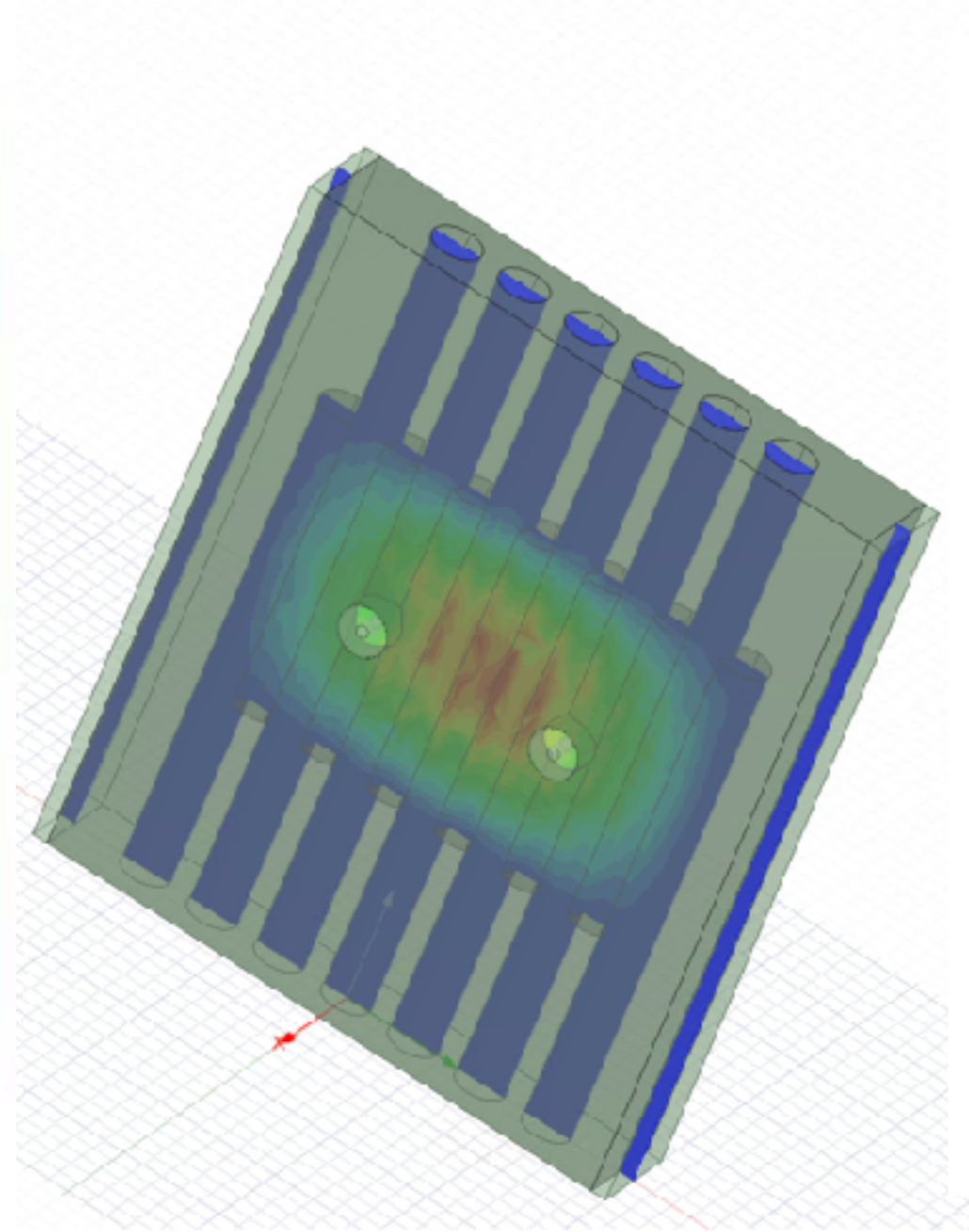
1. Design: Resonator

Detailed design is needed dedicated simulation.

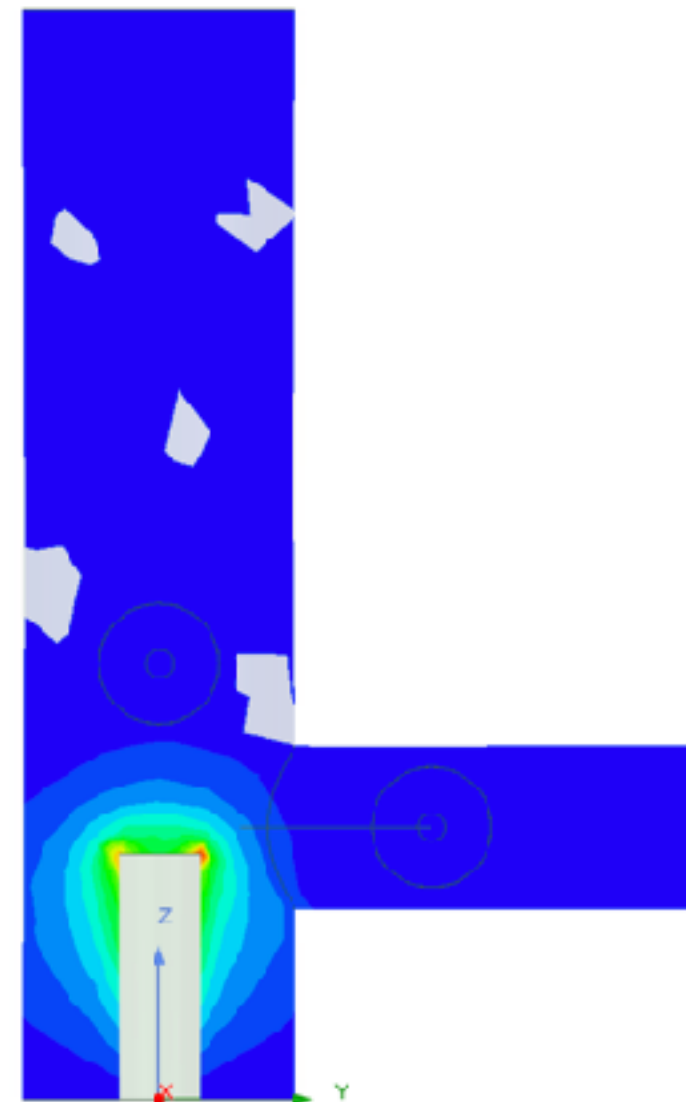
Cylinder



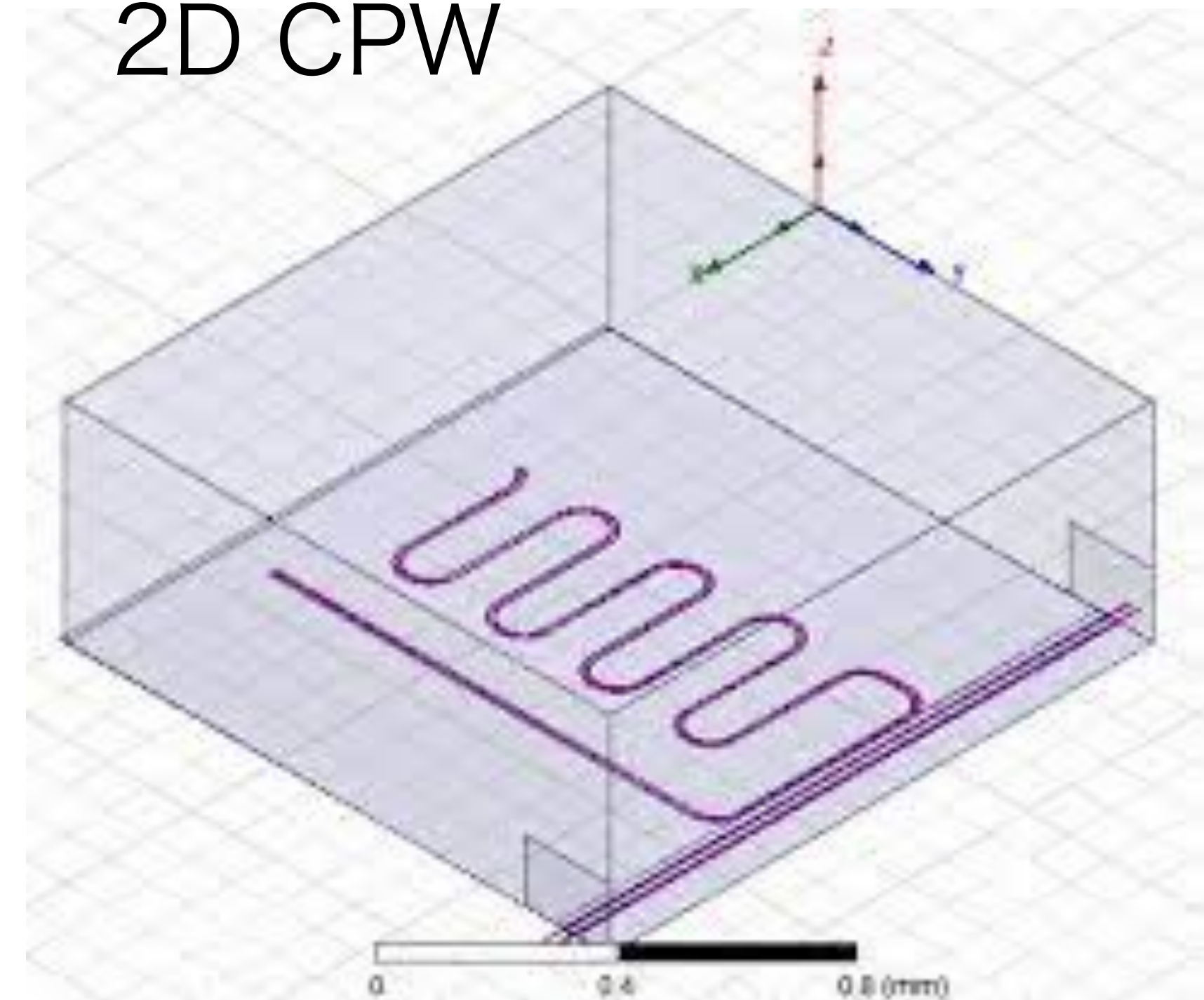
Flute



Coaxial

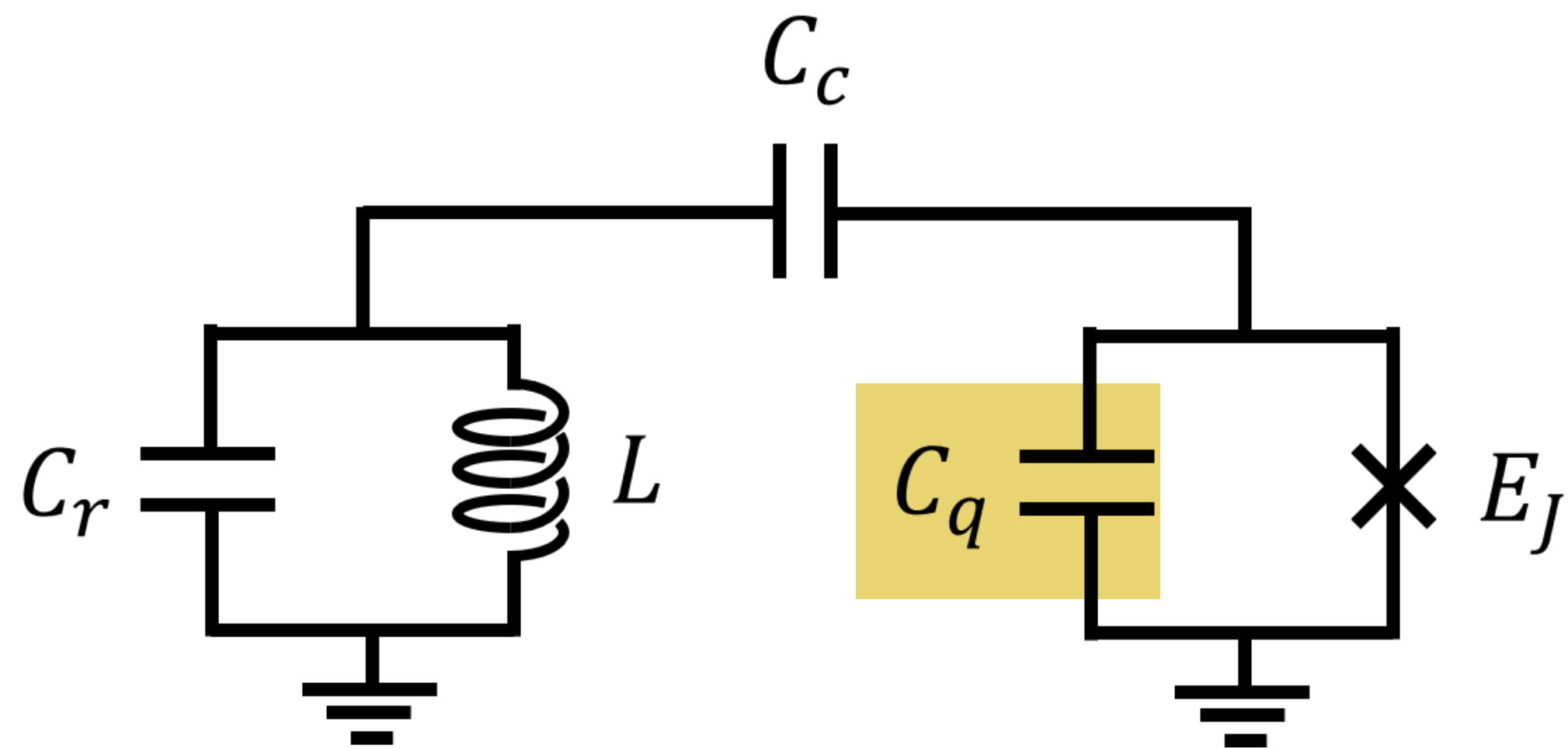


2D CPW

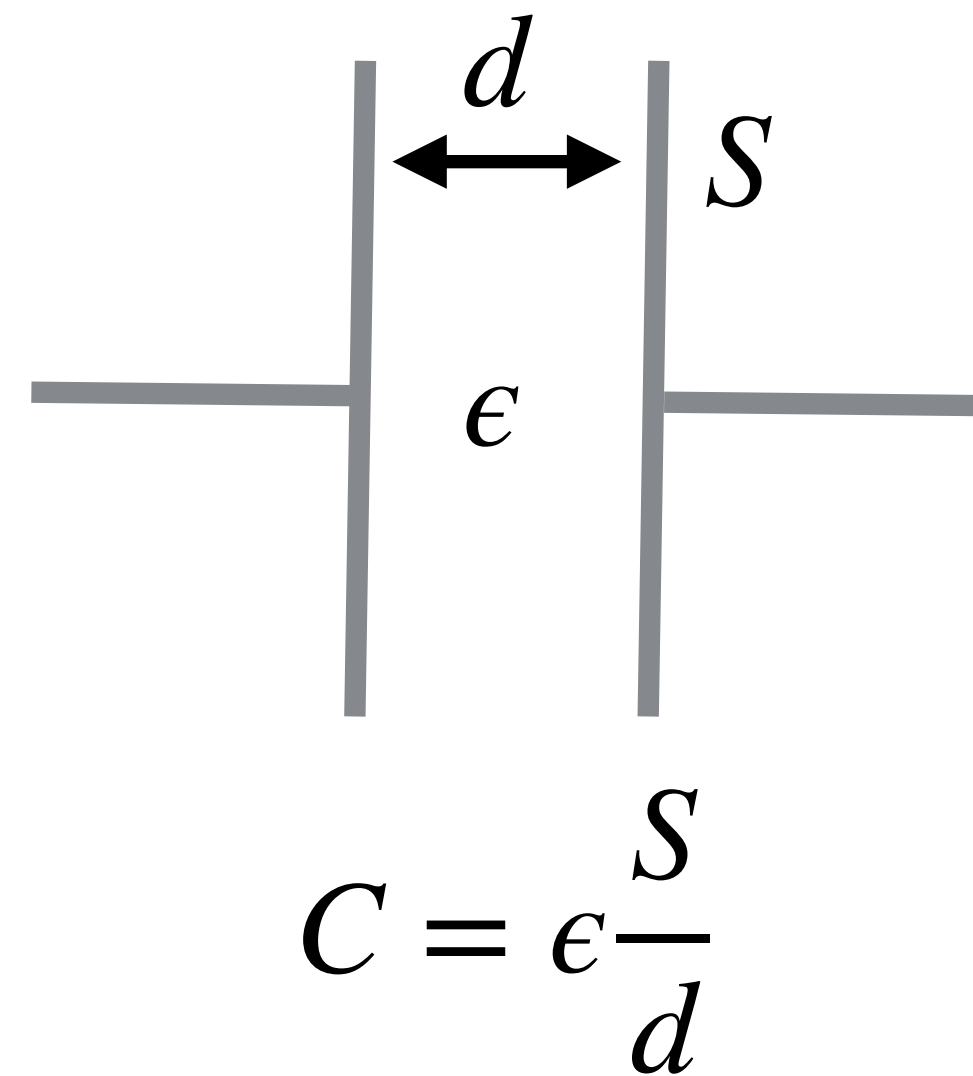


Simulation on finite element method are generally used.
ex: Ansys HFSS, Comsol multiphysics

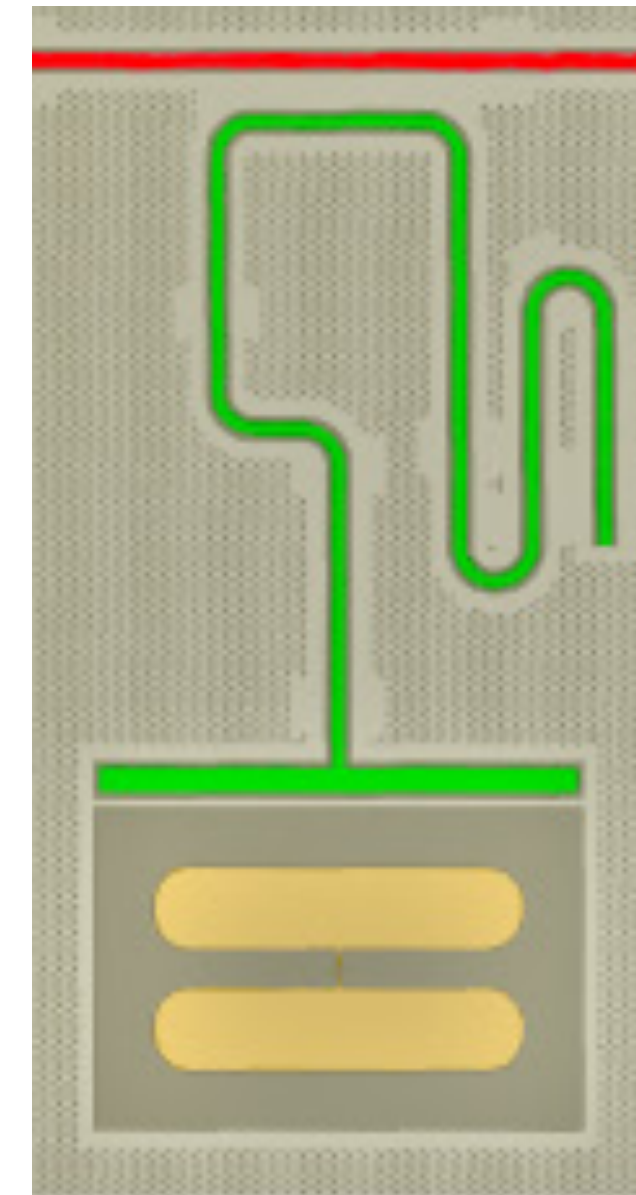
1. Design: Capacitor



Simplest case

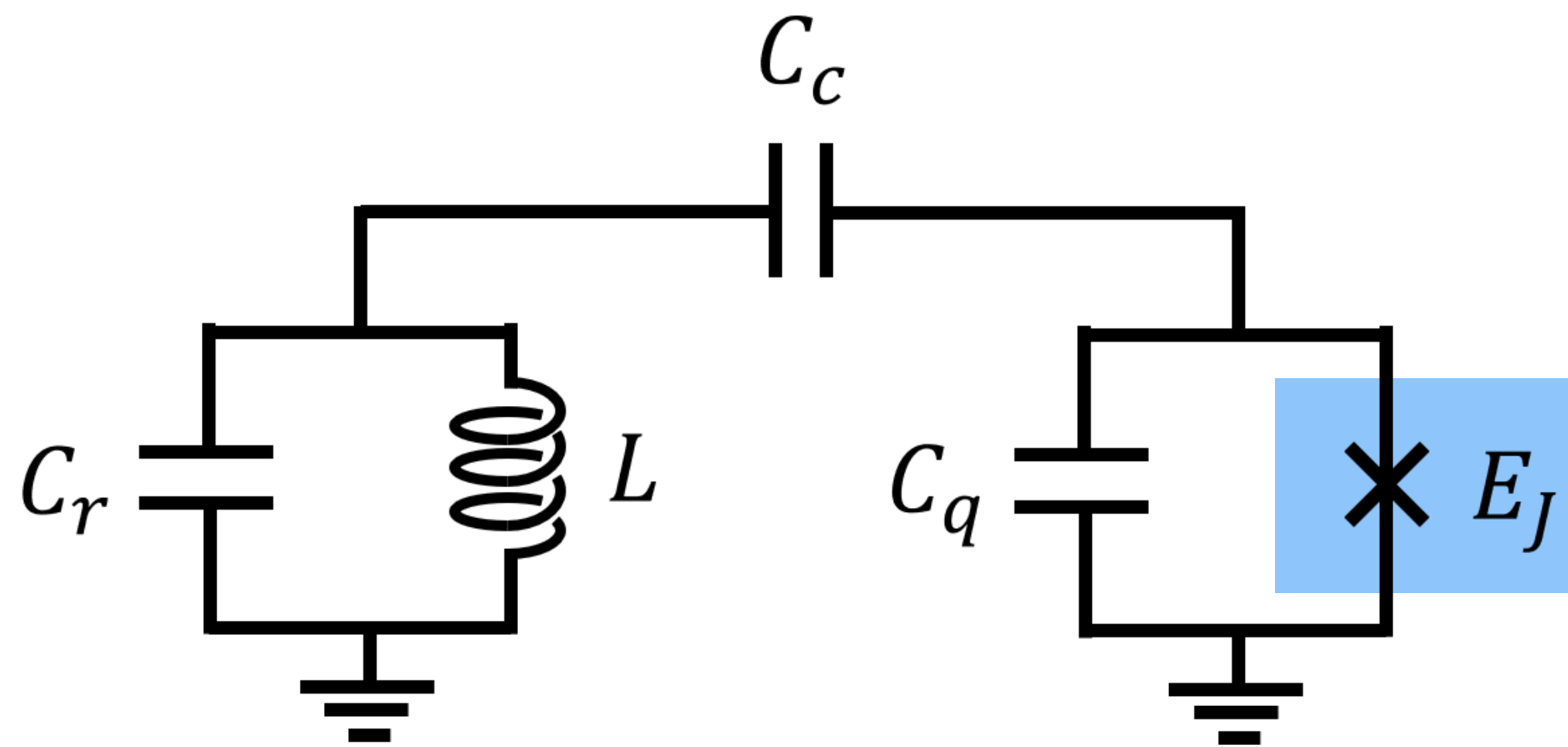


Reality



To know actual capacitance of the circuit, dedicated FEM simulation is necessary.

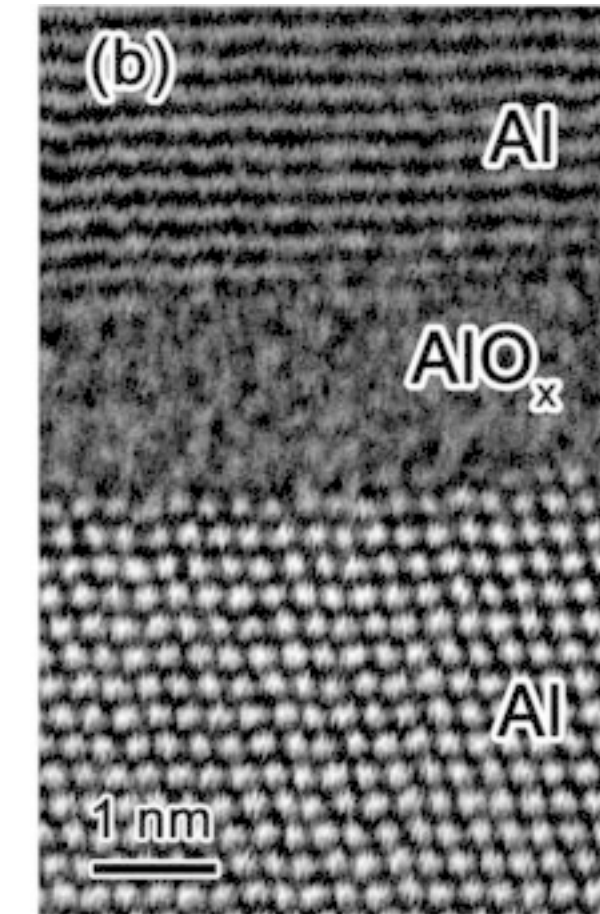
1. Design: Josephson Junction



PhysRevLett.11.104

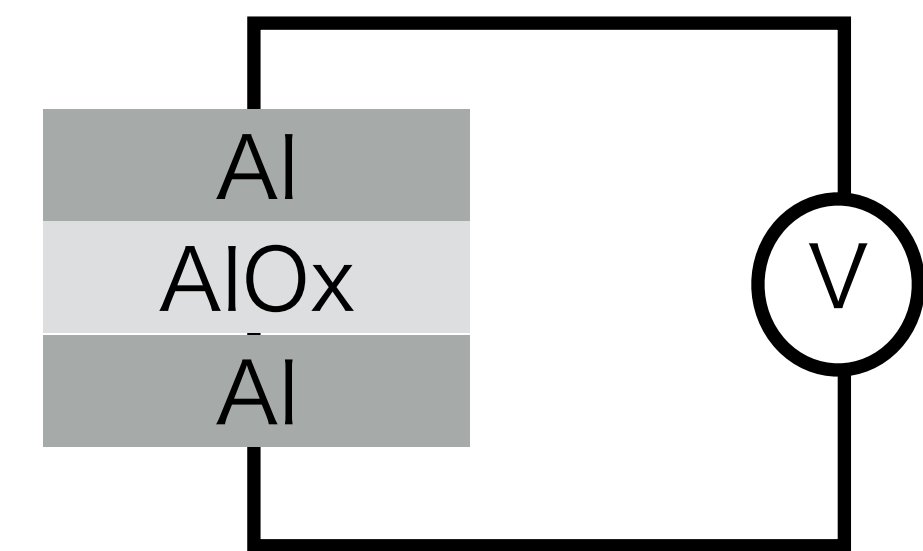
from Ambegaokar-Baratoff formula

$$E_J \sim \frac{\hbar \pi \Delta_{sc}}{4e^2 R} \quad \rightarrow E_J \text{ can be designed by AlOx resistance } (R) \text{ at 0K}$$



In reality, controlling R is not easy.

People do try and error at their environment

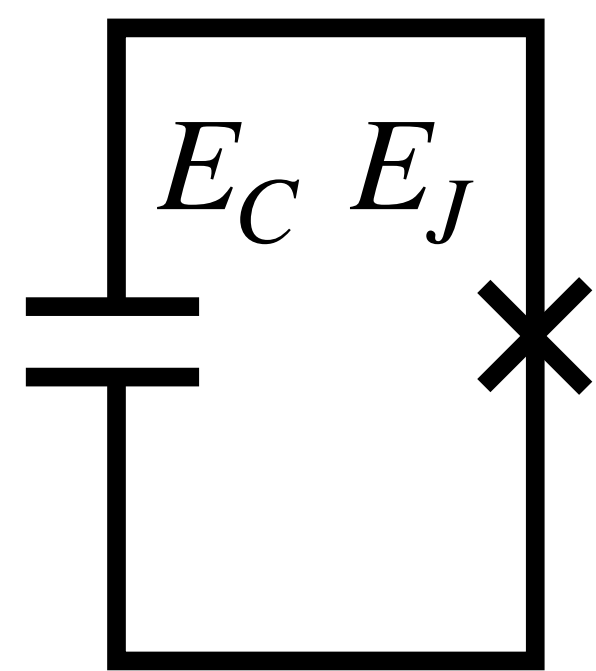


Mostly the size is the order of $\underline{O(100) \times O(100) \times O(1) \text{ nm}}$

thickness of AlOx

1. Design: Advanced Designs

Charge qubit



Transmon

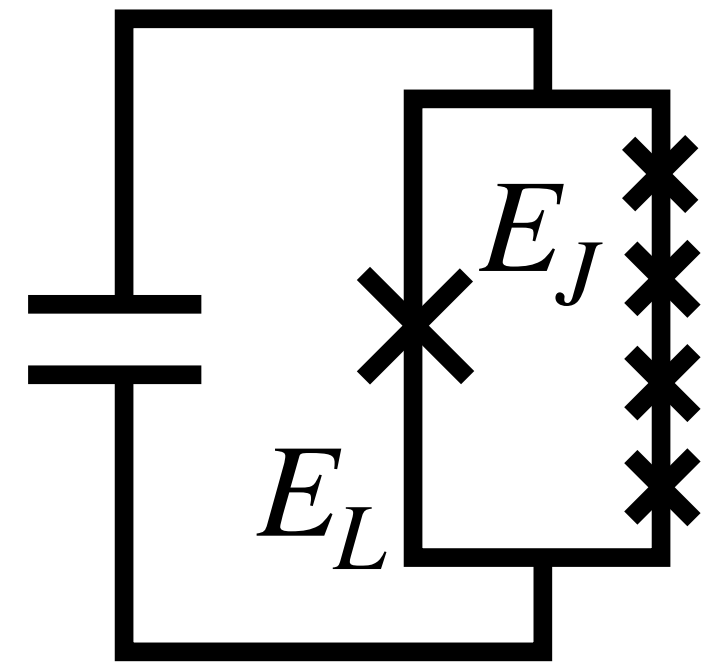
$$E_C \ll E_J$$

Cooper pair box

$$E_C \gg E_J$$

→ Fixed freq. qubit

Fluxonium

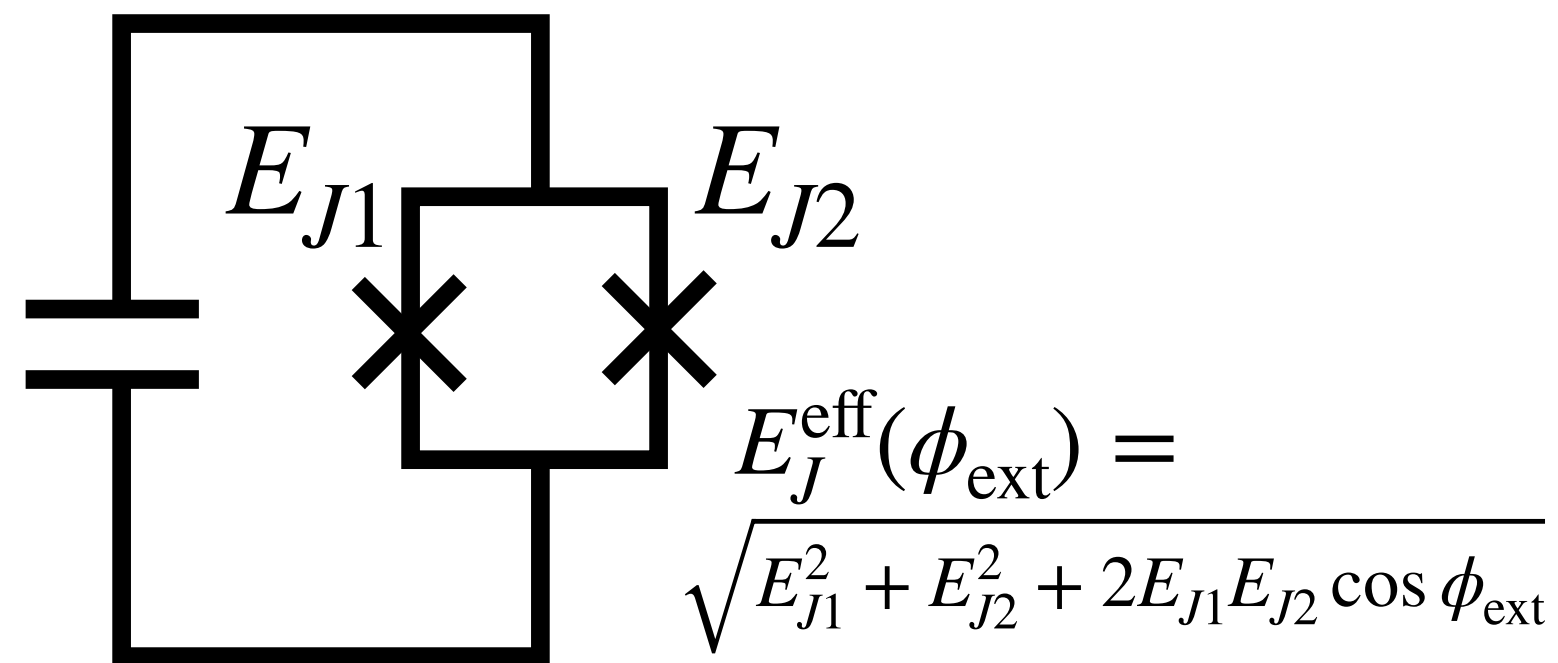


$$E_C \sim E_J$$

$$E_L \ll E_J$$

→ qubit/magnetometers

SQUID

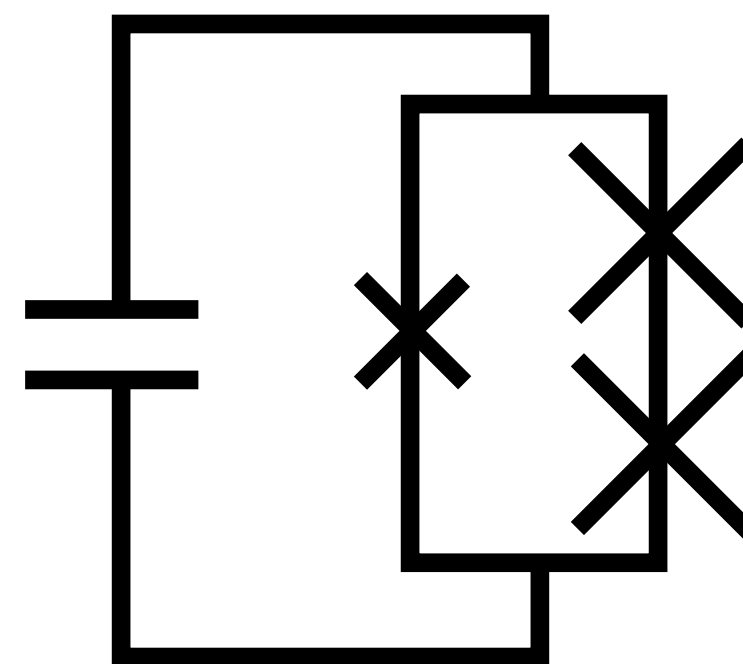


$$E_J^{\text{eff}}(\phi_{\text{ext}}) = \frac{E_{J1} E_{J2}}{\sqrt{E_{J1}^2 + E_{J2}^2 + 2E_{J1}E_{J2} \cos \phi_{\text{ext}}}}$$

→ Tunable freq. qubit

Josephson Parametric Amplifier

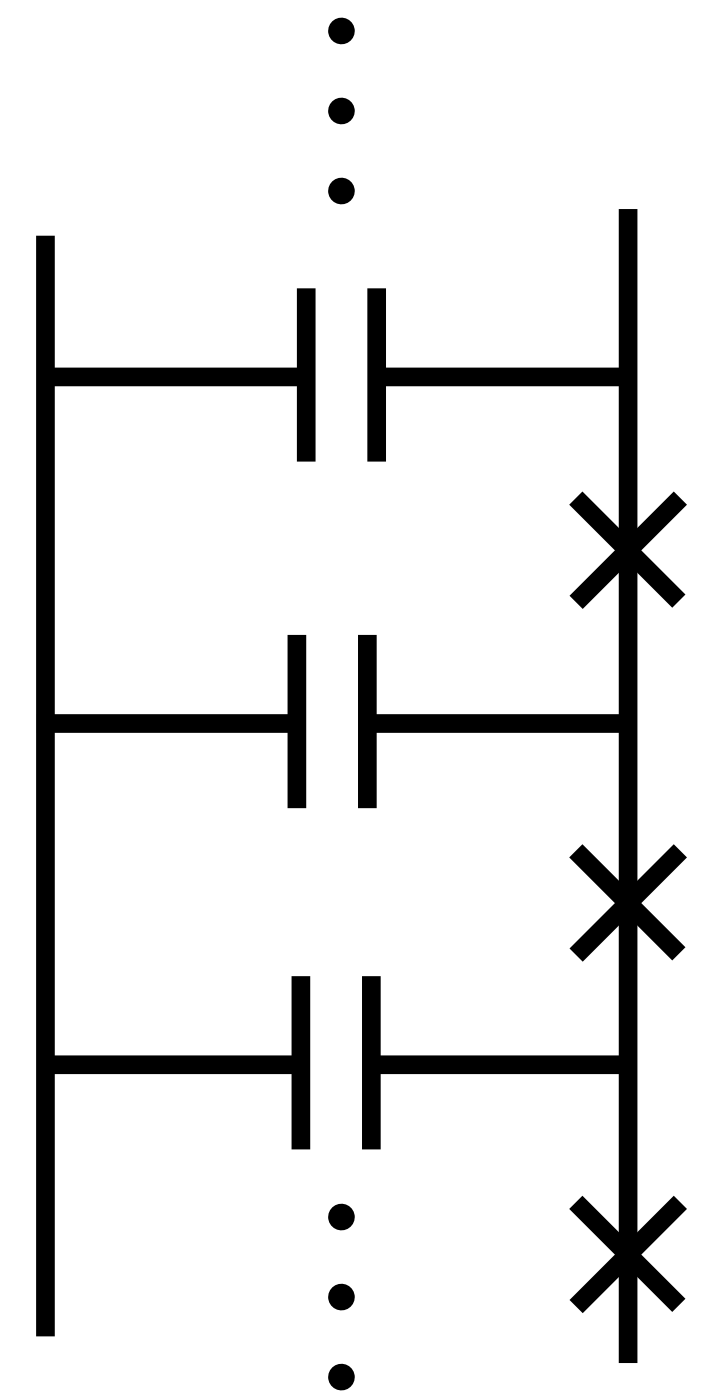
Flux qubit



$$E_C \sim E_J \sim E_L$$

→ qubits/ study amorphous...

Transmission line



→ Katayama-san's study

Traveling Wave Parametric Amplifier

2. Select Substrate

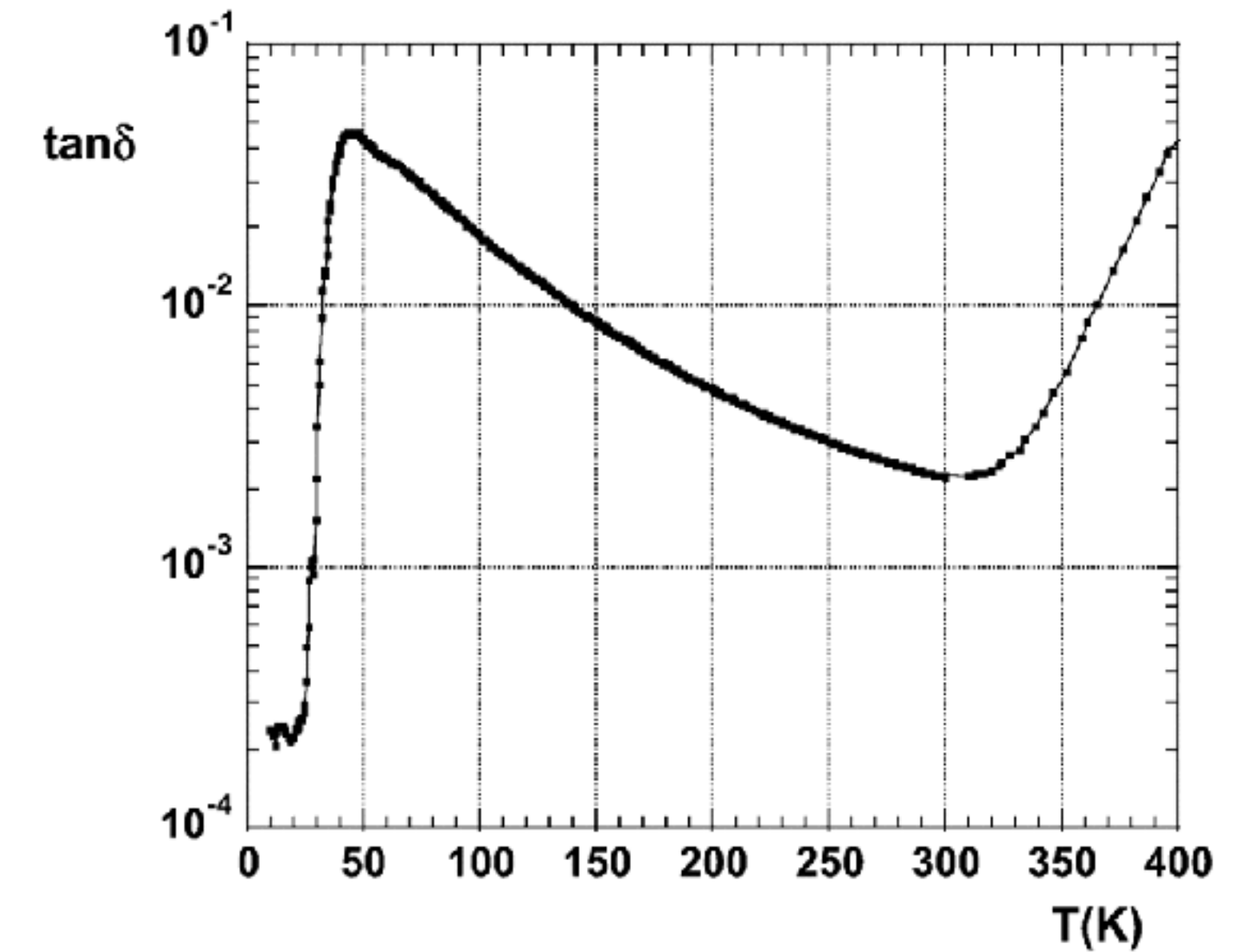
Silicon



Resistance: $>10^4 \Omega\text{cm}$
(Floating Zone)

Loss tangent: $\sim 10^{-4}$ @ 10 mK

Price: 1000 JPY / 100 mm wafer



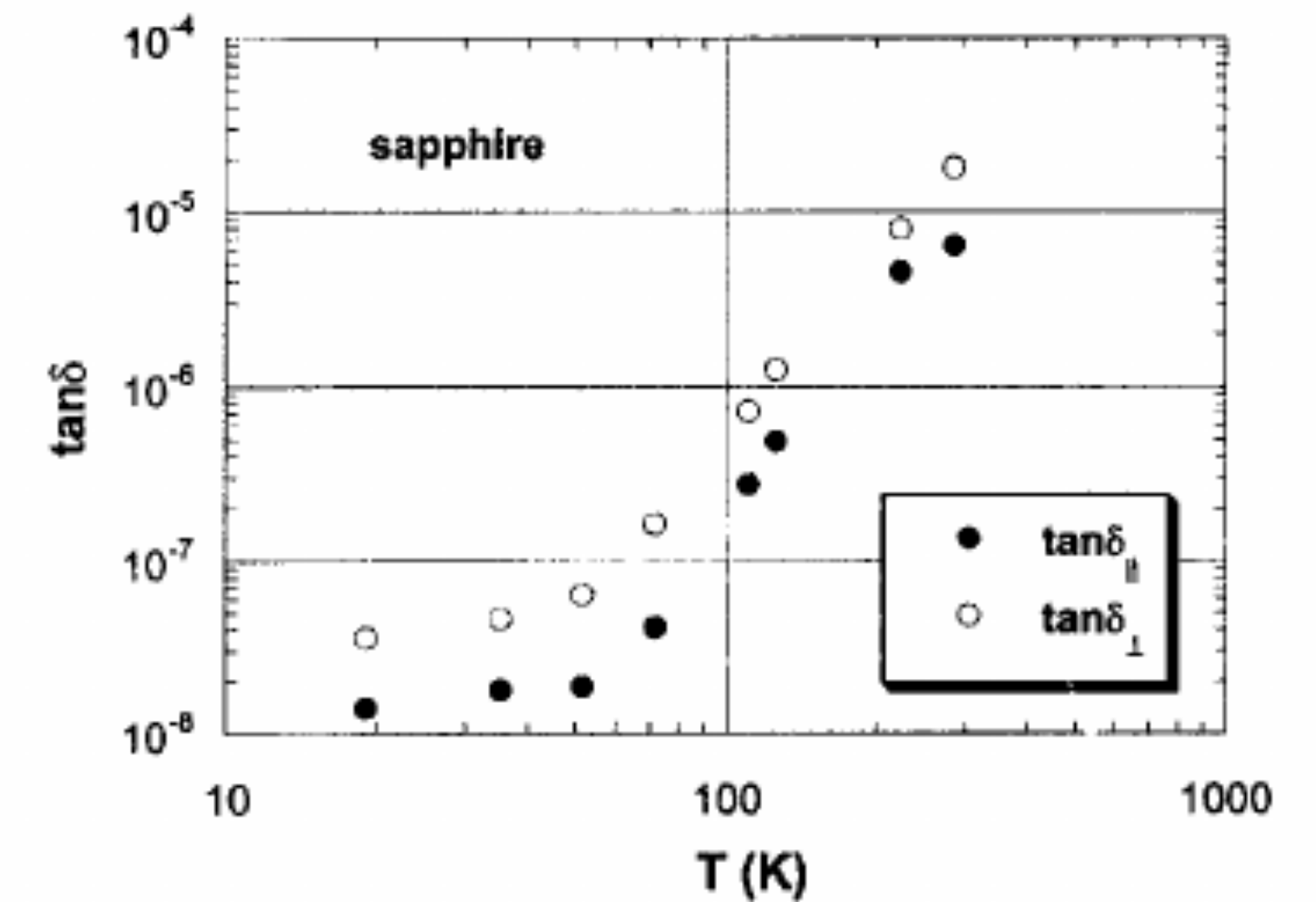
Sapphire



Resistance: $10^{11} \Omega\text{cm}$

Loss tangent: $\sim 10^{-8}$ @ 10 mK

Price: 4000 JPY/ 100 mm wafer



2. Substrate Cleaning

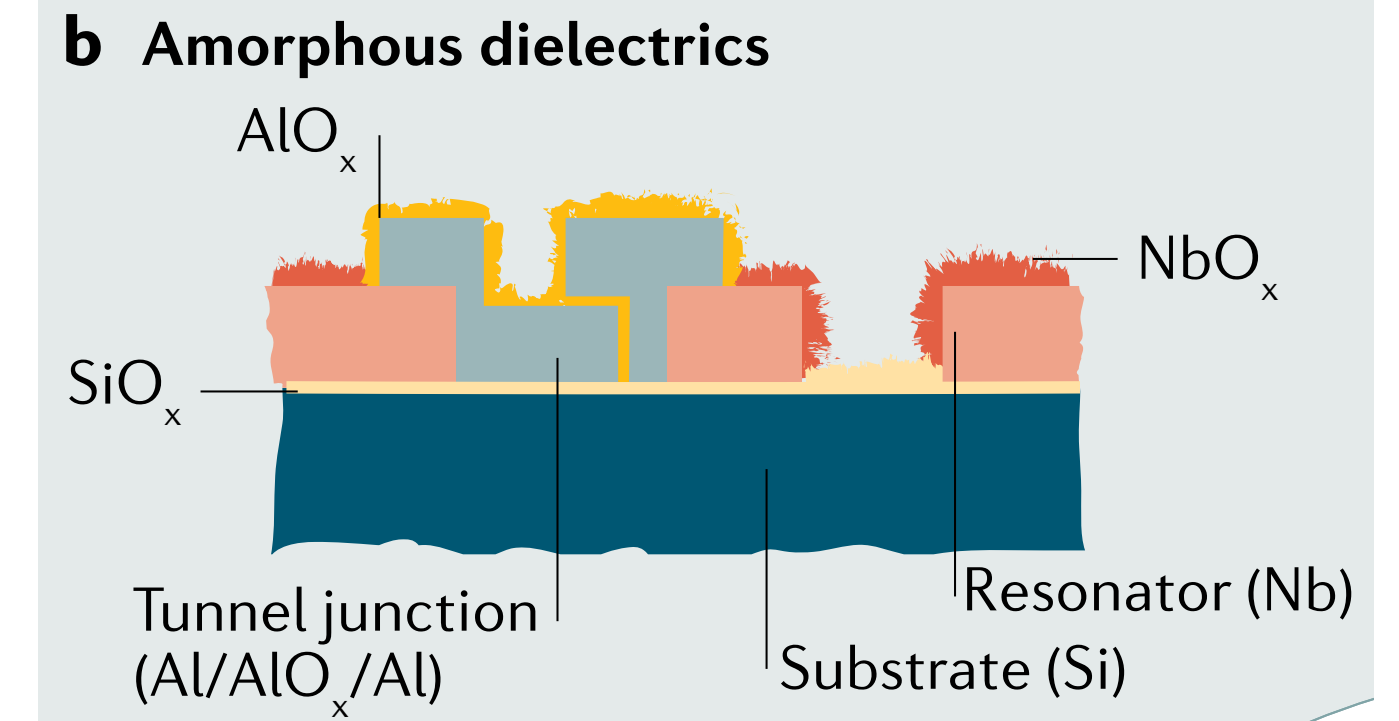
Shipped wafers



Source of impurity

- Dusts/Organic substances during fabrication
- Dusts/Organic substances during packing
- Native oxide on silicon substrate etc...

Nat Rev Mater 6, 875–891



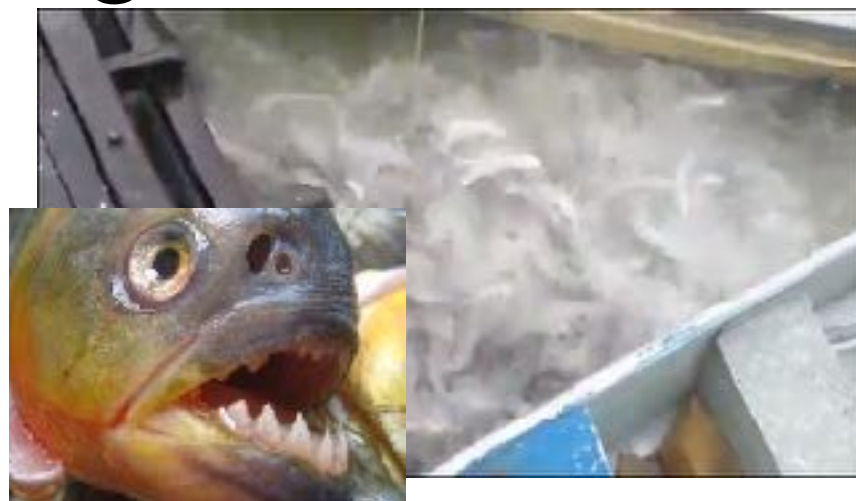
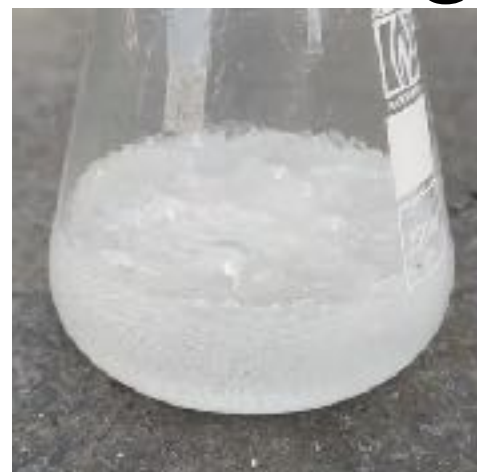
Contamination directly affects coherence of qubits

Typical Cleaning Processes

Piranha solution

$\text{H}_2\text{SO}_4 + \text{H}_2\text{O}_2$

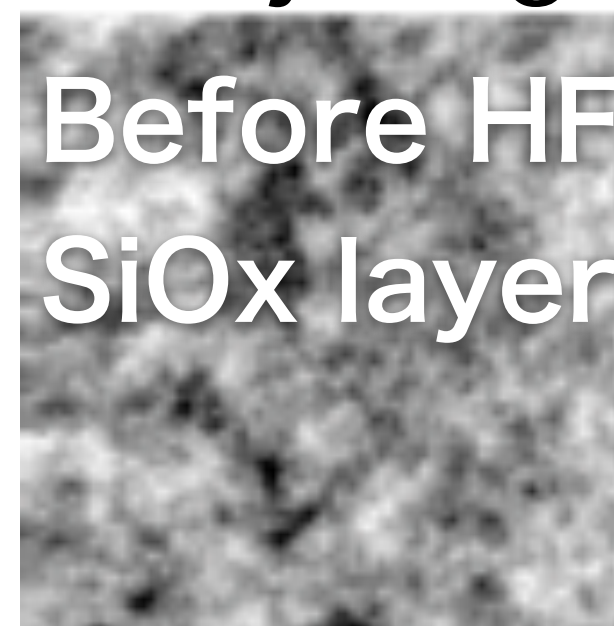
Removing organic substances



Hydrofluoric Acid (HF)

Remove oxidation layer & Hydrogen termination

Before HF
SiO_x layer



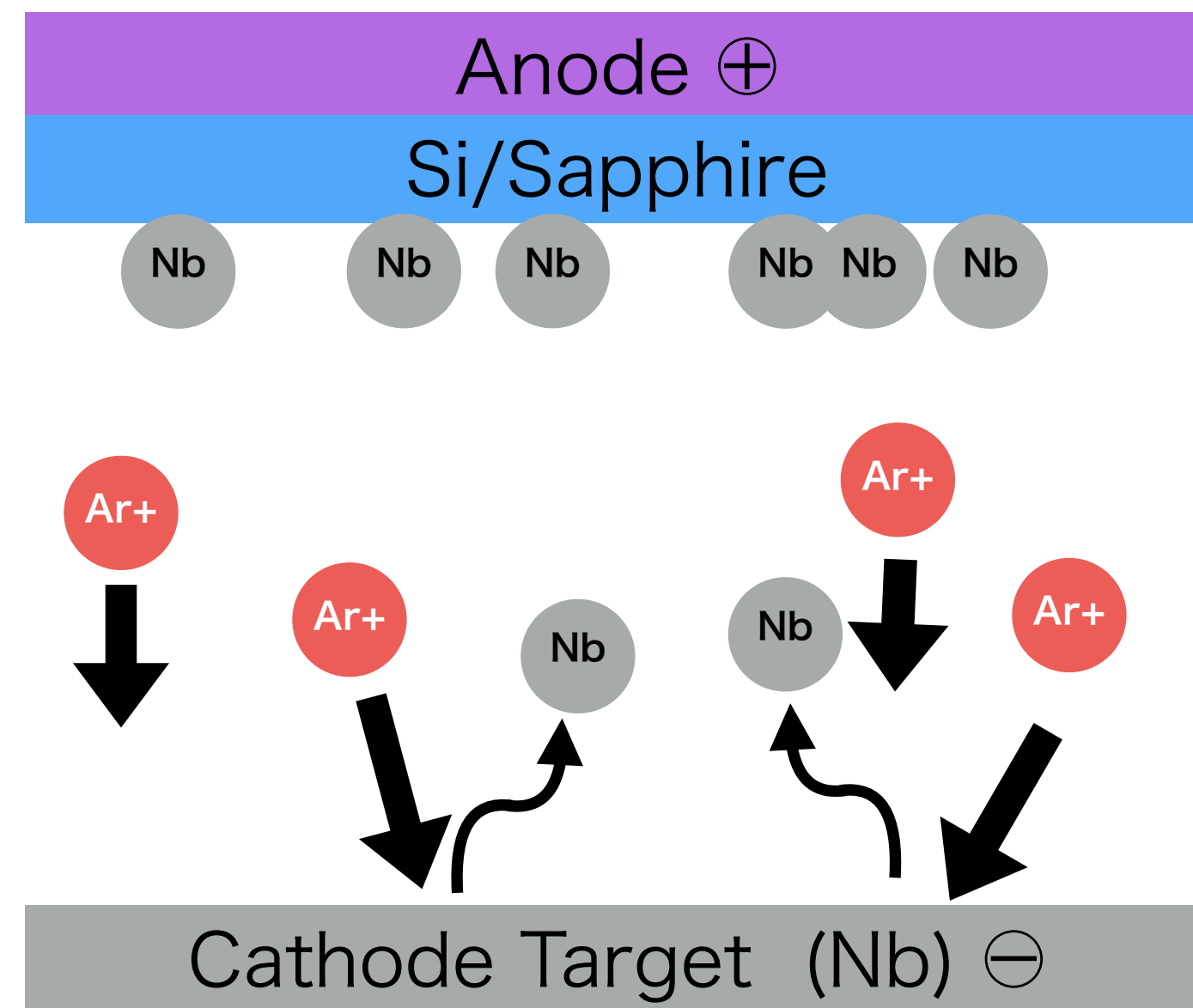
After HF
Si(111)



Make sure to use chemical draft and proper protections

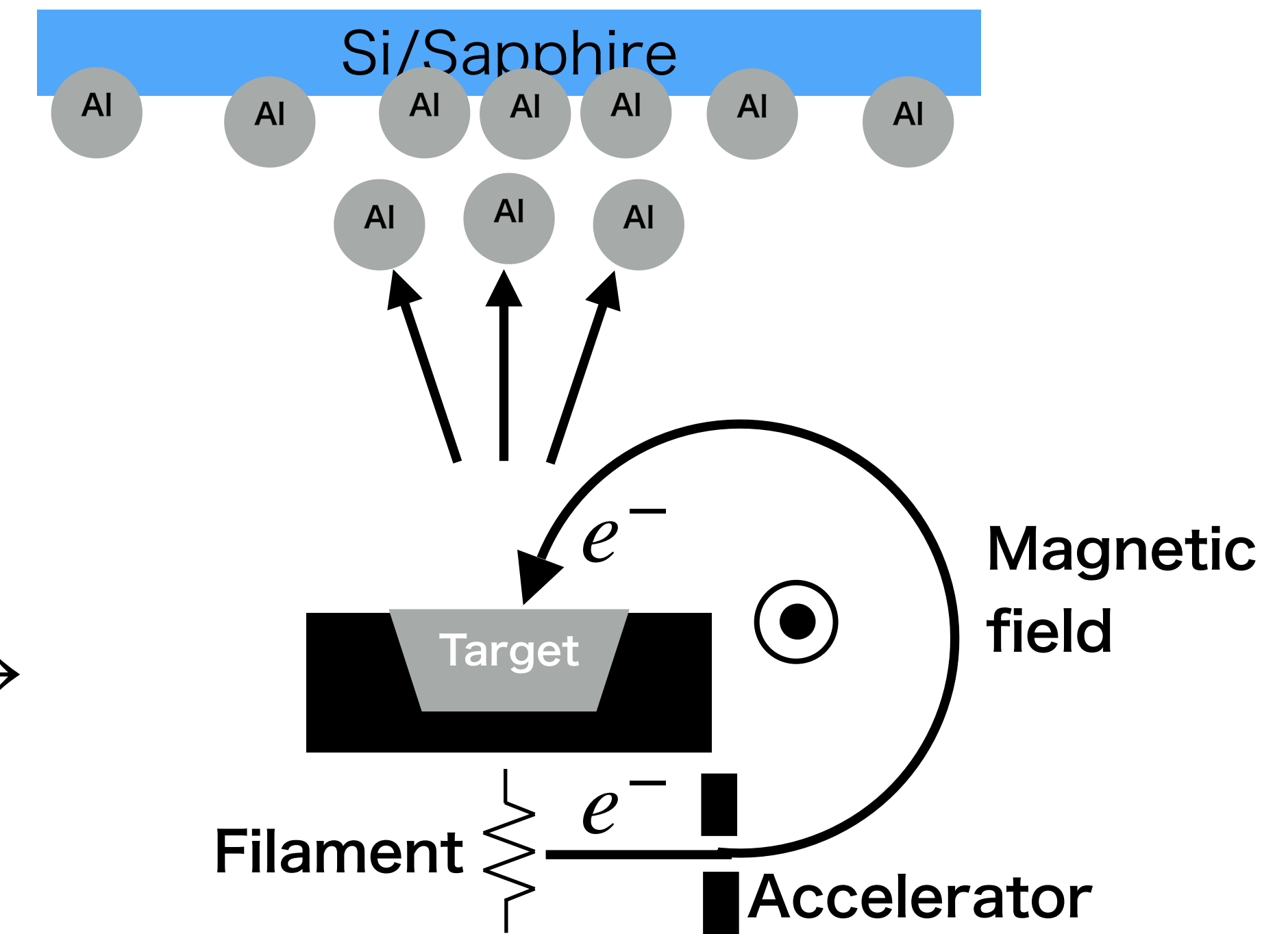


3. Thin film deposition



← Sputter

EB vapor
deposition →



Target

Cons:

- Homogeneity film
 - Larger area deposition
- **Used to make capacitors**

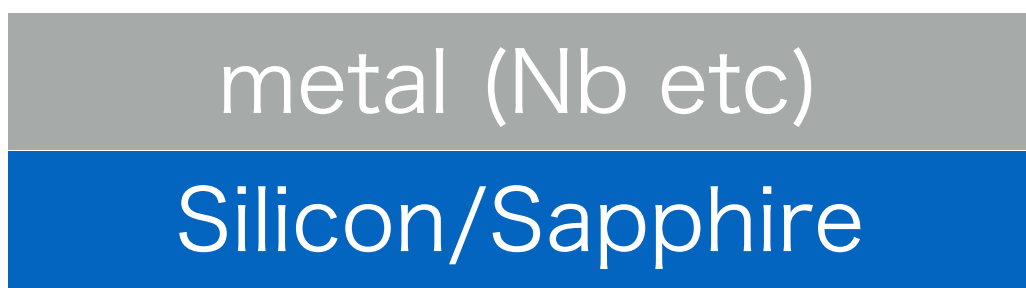
Target

Cons:

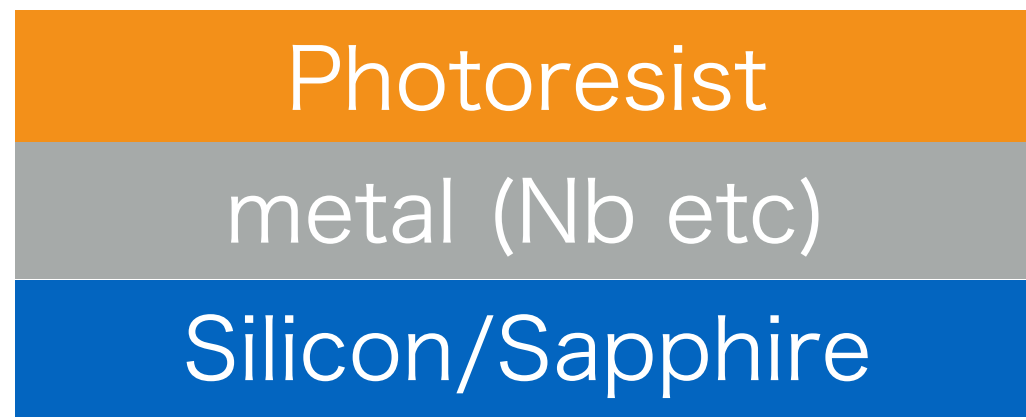
- **Directivity**
 - Faster deposition
- **Used to make JJ**

4. Photolithography

0. Prepare substrate



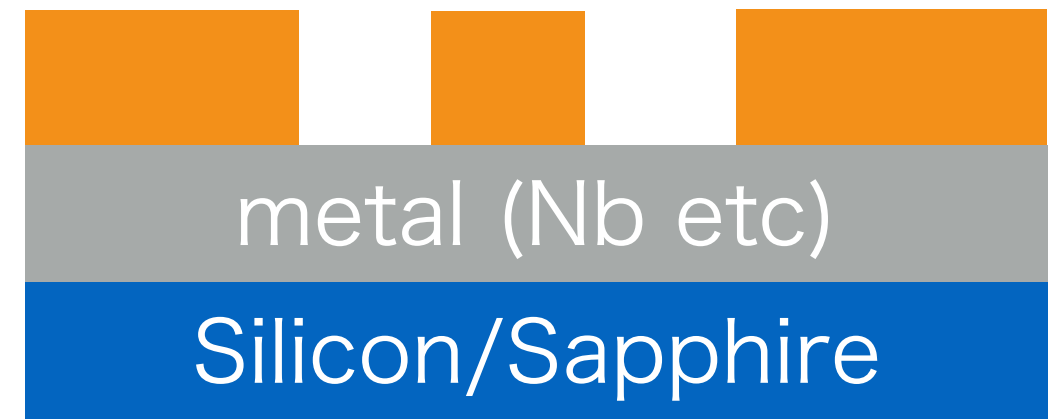
1. Spincoating Photoresist



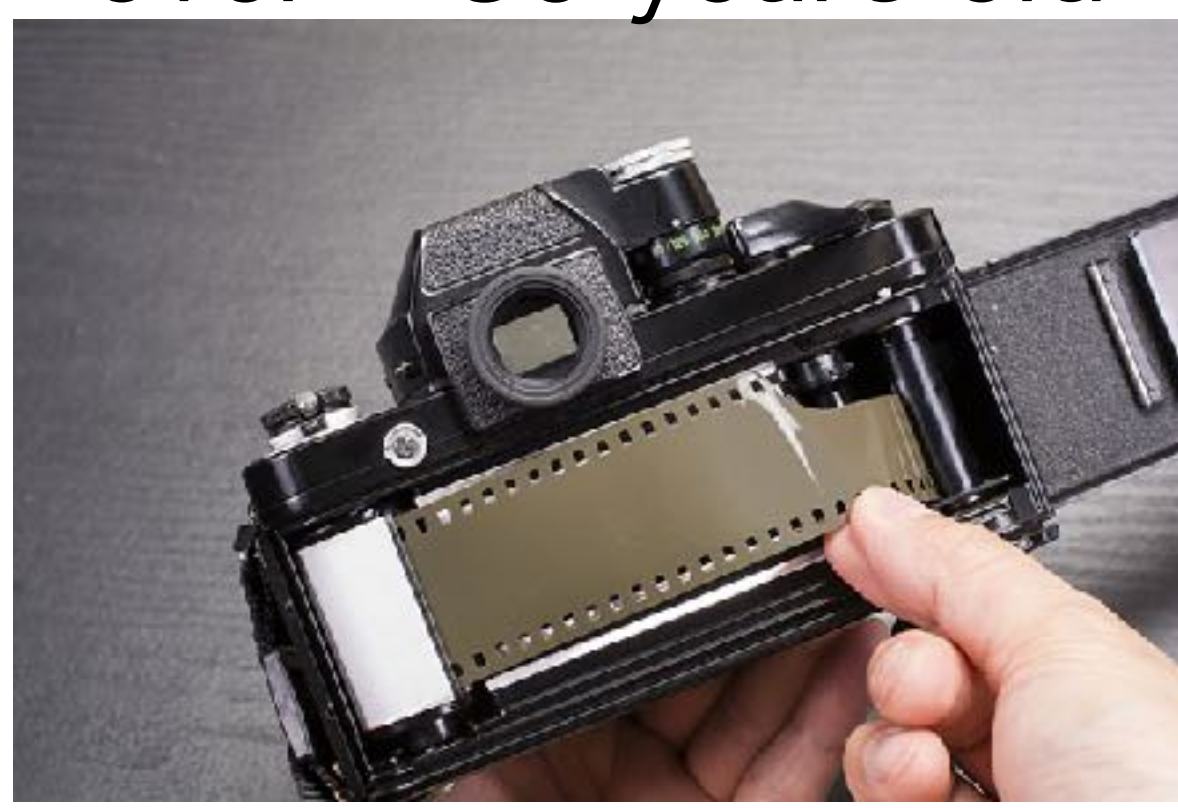
2. Exposure
UV ↓ ↓ exposed



3. Development
remove exposed or unexposed resist



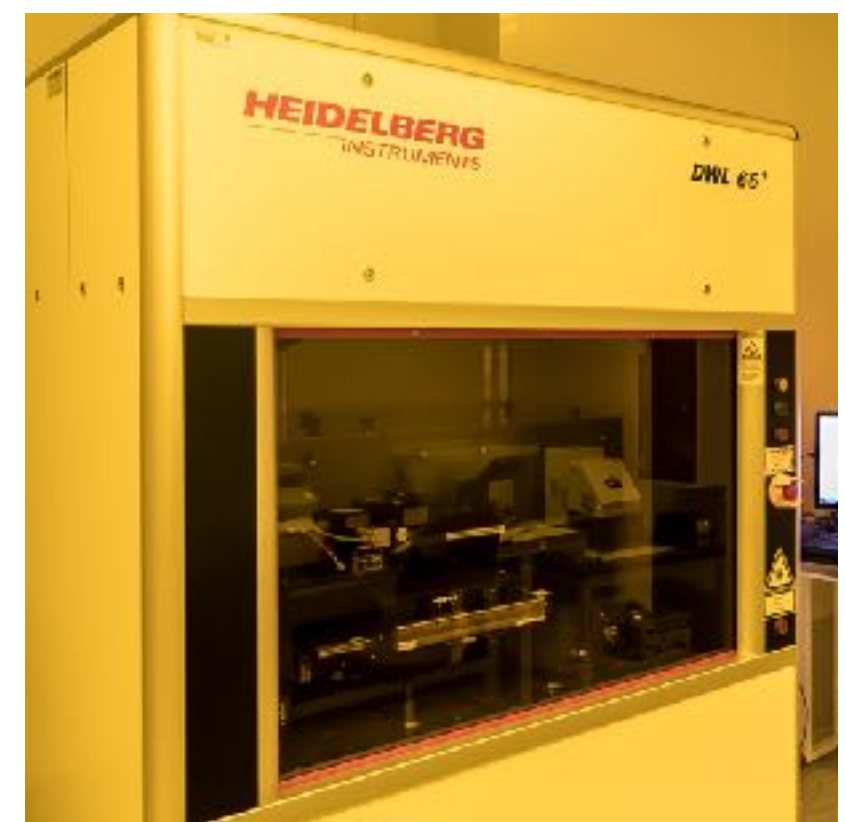
Good example for over ~ 30 years old



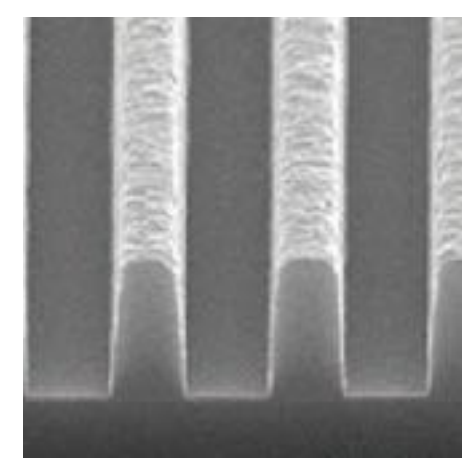
spincoater



Photolithography



Development



~ 1um resolution
→ only for larger structures

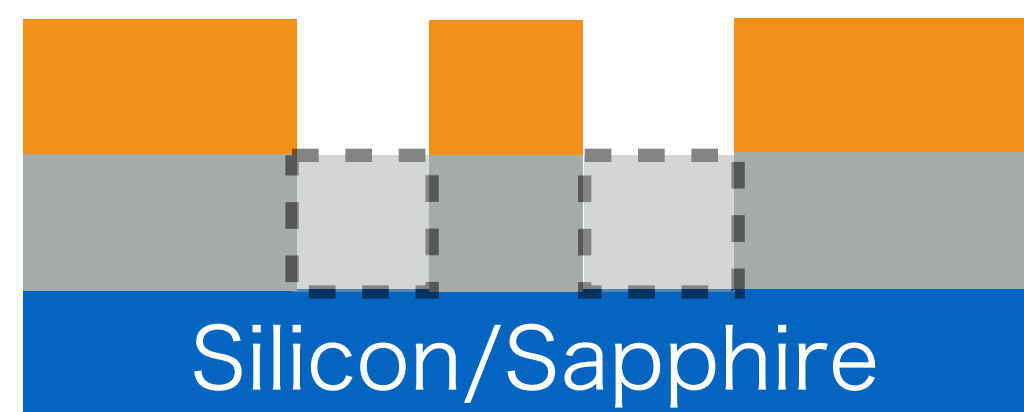
5. Etching

0. After development



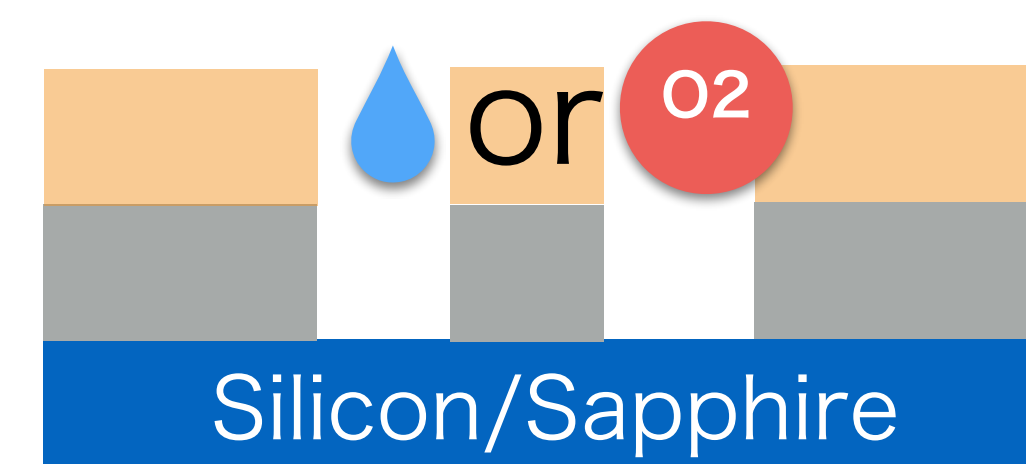
1. Etching

Removing metal
not masked by resist



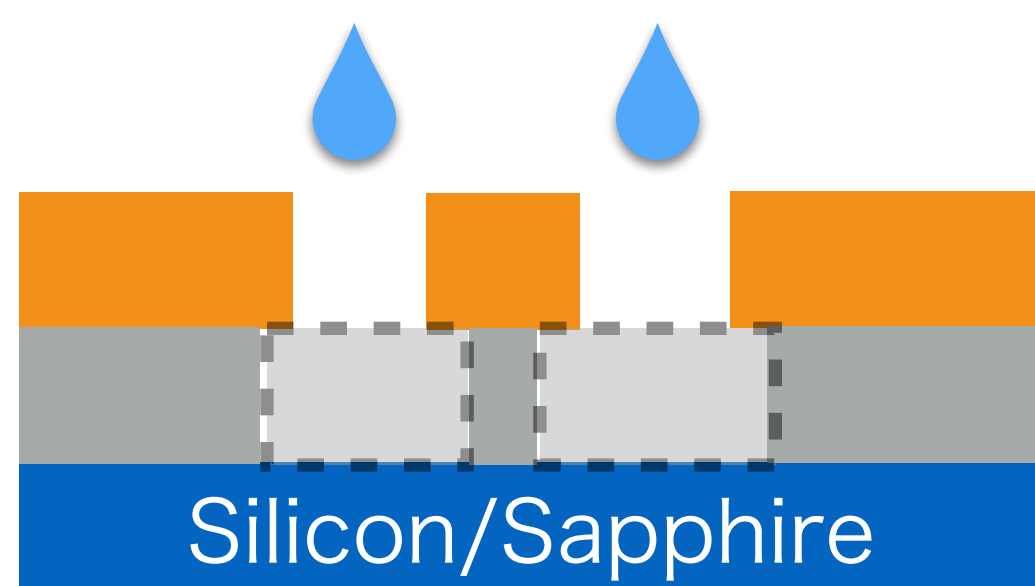
2. Ashing

Removing resist



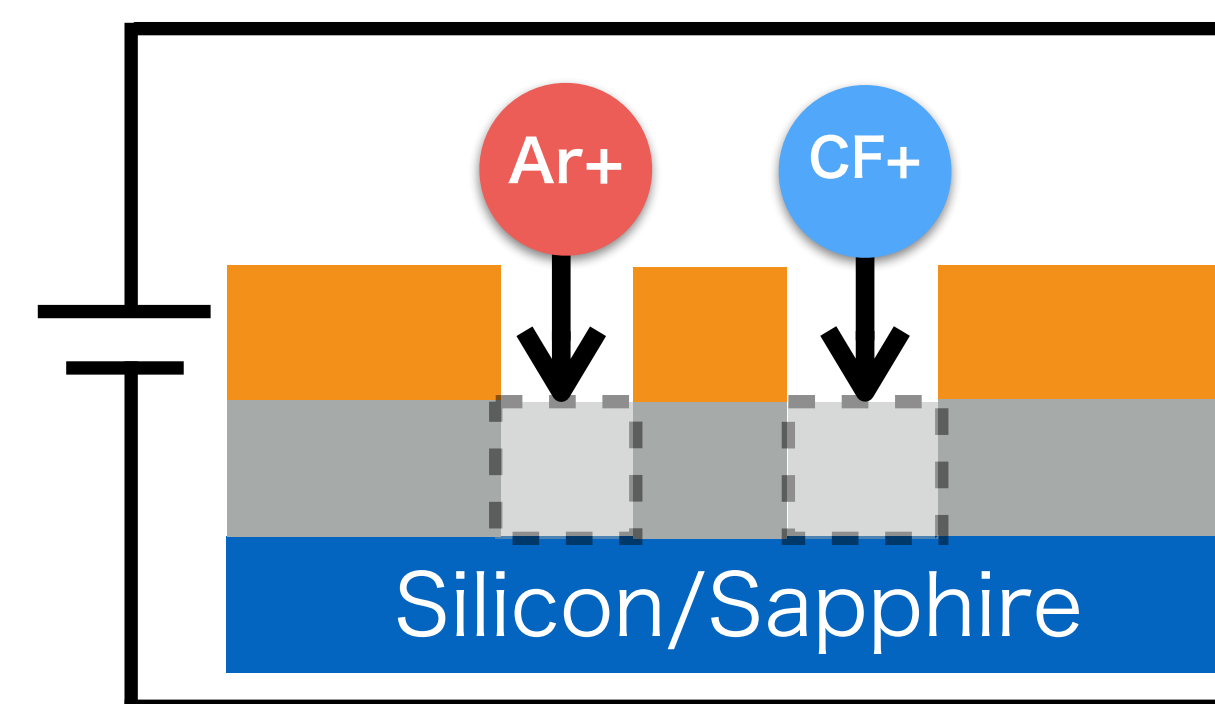
Two ways

1 a. Wet etching



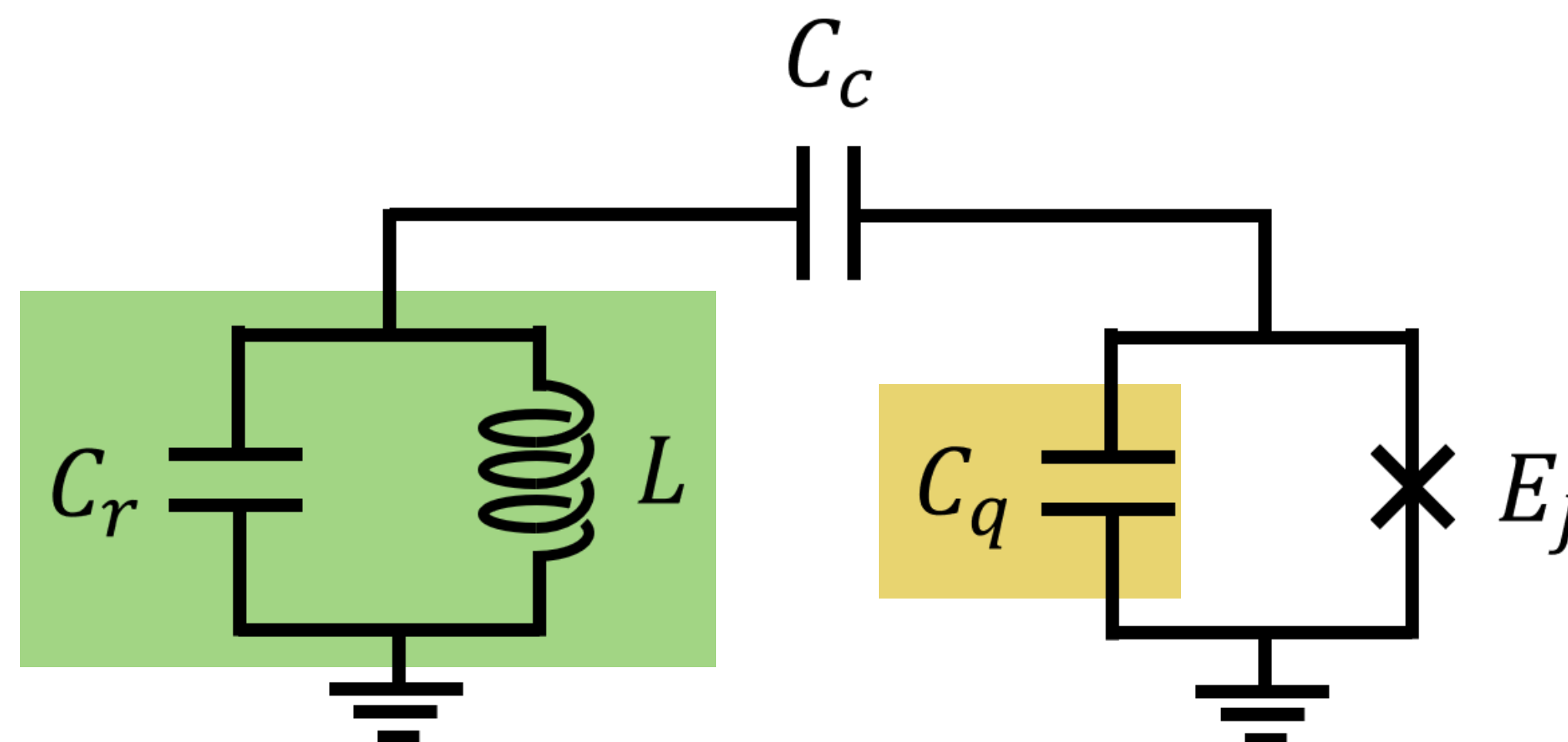
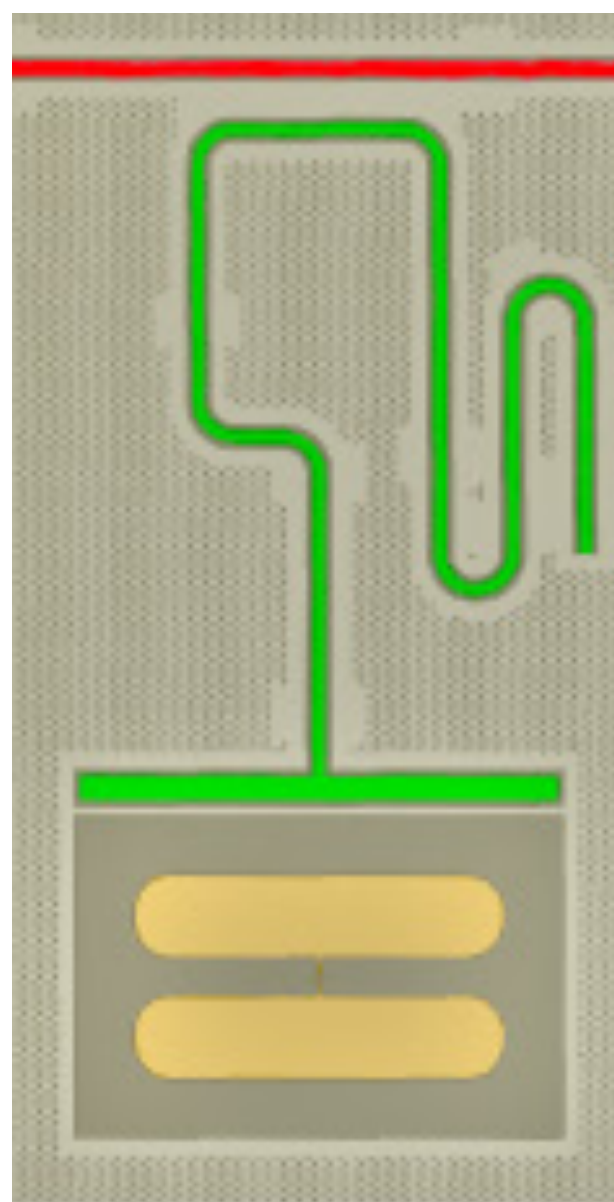
ex)
Al can be dissolved by
 $\text{HNO}_3 + \text{H}_3\text{PO}_4$ solution

1 b. dry etching



Similar to sputtering
Called RIE (reactive
ion etching)

Where we are



After Step 1-5, capacitance and resonator (in the case of 2D resonator) are fabricated.

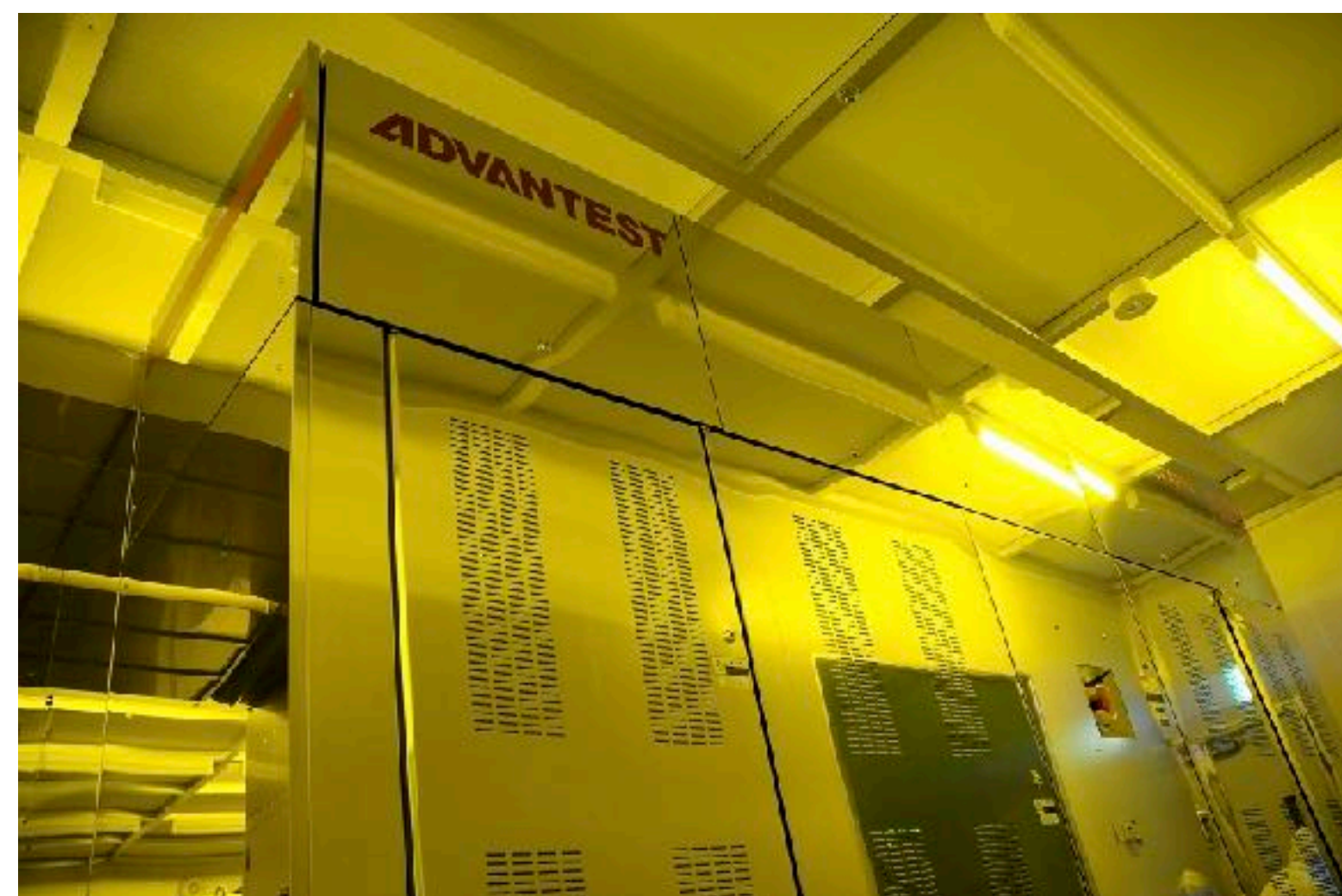
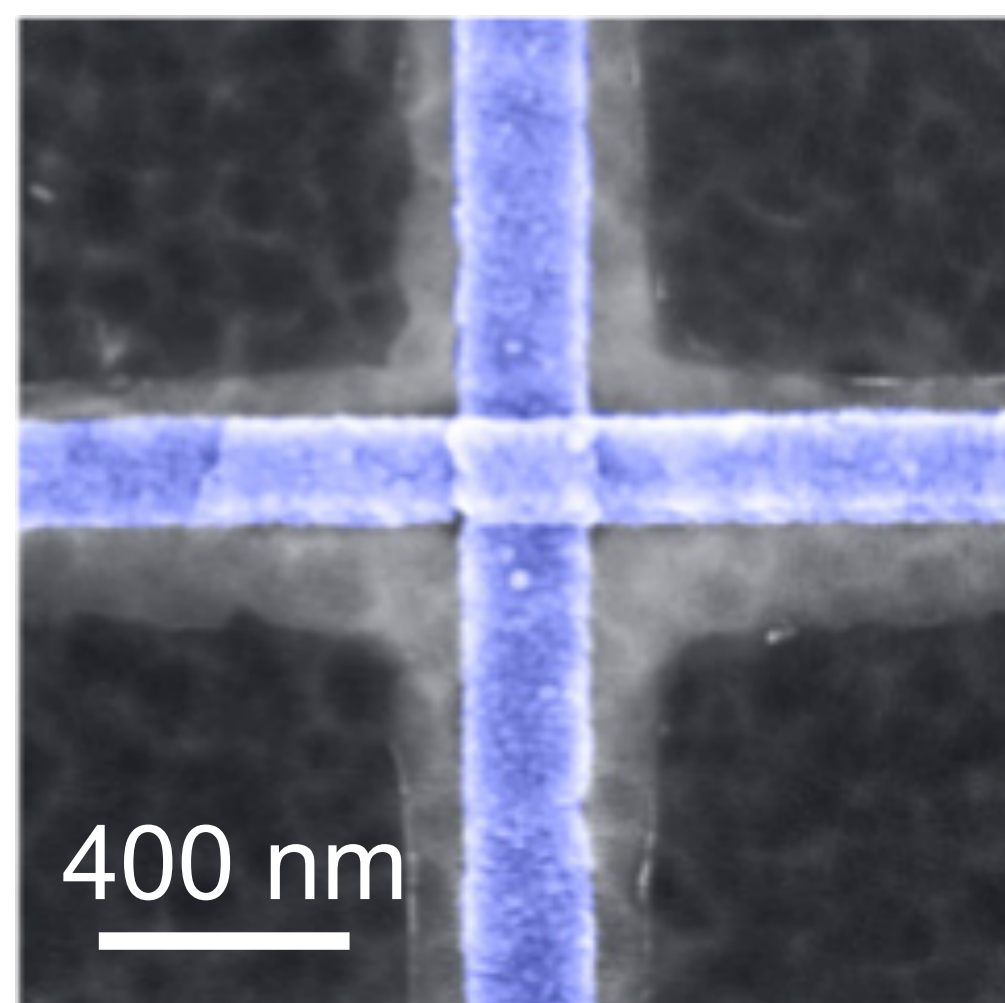
6. Electron Beam(EB) lithography

UV lights: $\sim 10^{-7}$ m, electron: $\sim 10^{-10}$ m, accelerator: $< \sim 10^{-17}$ m

Electron beam has higher energy than UV \sim Higher resolution

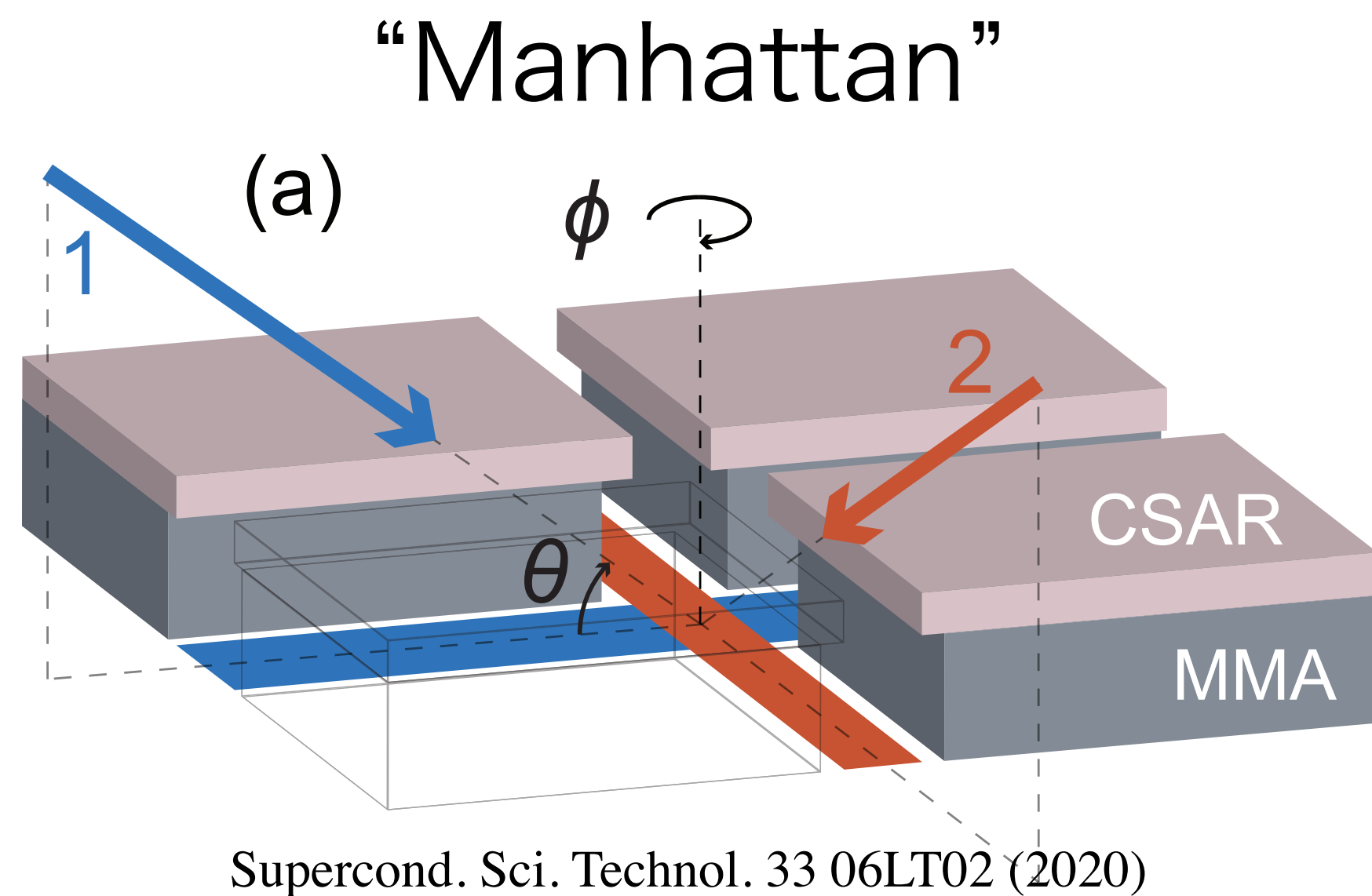
ex) UV Photolithography $\sim 1 \mu\text{m}$ (EUV can go better in semiconductor industry)

EB lithography ~ 10 nm



Processes are the same as photolithography

7. Shadow evaporation



1. First deposition

$$\Phi = 0^\circ, \theta = 45^\circ$$

Cross-section
view

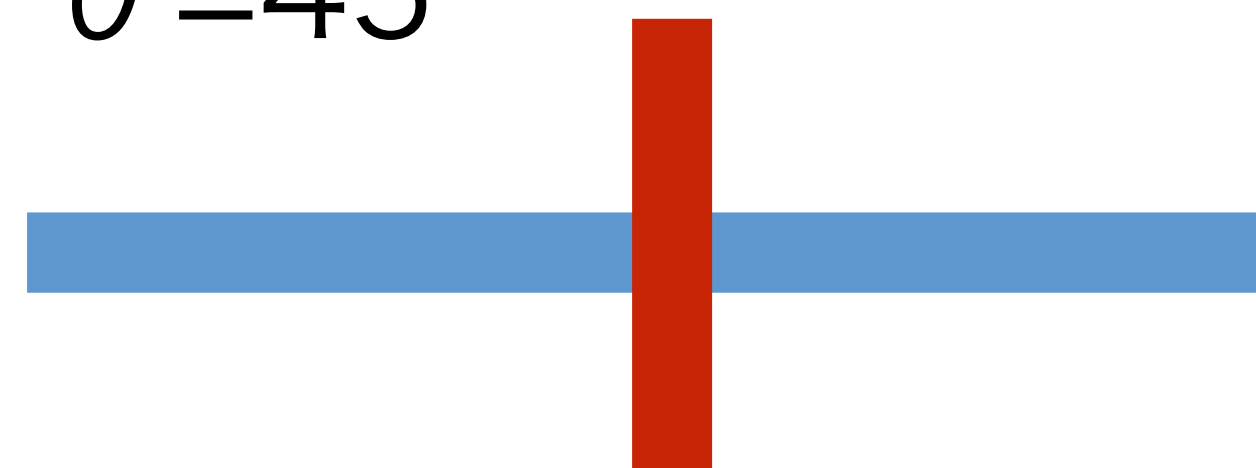


2. Oxidation



3. Second deposition

$$\Phi = 90^\circ, \theta = 45^\circ$$



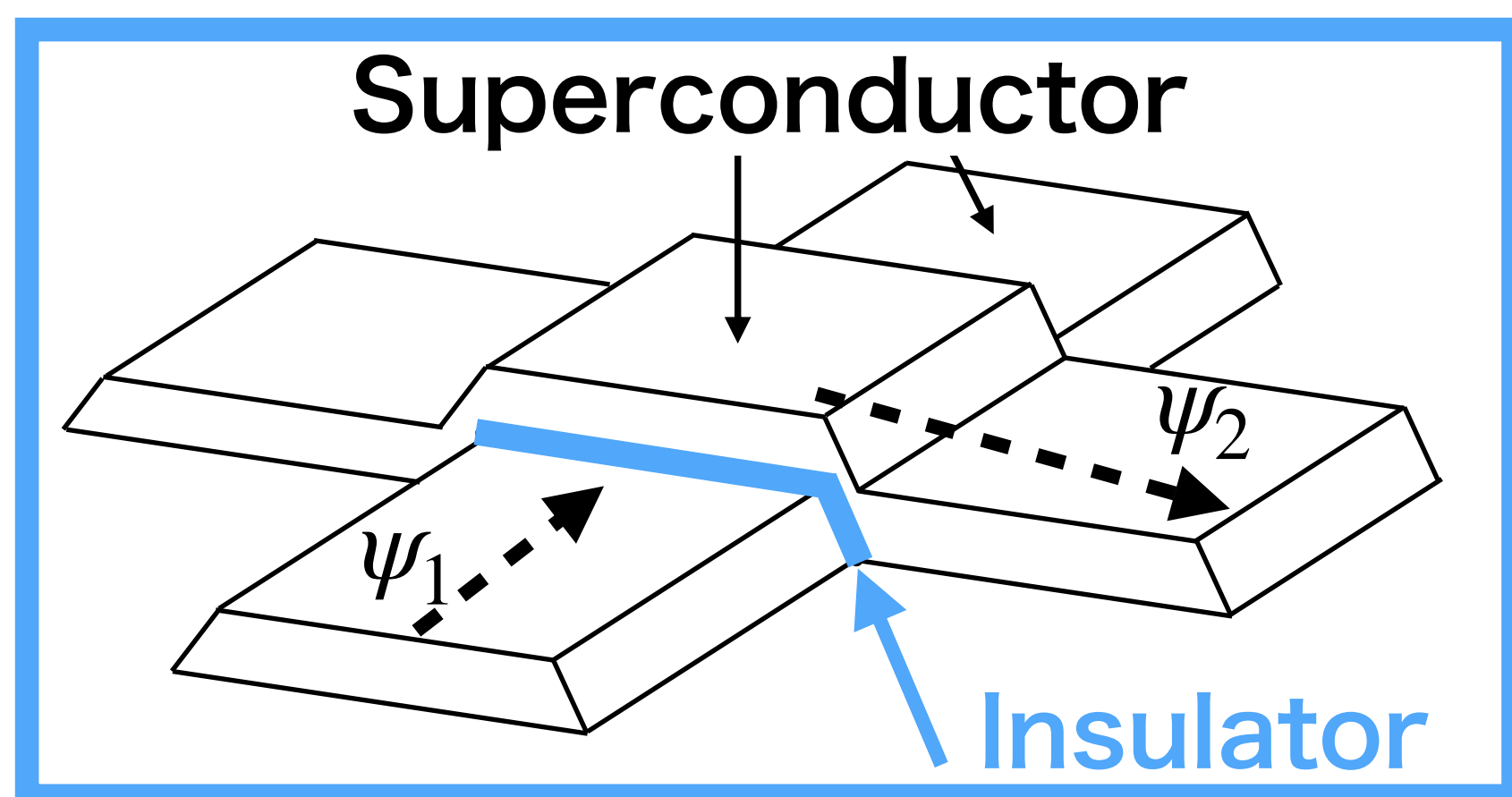
JJ



except
JJ

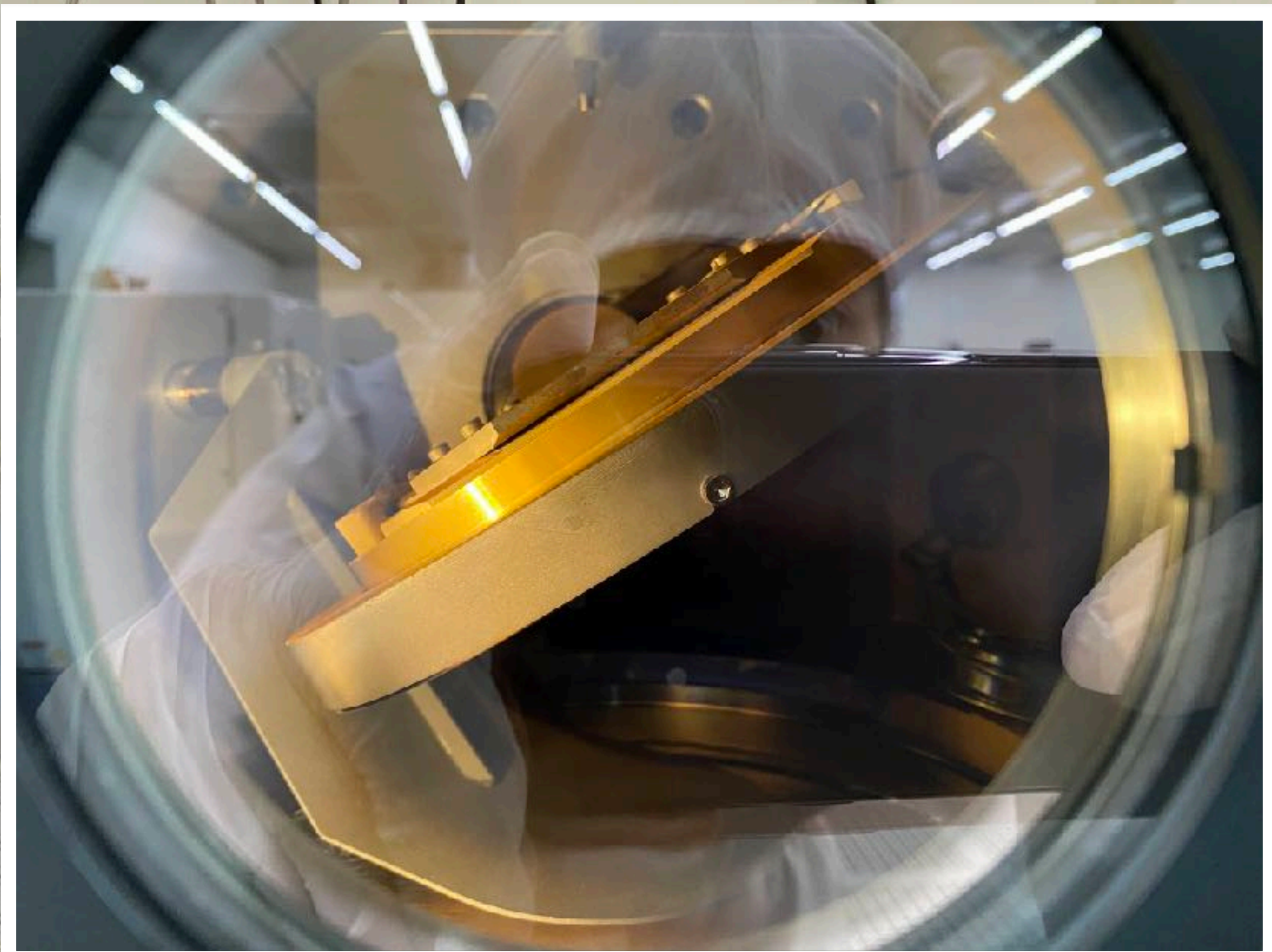
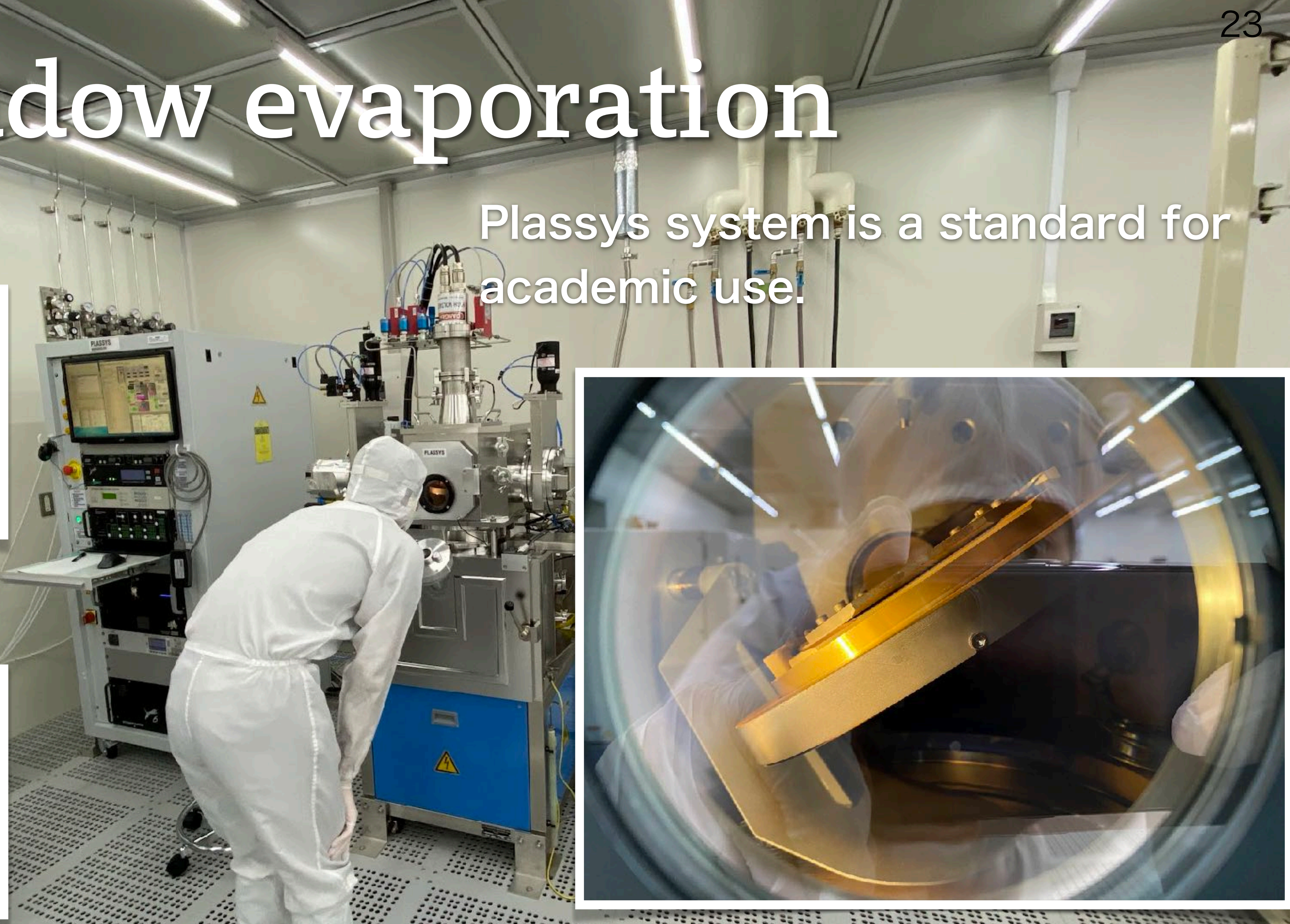


or

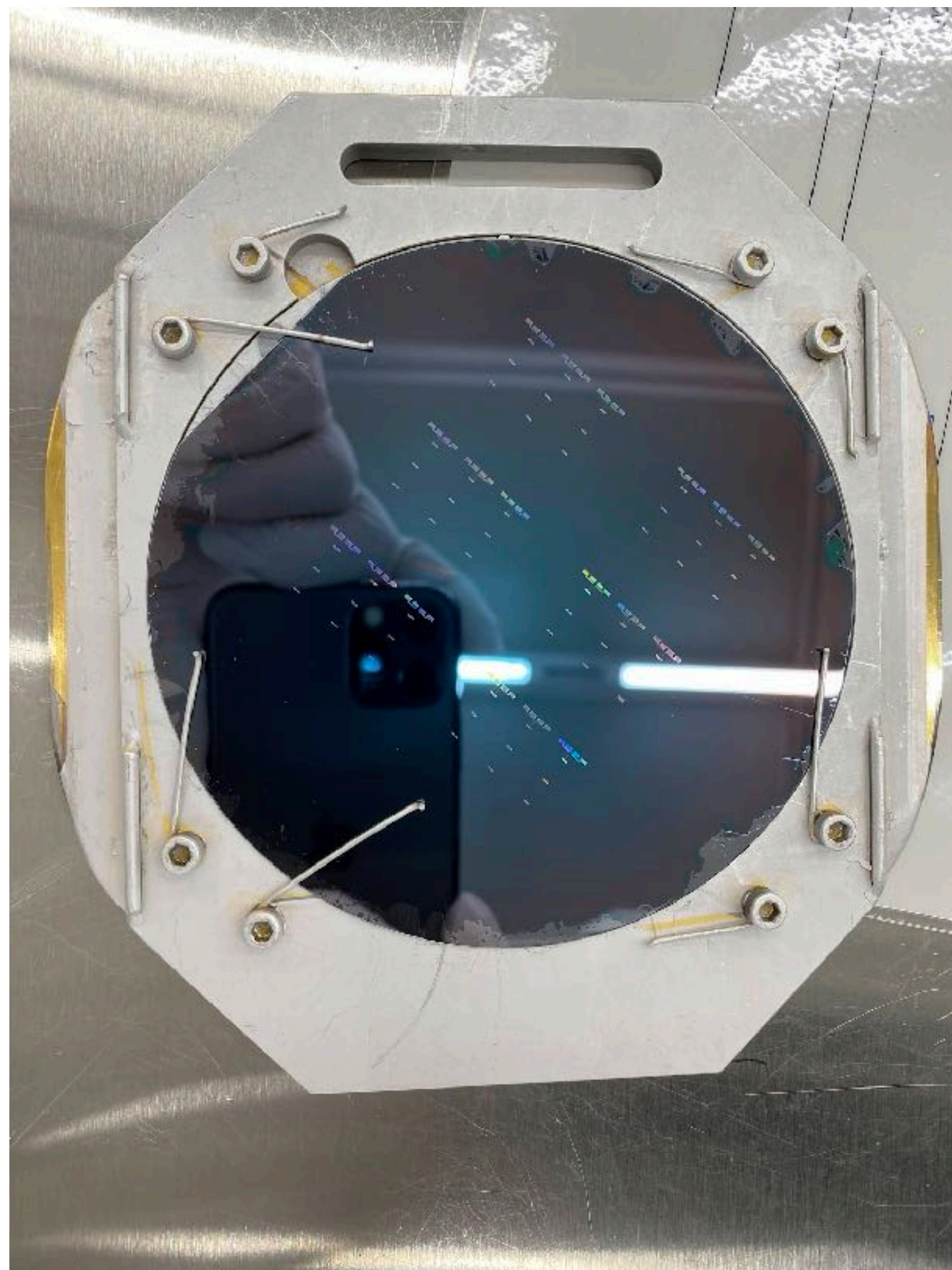


7. Shadow evaporation

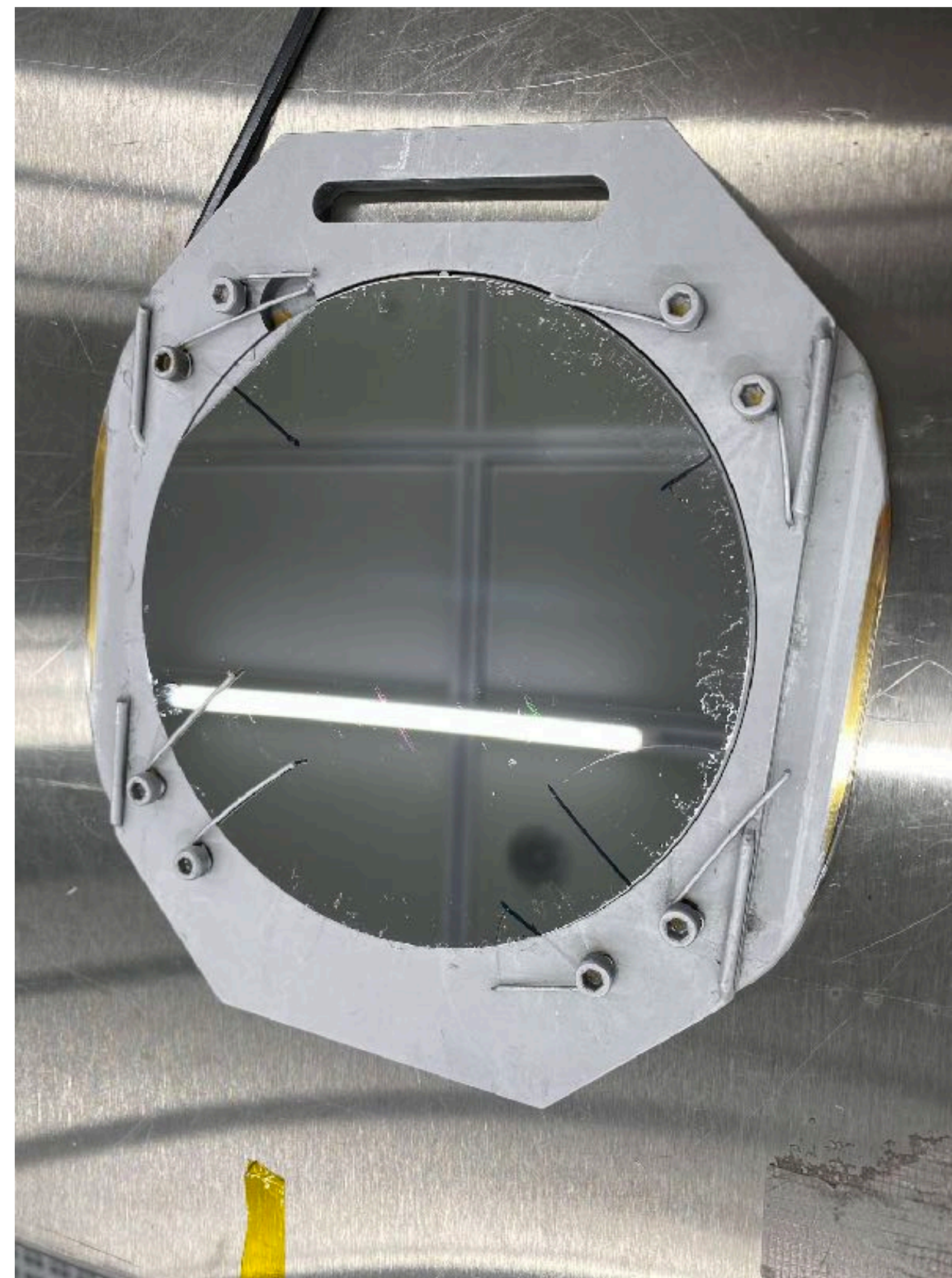
Plassys system is a standard for academic use.



7. Shadow evaporation



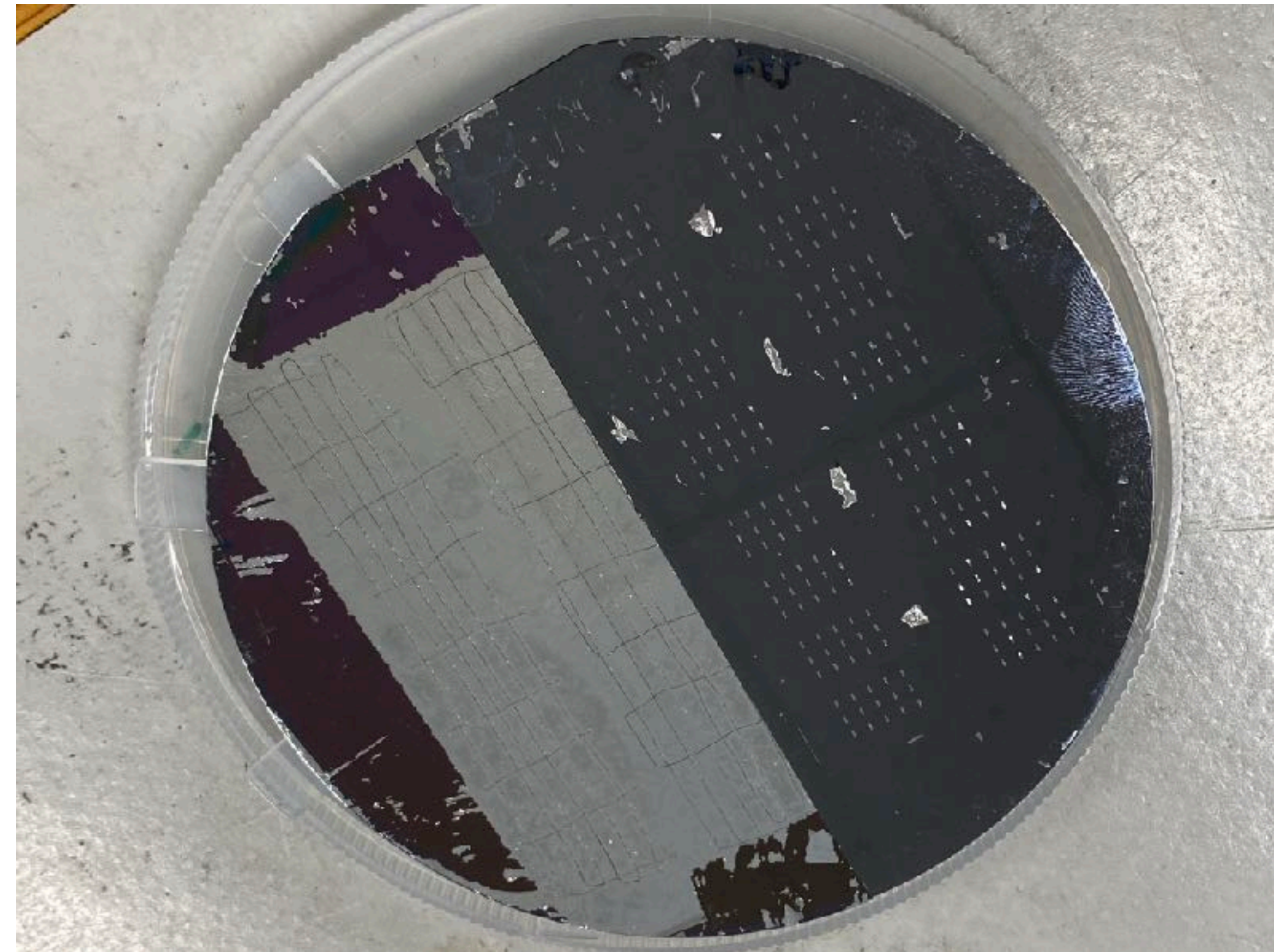
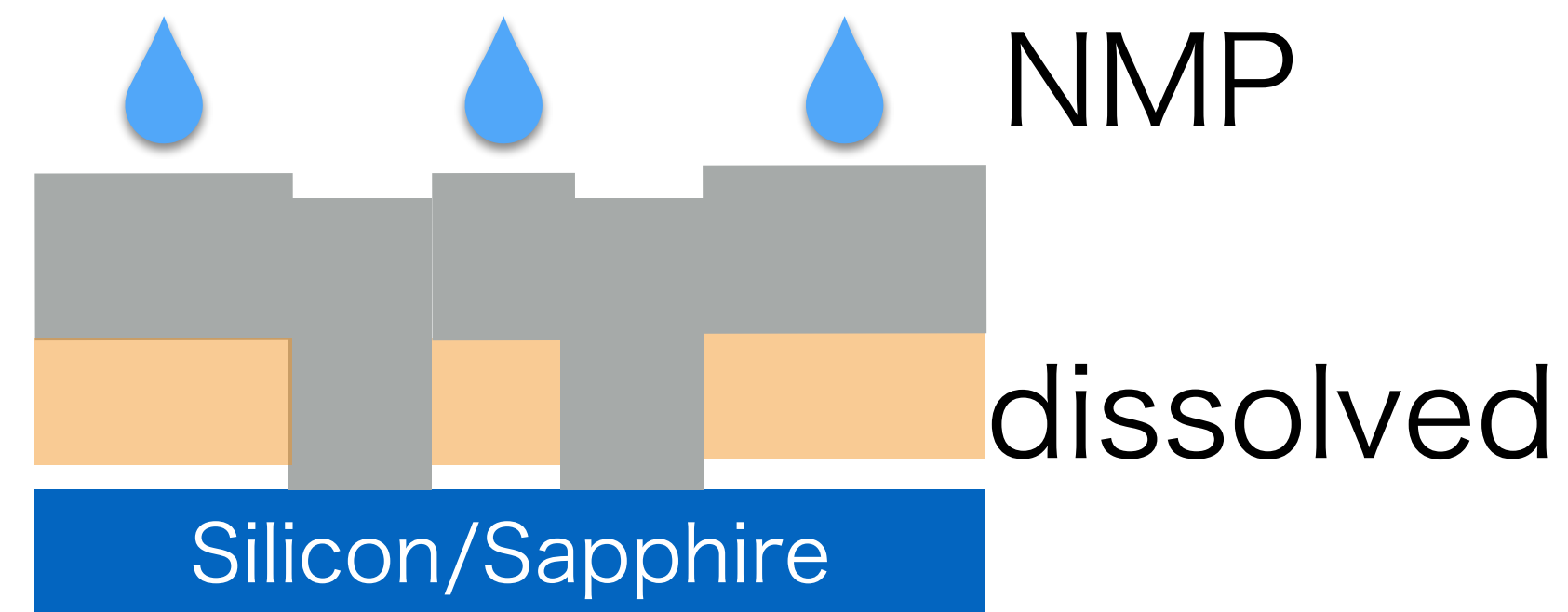
Before deposition



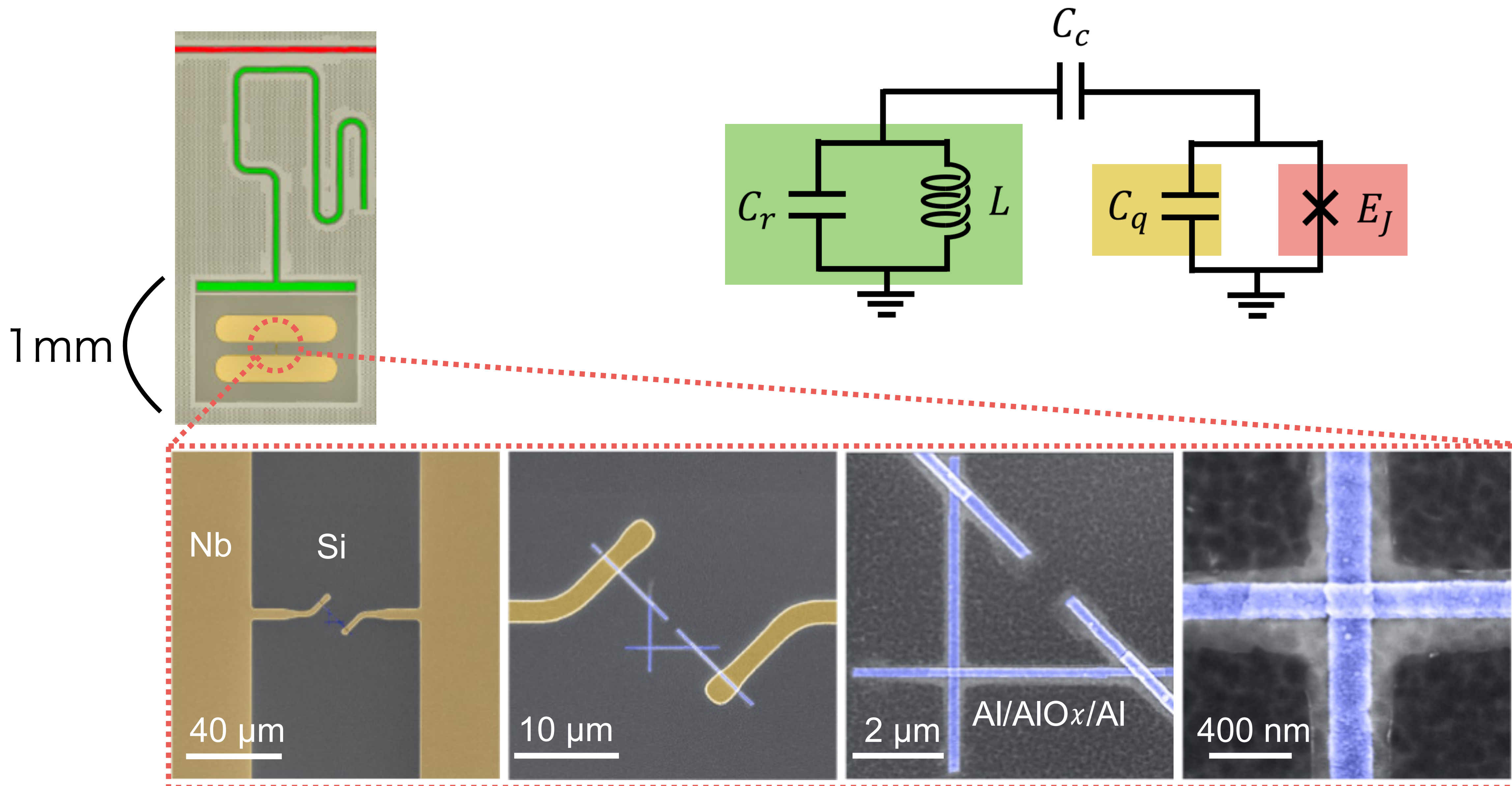
After deposition

8. Lift-off

A process to remove unnecessary Aluminium film.
NMP (N-methylpyrrolidone) is used to dissolve resist layer.



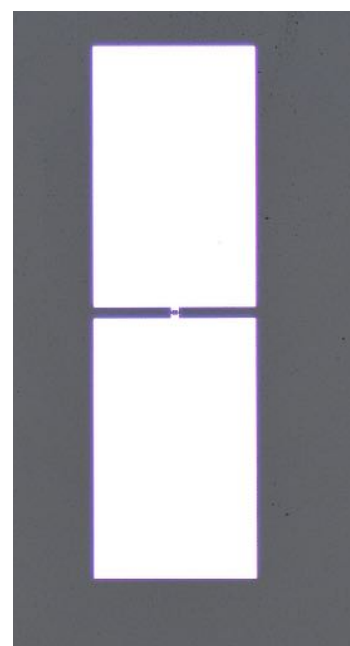
Where we are



Before cryogenic test...

9. Microscope

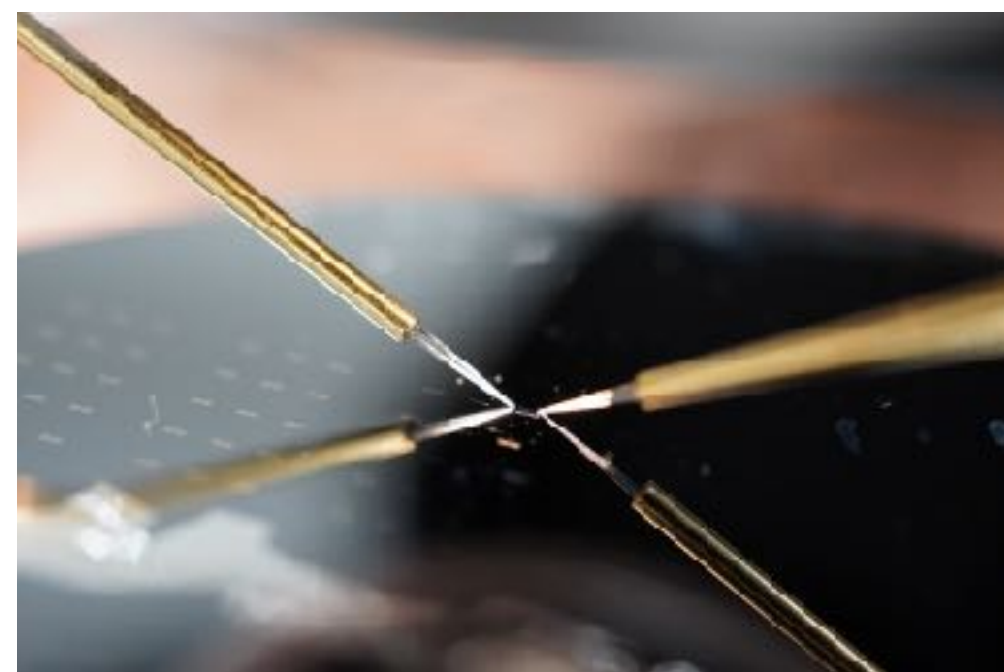
Optical



SEM

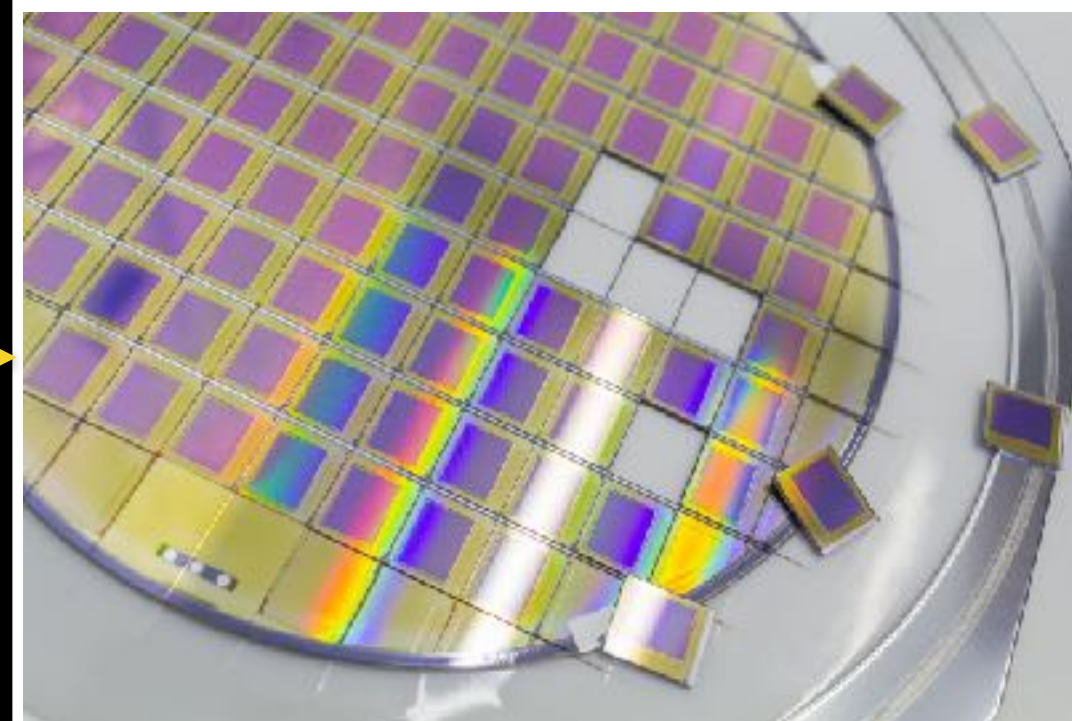


10. Resistance



$$E_J \sim \frac{\hbar \pi \Delta_{sc}}{4e^2 R}$$

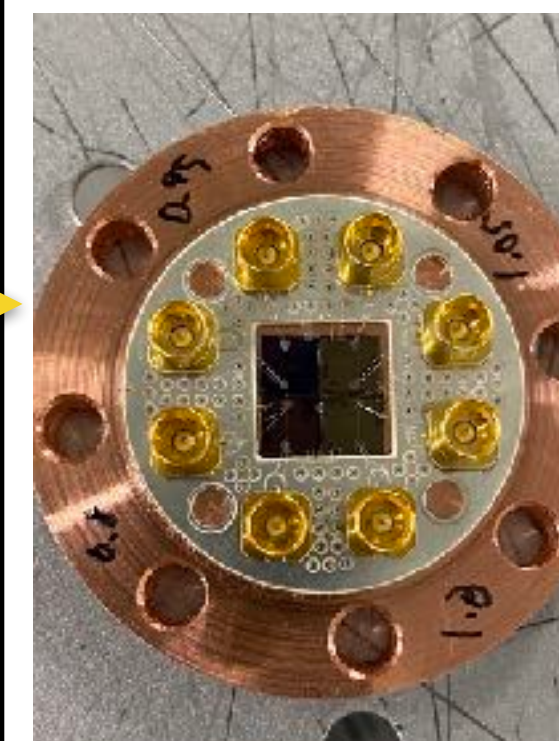
11. Dicing



12. Packaging

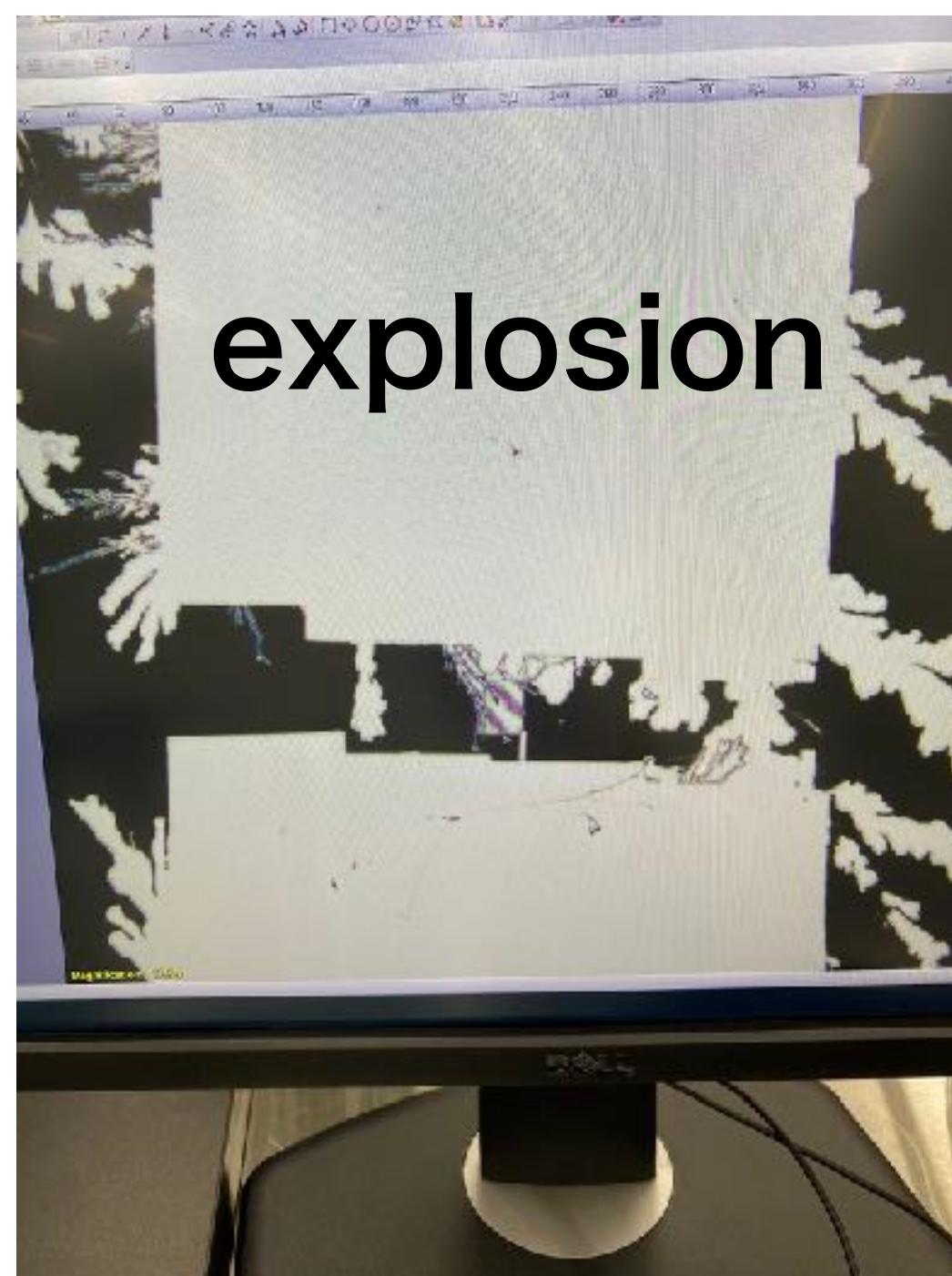
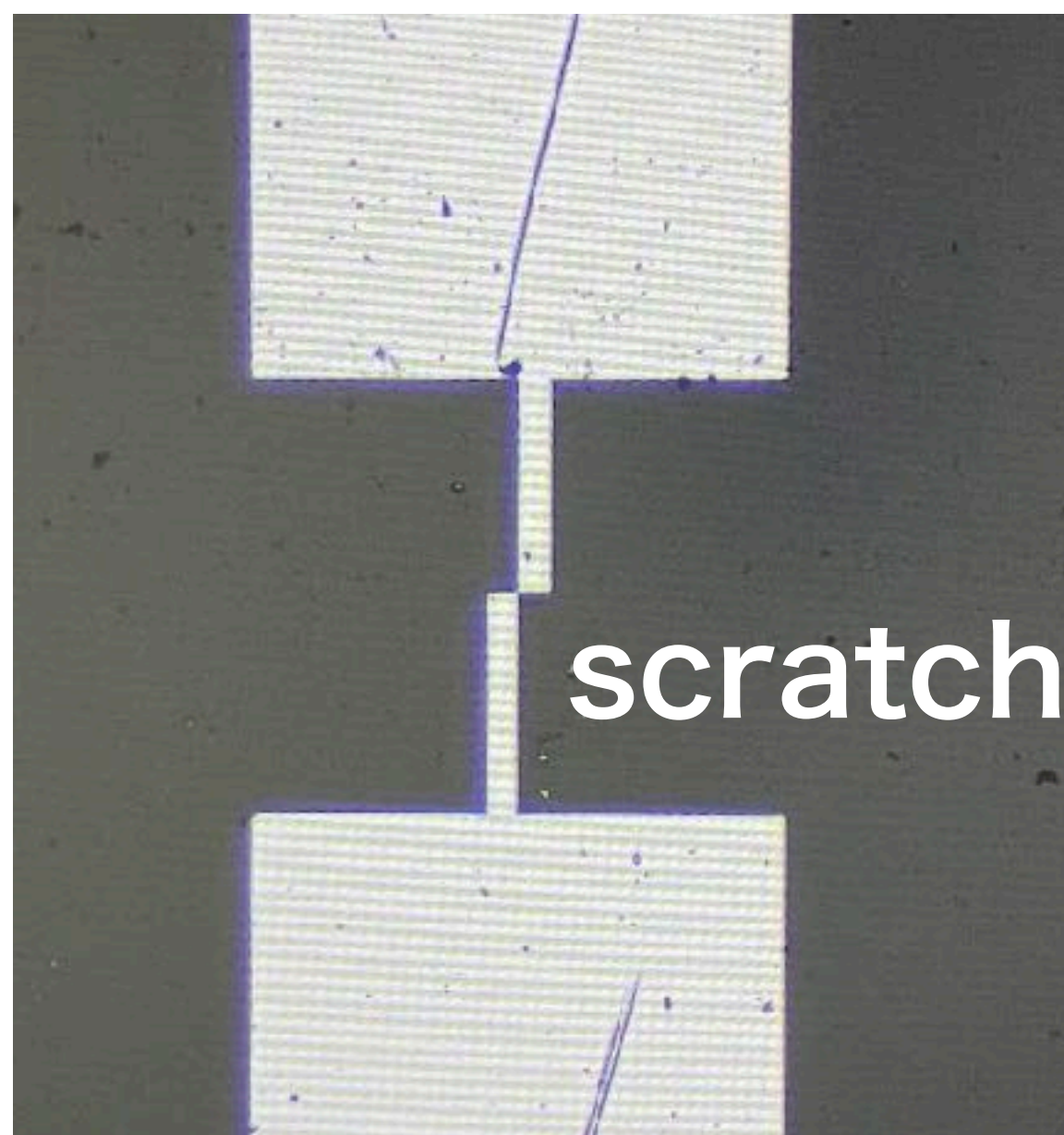
2D

3D



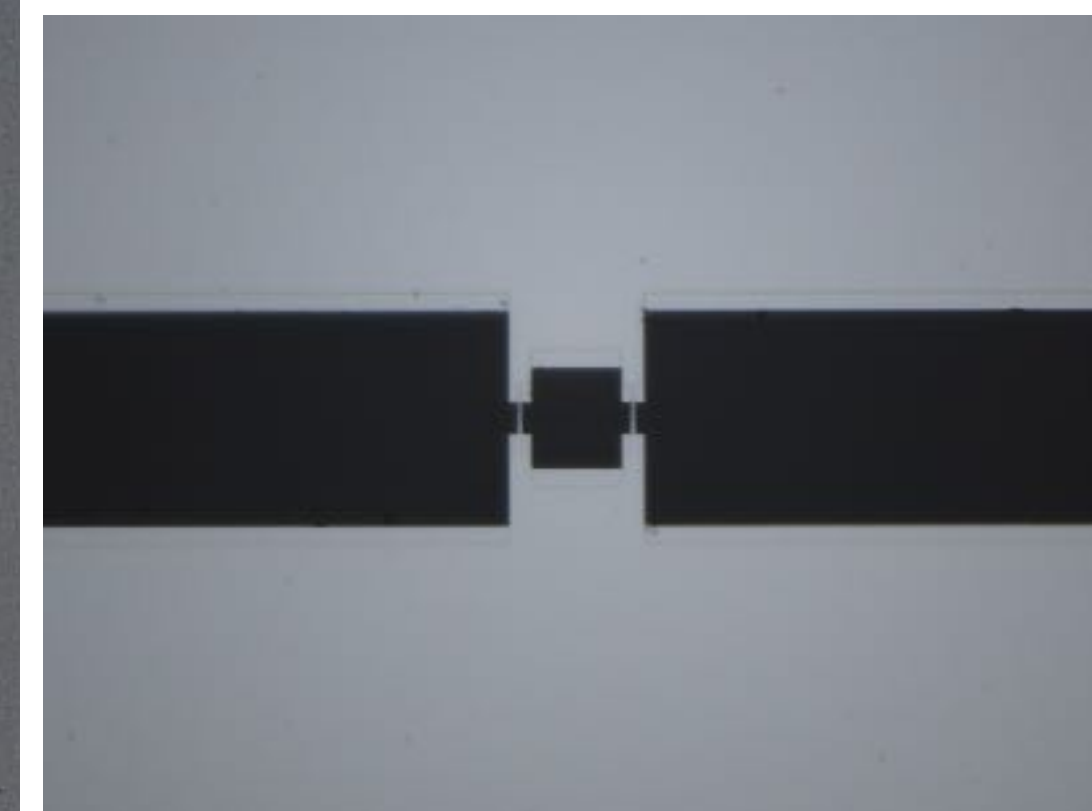
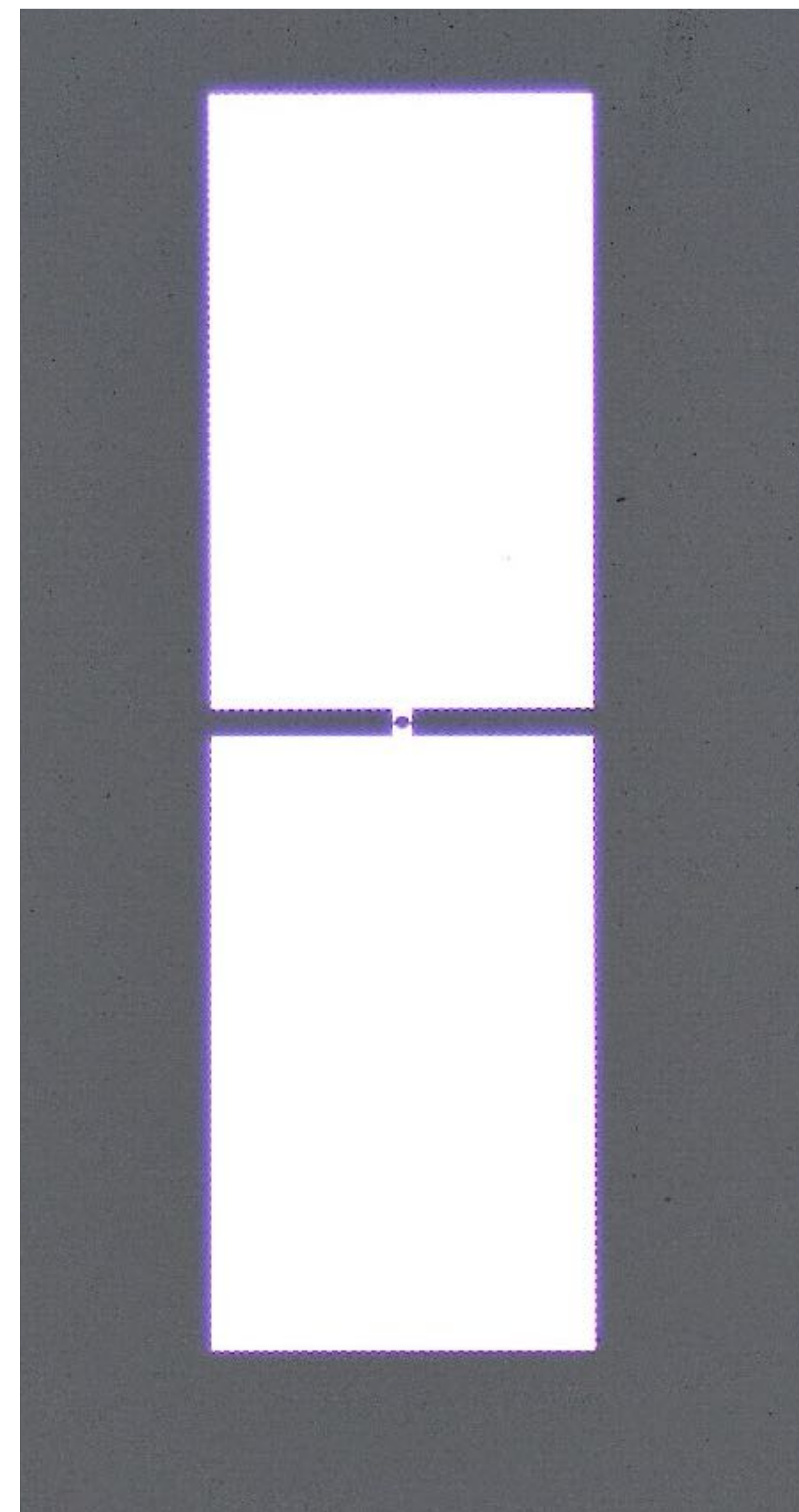
9. Microscope

Failure example



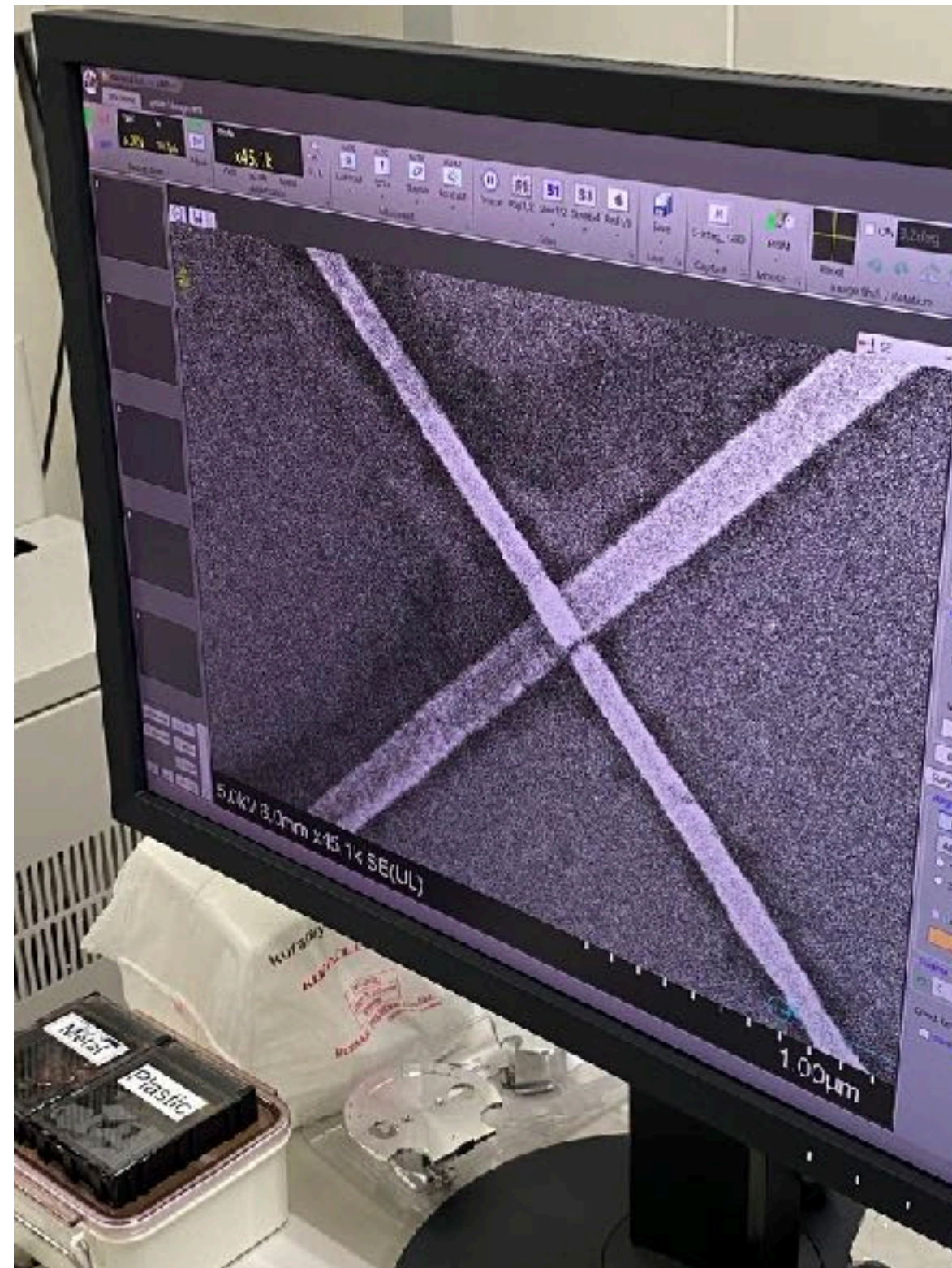
Obvious failure ones goes
to trash bin

good example



Picked up
clean ones

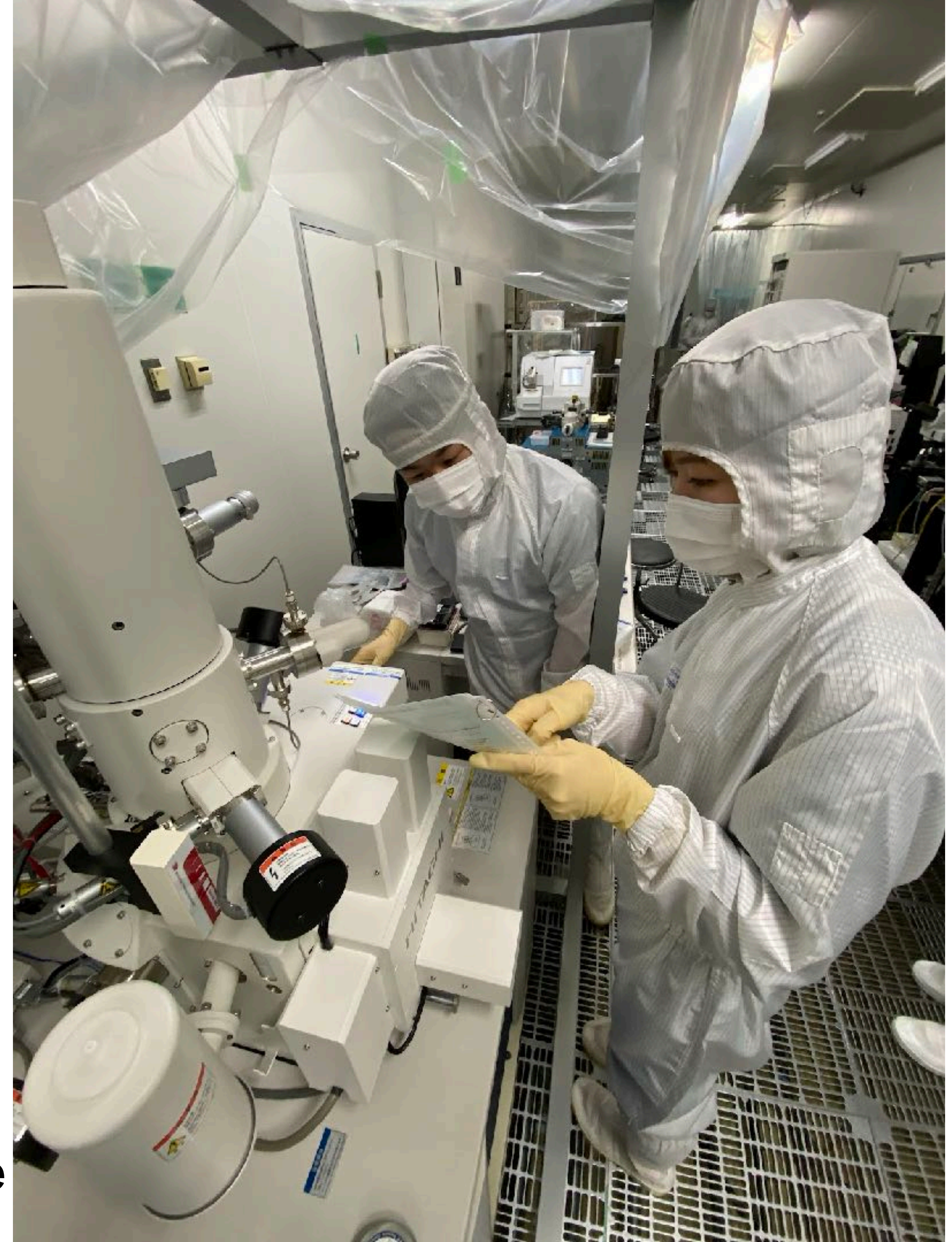
9. SEM



SEM(scanning electron microscope)

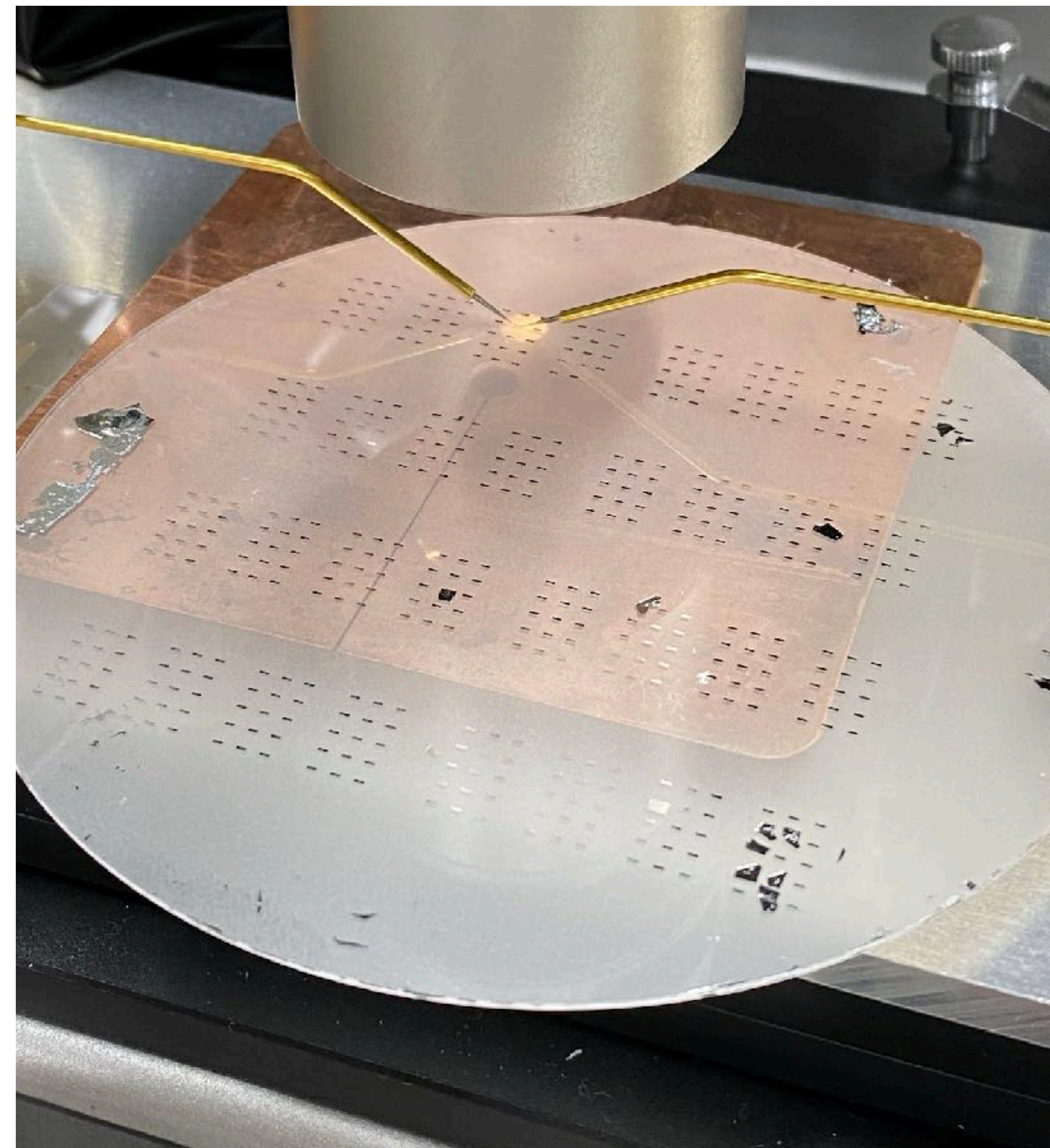
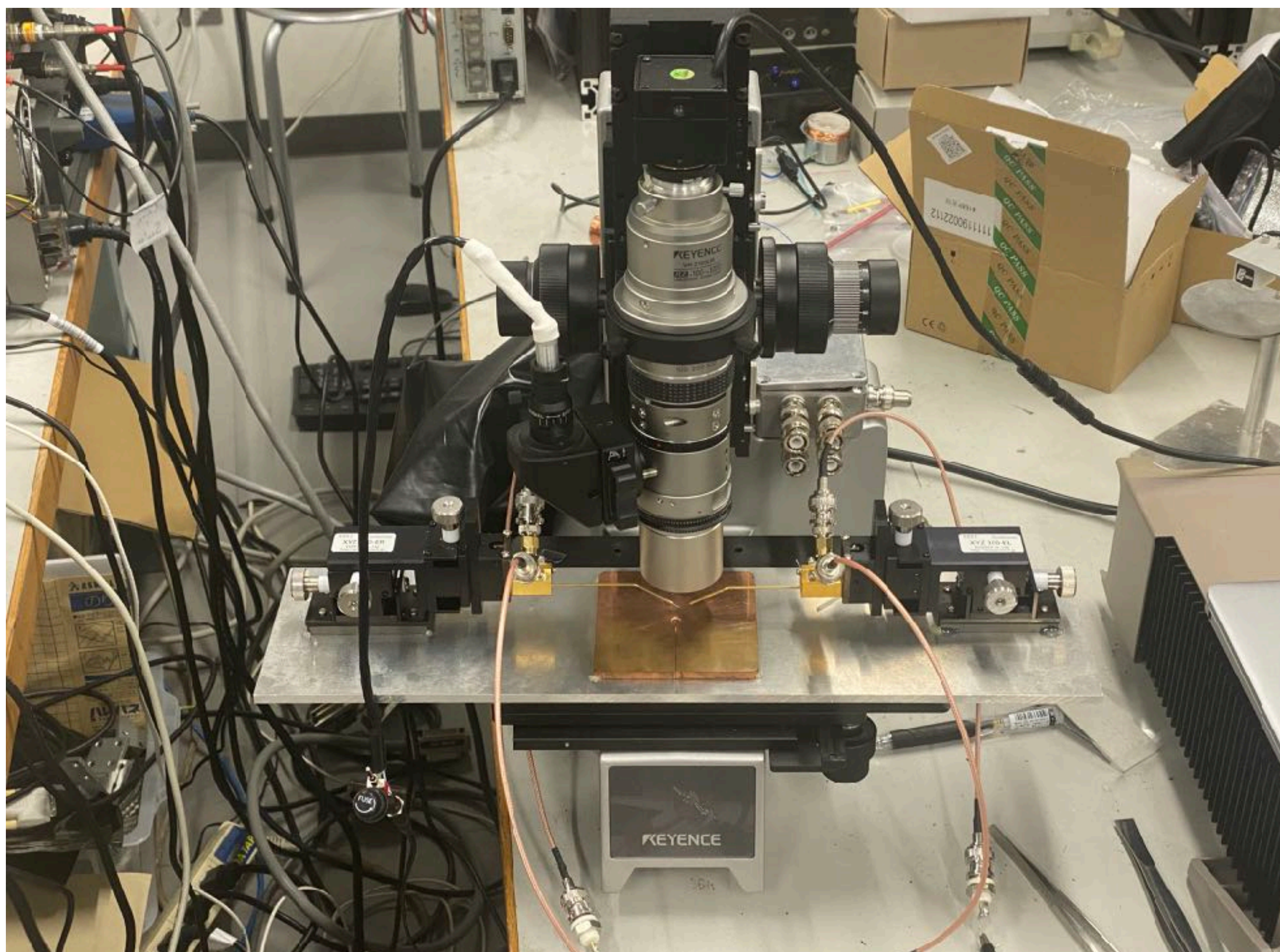
Cons: Reveal junction structure

Pros: “SEM barn” -> can’t use for real sample

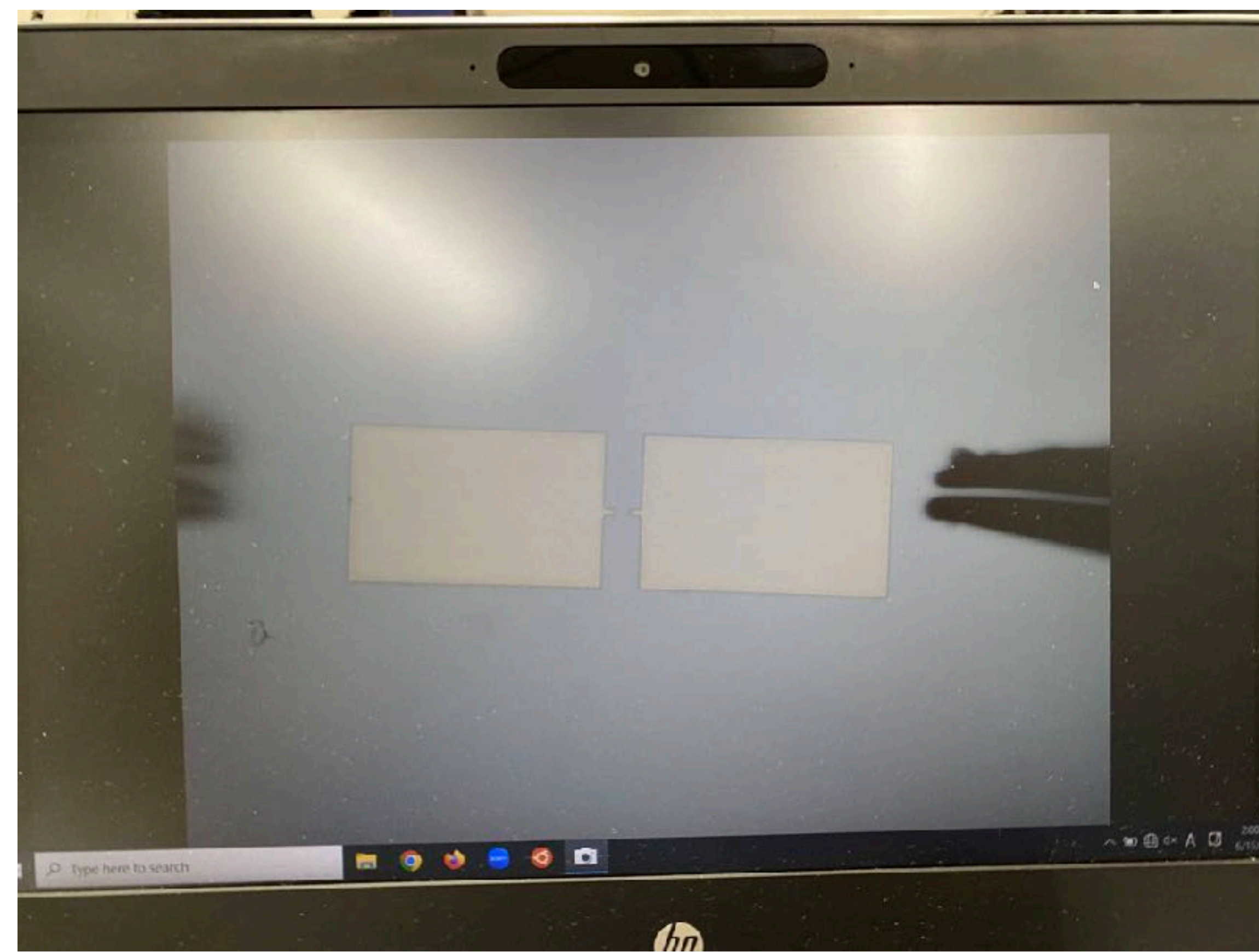
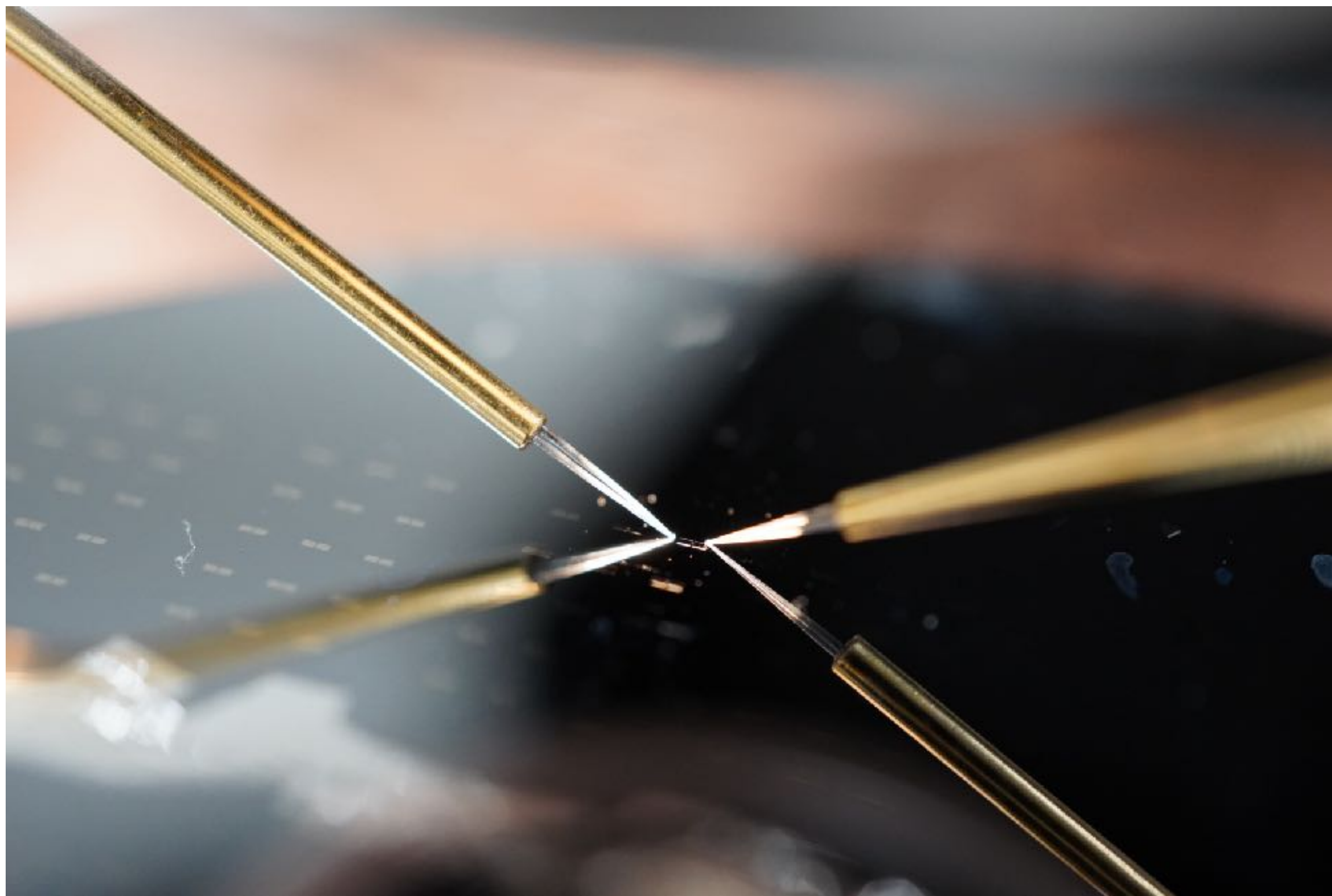


10. Resistance Measurement

Remember $E_J \sim \frac{\hbar\pi\Delta_{sc}}{4e^2R}$ Only effective test at room temperature



11. Resistance Measurement



- 4 wire measurement for precise reading
- current will be around μA (higher current burns JJ)
- Grounded by metal plate below wafer
- Minimum contact to avoid making scratch

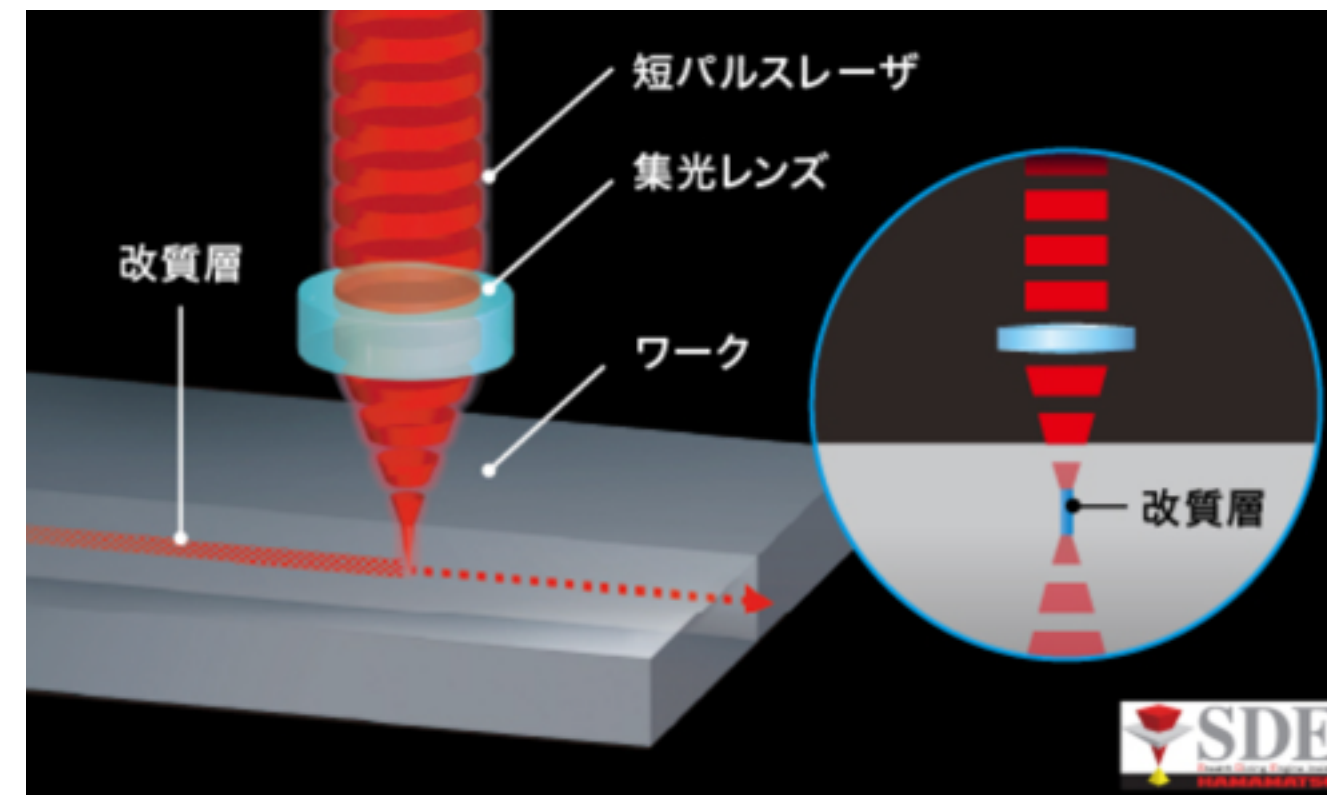
11. Dicing

Diamond cutter



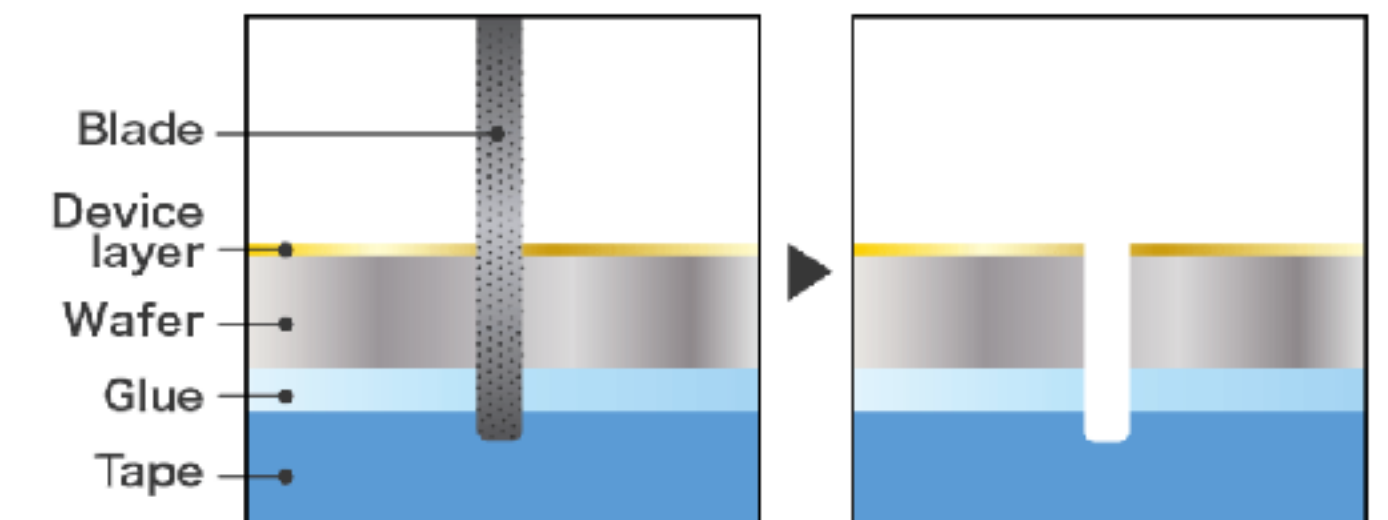
Automatic dicer

Stealth dicer



- Damage inside wafer by laser
- Expensive but clean cutting

blade dicer

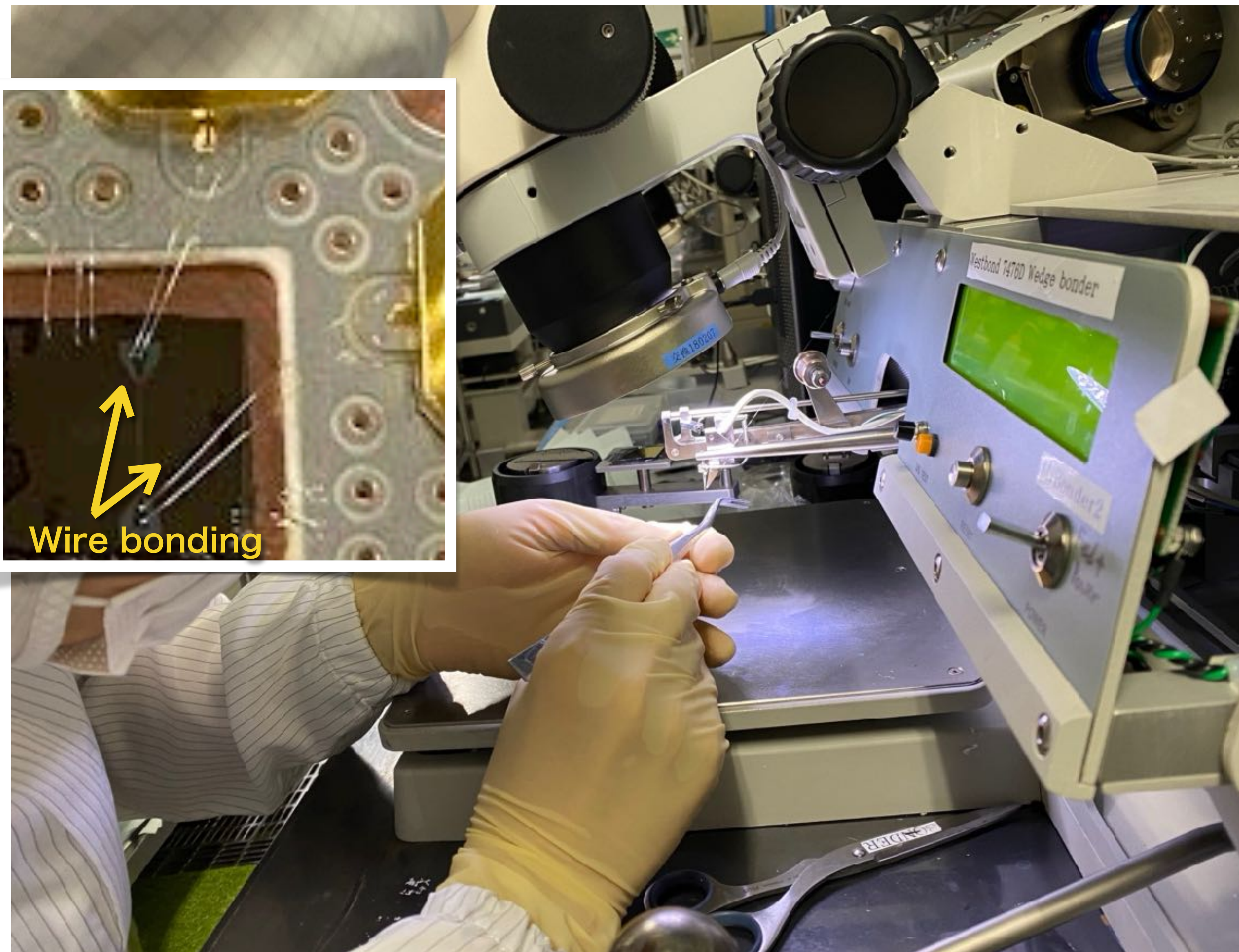
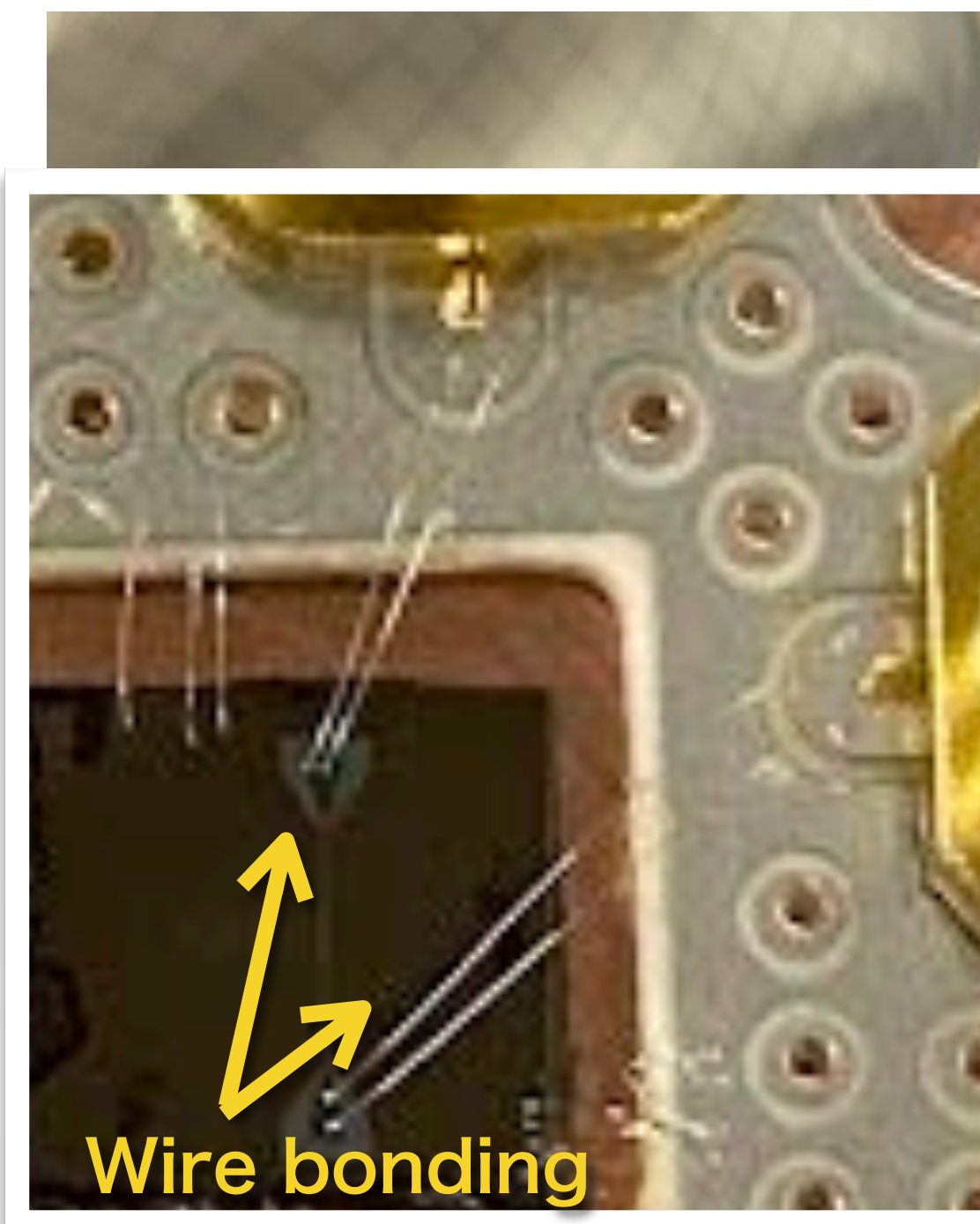
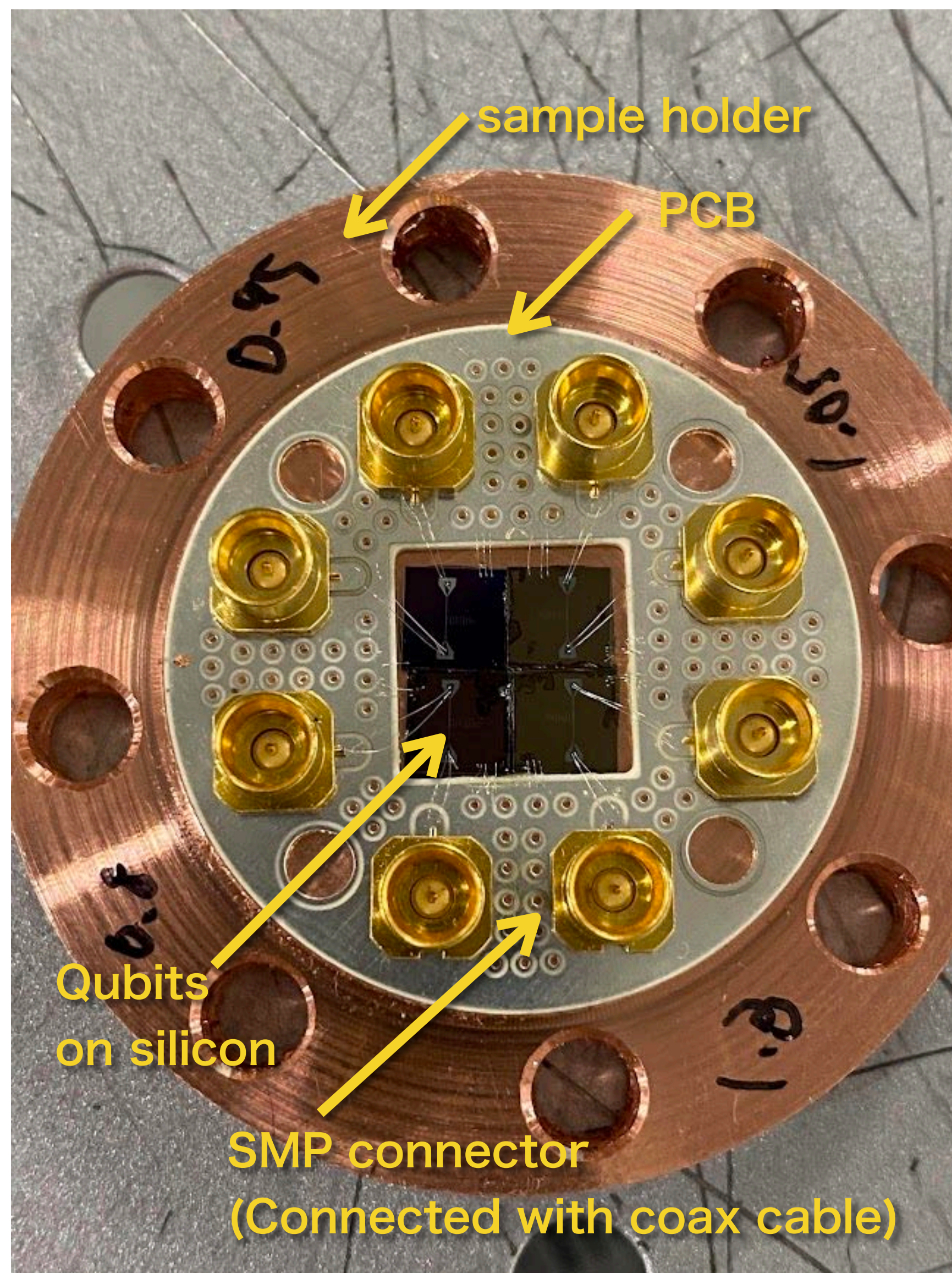


- Cutting physically by blade
- Smilier but more unclean dust and cleaning water

Looks trivial but technically difficult process

12. Wire bonding

Connecting qubit to
macroscopic coax cables

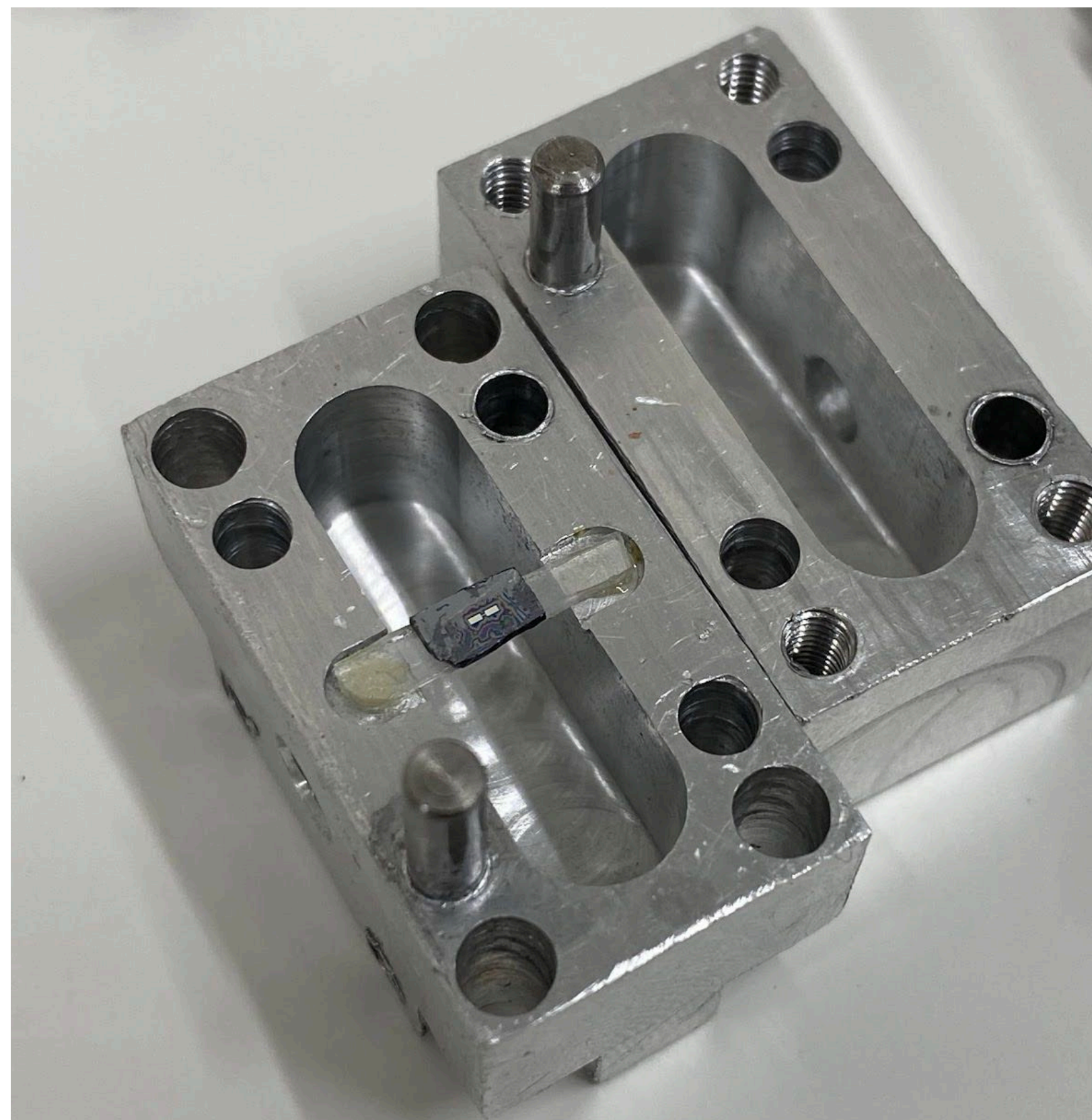


12. 3D-cavity packaging

Cavity made
by milling machine



Cu for decent cavity
Al, Nb for high quality ones



Loading qubit
on cavity

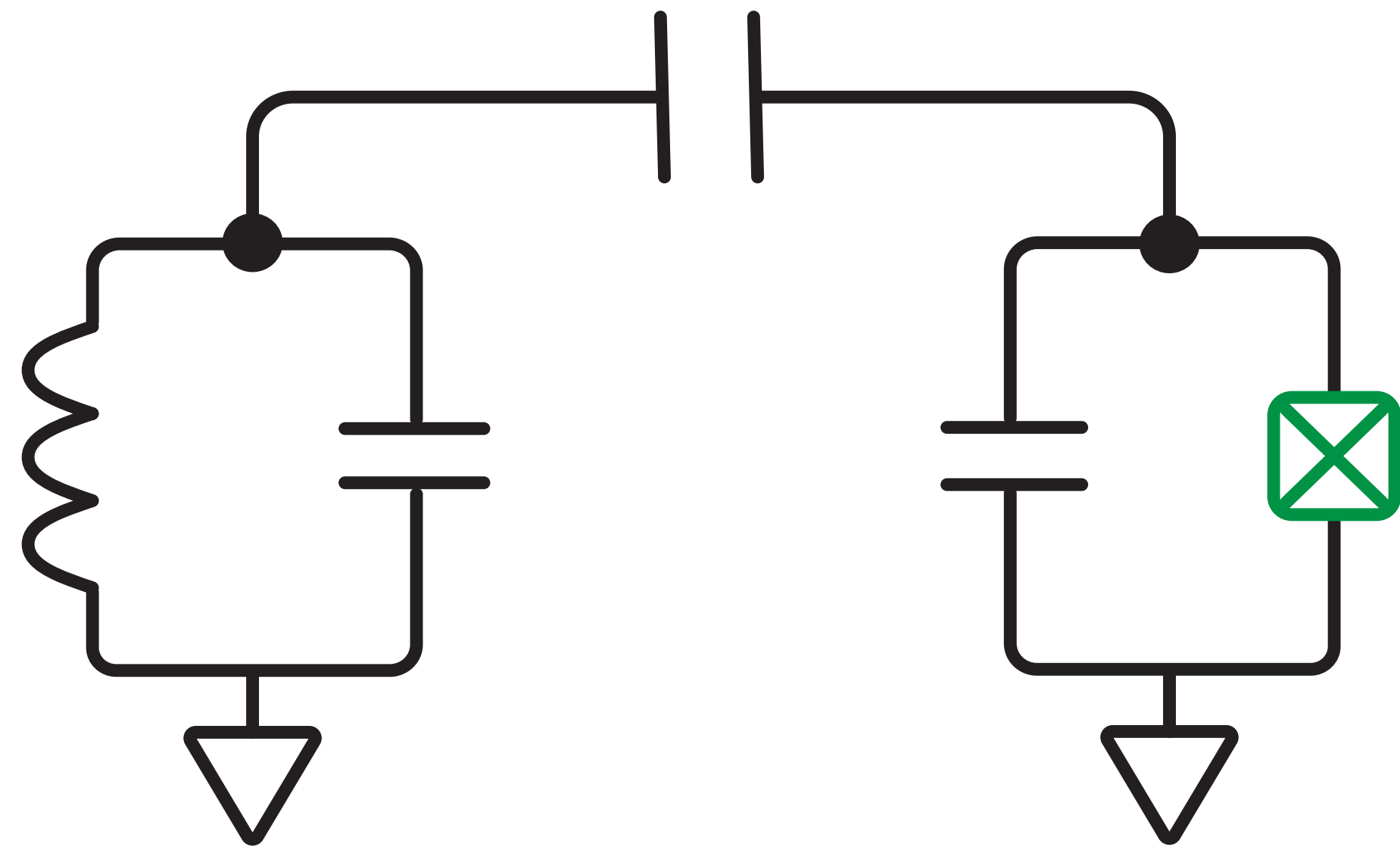


Ready to measurement!

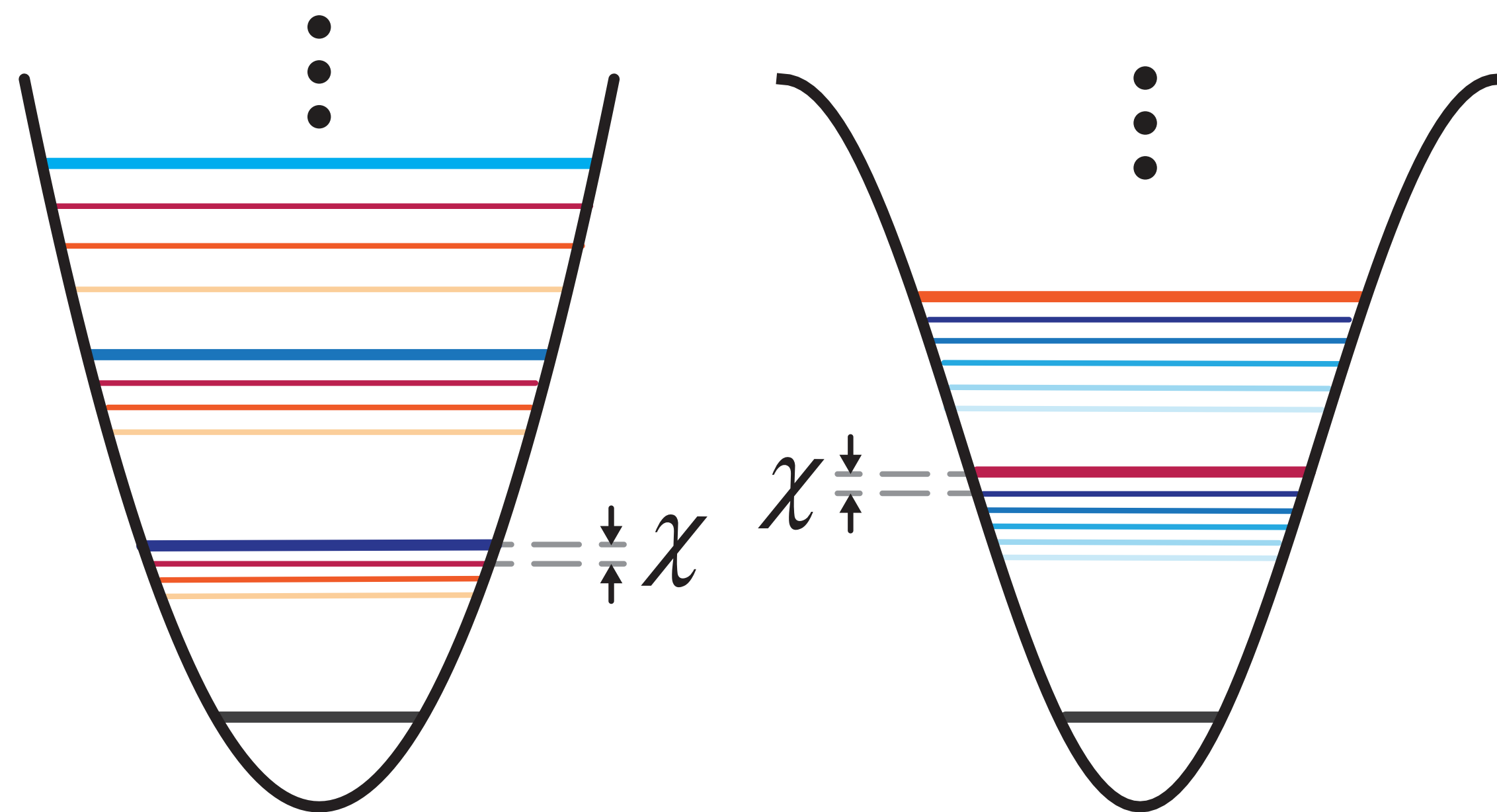
Introduced basic process to make a superconducting qubit

Next lecture shows how to measure these qubits

Backup

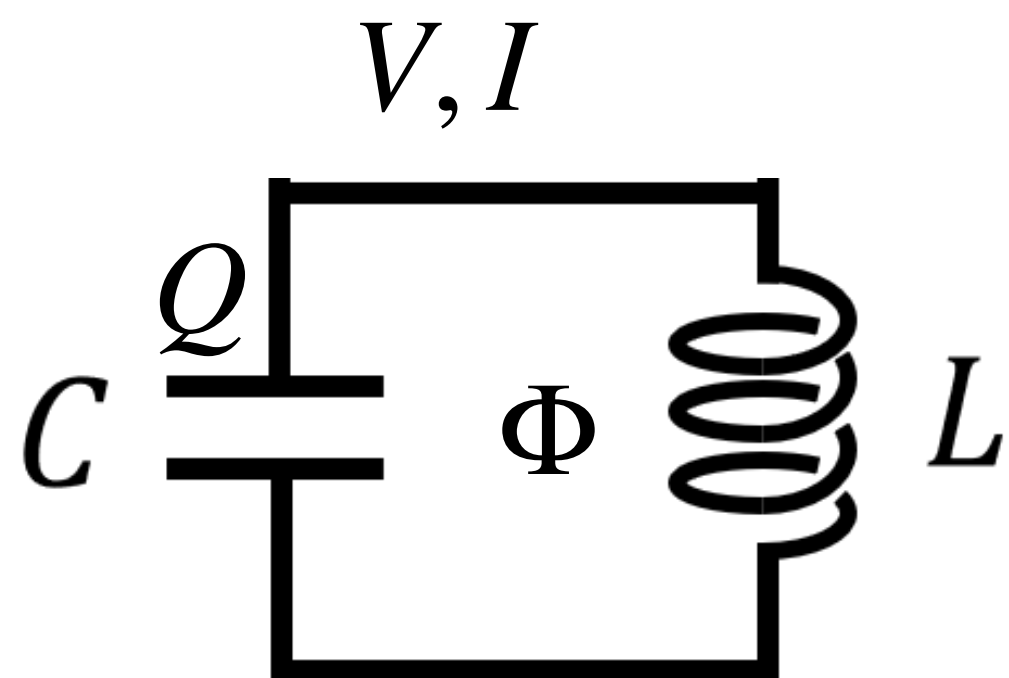


超伝導量子ビットの基礎



LC共振器の量子化

手始めに、おなじみのLC共振回路を量子化してみる。



共振周波数 $1/2\pi\sqrt{LC}$

キャパシタの電荷 Q と共振回路を貫く磁束 Φ は

$$Q = CV, \quad \Phi = LI$$

また

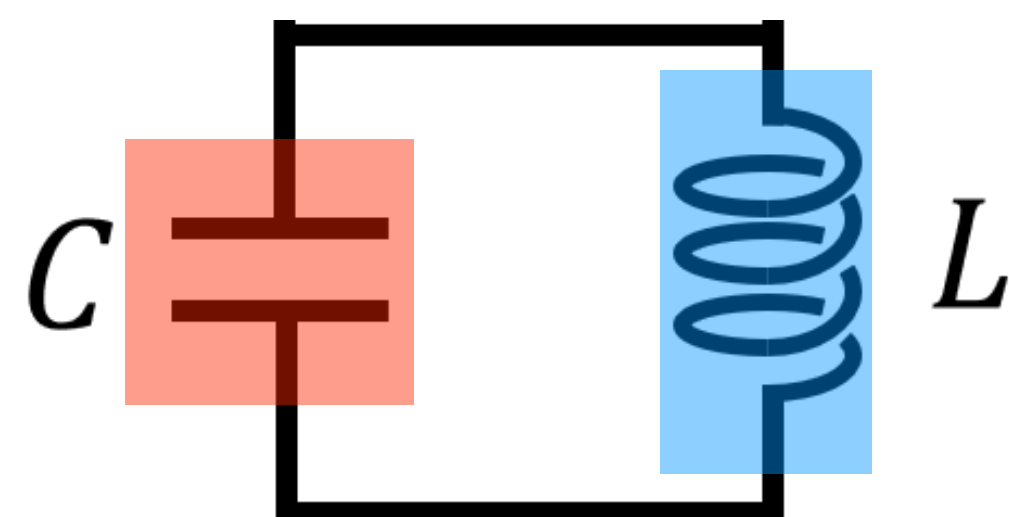
$$I = \frac{dQ}{dt}, \quad V = \frac{d\Phi}{dt}$$

なので

$$\frac{d^2Q}{dt^2} = -\frac{Q}{LC}, \quad \frac{d^2\Phi}{dt^2} = -\frac{\Phi}{LC}$$

LC共振器の量子化

ラグランジアンとハミルトニアンはそれぞれ



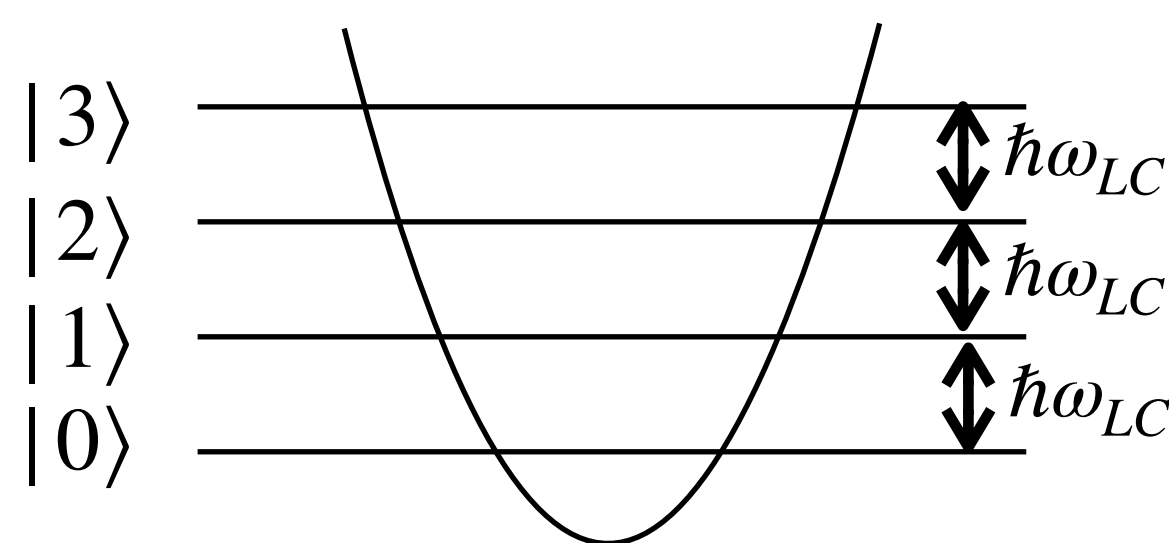
$$\mathcal{L} = \frac{Q^2}{2C} - \frac{L}{2} \left(\frac{dQ}{dt} \right)^2, \quad \mathcal{H}_{LC} = \frac{Q^2}{2C} + \frac{\Phi^2}{2L}$$

共振器内の光子の生成・消滅演算子を

$$a = \frac{1}{2\hbar} \sqrt{\frac{L}{C}} Q + \frac{i}{2\hbar} \sqrt{\frac{C}{L}} \Phi, \quad a^\dagger = \frac{1}{2\hbar} \sqrt{\frac{L}{C}} Q - \frac{i}{2\hbar} \sqrt{\frac{C}{L}} \Phi$$

とすると交換関係は $[a, a^\dagger] = 1$ 、 $\mathcal{H}_{LC} = \hbar\omega_{LC} \left(a^\dagger a + \frac{1}{2} \right)$

基底状態付近のエネルギー



注) $|0\rangle$ のエネルギーは不確定性関係より0でない

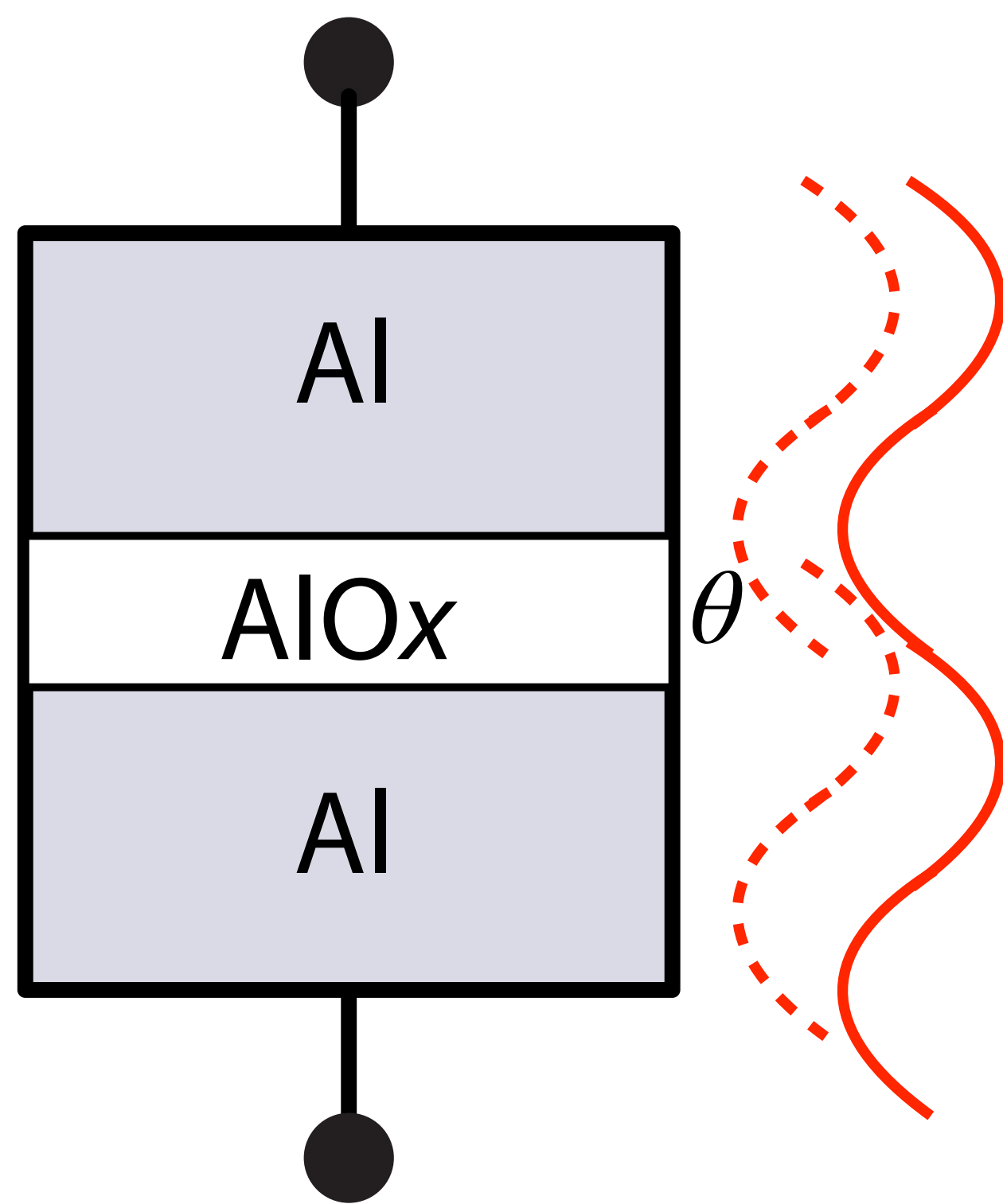
$$\Delta Q \cdot \Delta \Phi > \frac{1}{2}$$

ただしこれでは $|0\rangle$ と $|1\rangle$ の操作が極めて難しい

エネルギーギャップ ($\hbar\omega_{LC}$) が等間隔のため

エネルギーギャップを変えるために、LかCに非線形性を導入。

ジョセフソン接合



Al: $T_C = 1.2 \text{ K}$

- 超伝導-絶縁体-超伝導のサンドイッチを作る
- 冷やすと超伝導体が1つの巨大な物質波を形成
(ボースアインシュタイン凝縮)
- 隣接した超伝導体はそれぞれ異なった位相を持つ
→位相差を吸収するために電流が流れる。

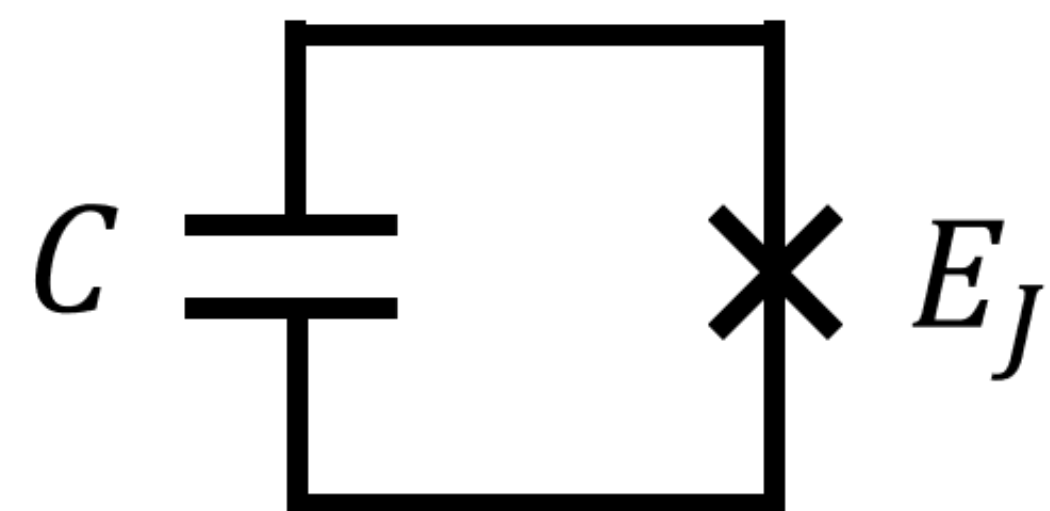
定量的にジョセフソン関係:

$$I = I_0 \sin \theta$$

$$V = \frac{\hbar}{2e} \frac{\partial \theta}{\partial t}$$

非線形LC共振器の量子化

$\Phi_0 = h/2e$ を使って、磁束を $\Phi_J = (\theta/2\pi)\Phi_0$ と定義すると



$$I = I_0 \sin \theta, \quad V = \frac{\hbar}{2e} \frac{\partial \theta}{\partial t} \rightarrow I = I_0 \sin \left(2\pi \frac{\Phi_J}{\Phi_0} \right), \quad V = \frac{d\Phi_J}{dt}.$$

$Q = CV$ より、

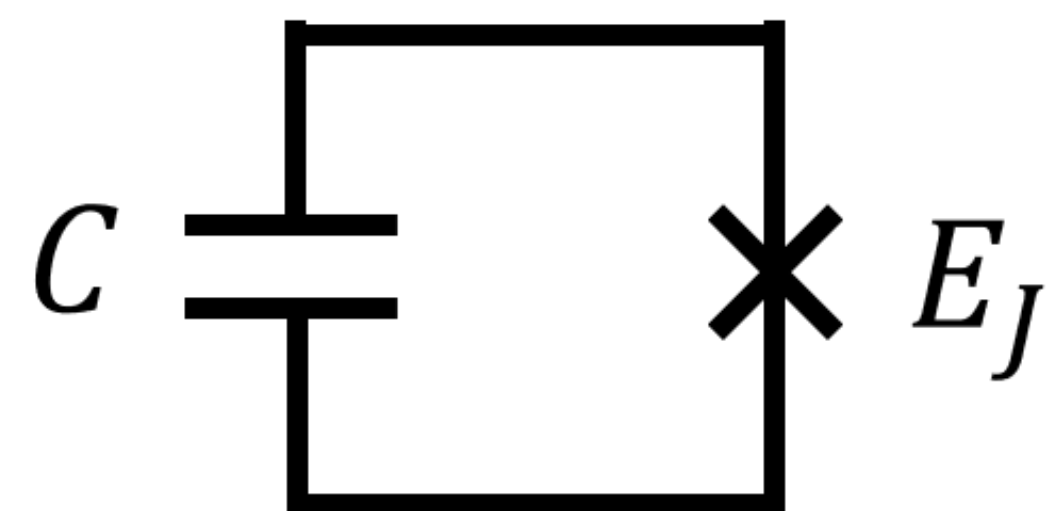
$$\frac{dQ}{dt} = C \frac{dV}{dt} = -I_0 \sin \left(2\pi \frac{\Phi_J}{\Phi_0} \right)$$

$$\rightarrow C \frac{d^2 \Phi_J}{dt^2} = -I_0 \sin \left(2\pi \frac{\Phi_J}{\Phi_0} \right)$$

Lagrange方程式

非線形LC共振器の量子化

Lagrangianは



$$\mathcal{L}_q = \frac{C}{2} \left(\frac{d\Phi_J}{dt} \right)^2 + \frac{I_0 \Phi_0}{2\pi} \cos \left(2\pi \frac{\Phi_J}{\Phi_0} \right)$$

$$= \frac{Q^2}{2C} + \frac{I_0 \Phi_0}{2\pi} \cos \left(2\pi \frac{\Phi_J}{\Phi_0} \right)$$

ここで $E_J = I_0 \Phi_0 / 2\pi$ (Josephson Energy),

$E_C = e^2 / 2C$ (Charge Energy),

$n_C = Q / 2e$ (Cooper対の個数)

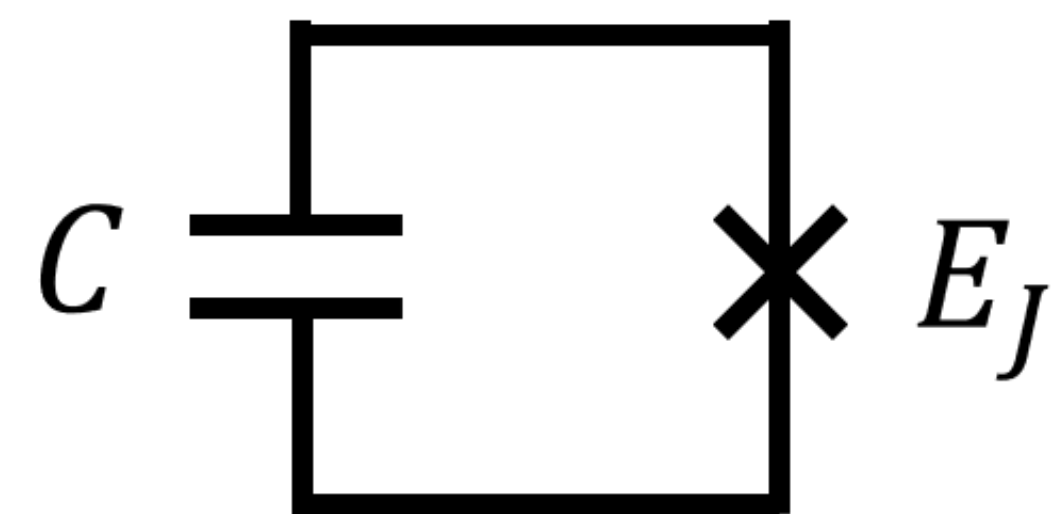
を導入すると、 (Legendre変換より)

ハミルトニアンがかけた

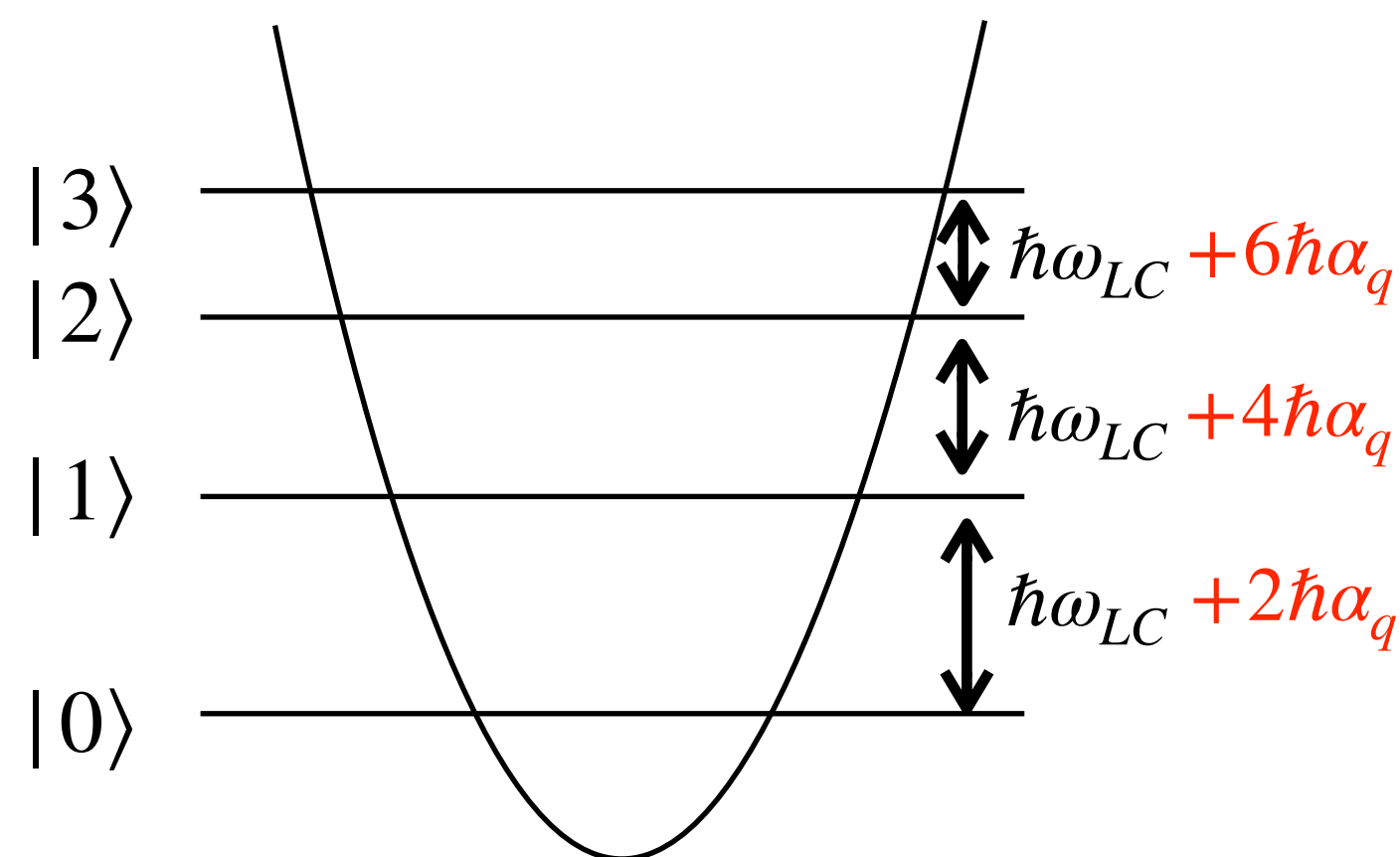
$$\mathcal{H}_q = 4E_C n_C^2 + E_J \cos \theta$$

非線形LC共振器の量子化

生成消滅演算子は



$$n_C = \left(\frac{E_J}{8E_C} \right)^{\frac{1}{4}} \frac{a + a^\dagger}{\sqrt{2}}, \quad \theta = \left(\frac{8E_C}{E_J} \right)^{\frac{1}{4}} \frac{a - a^\dagger}{i\sqrt{2}}$$



$$\mathcal{H}_q = (\sqrt{8E_C E_J} - E_C) a^\dagger a - \frac{E_C}{2} a^\dagger a^\dagger a a$$

$$= \hbar\omega_q a^\dagger a + \frac{\hbar\alpha_q}{2} a^\dagger a^\dagger a a$$

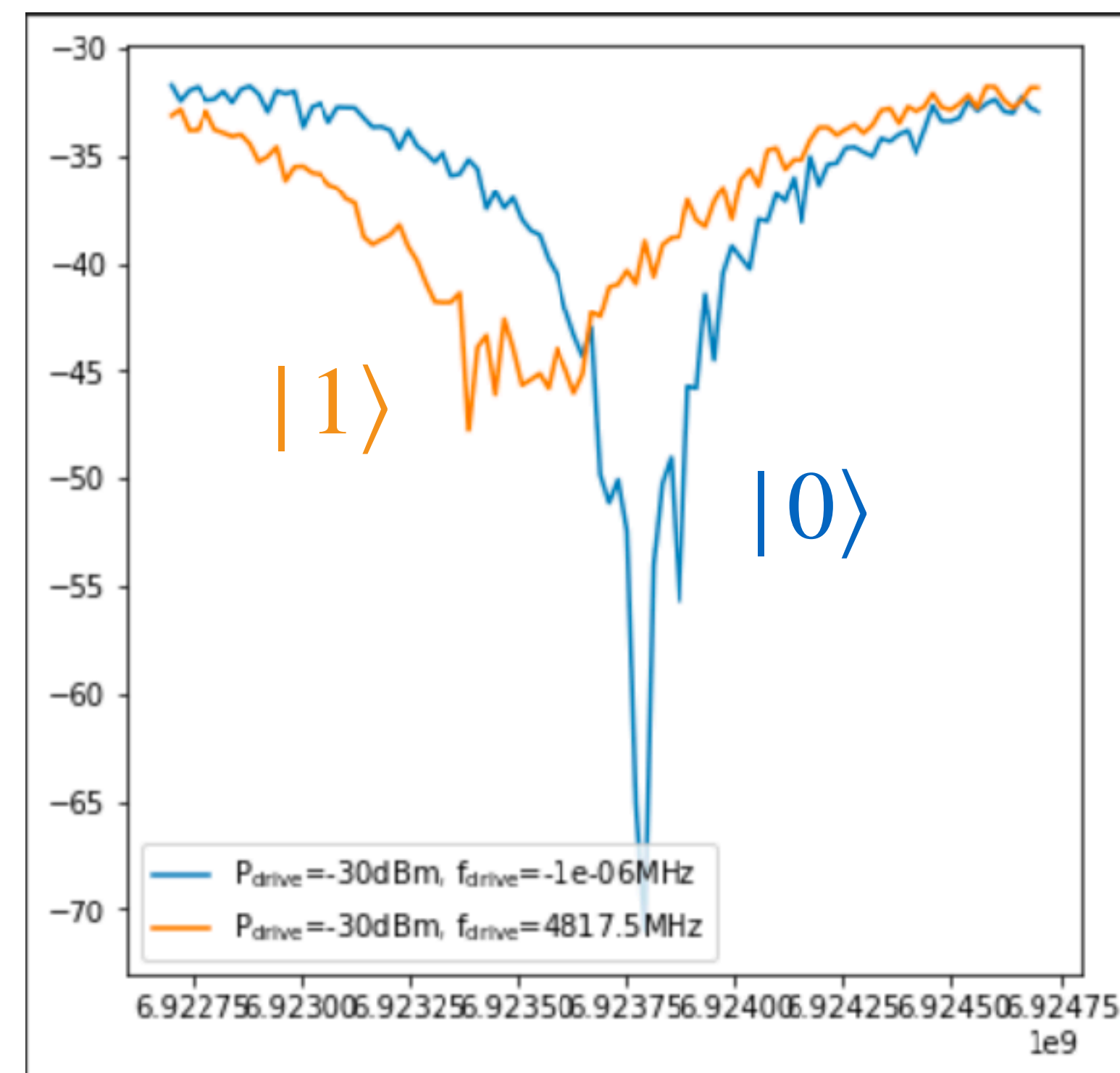
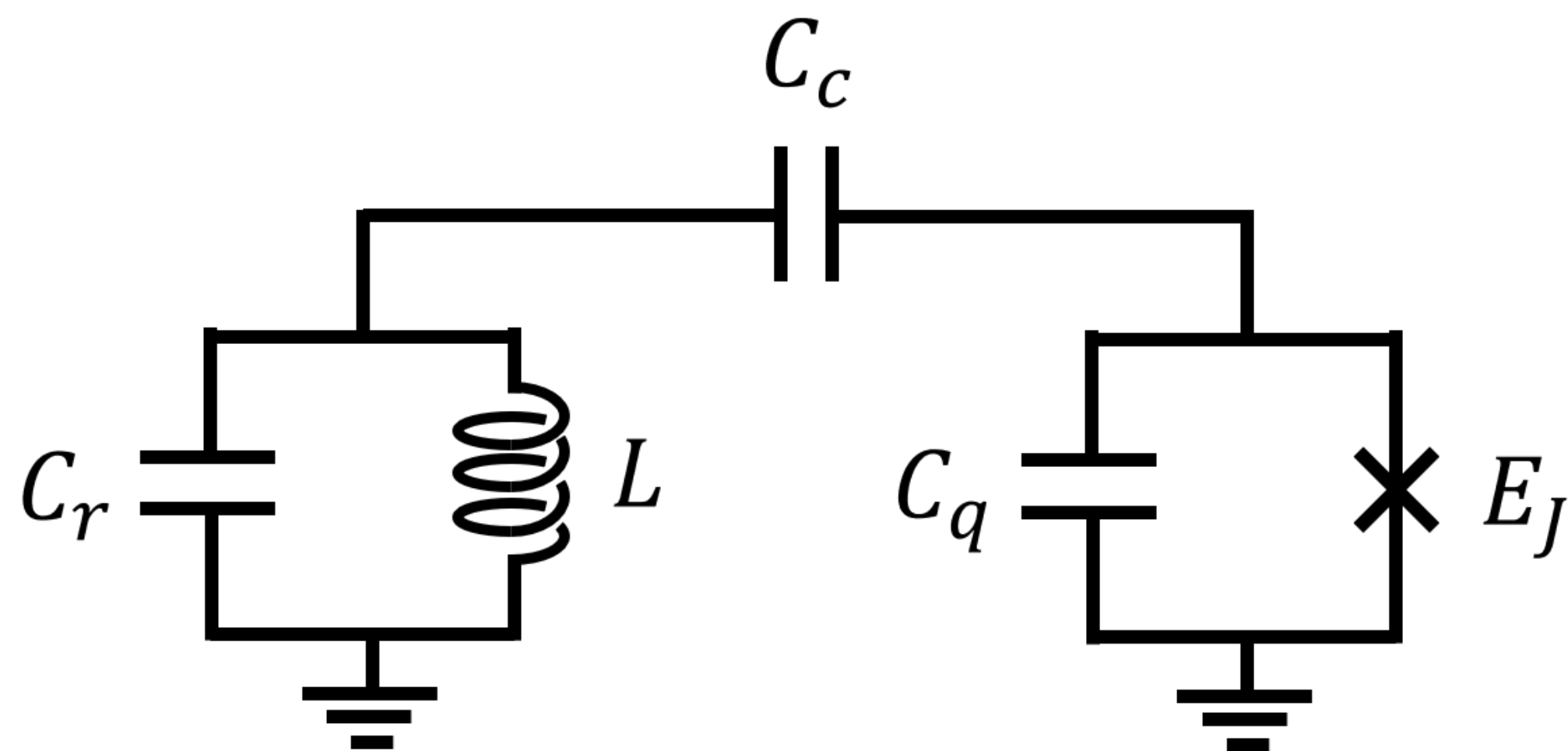
$E_J/E_C \gg 1$ として

$\cos \theta \simeq 1 - \theta^2/2! + \theta^4/4!$ を使っている

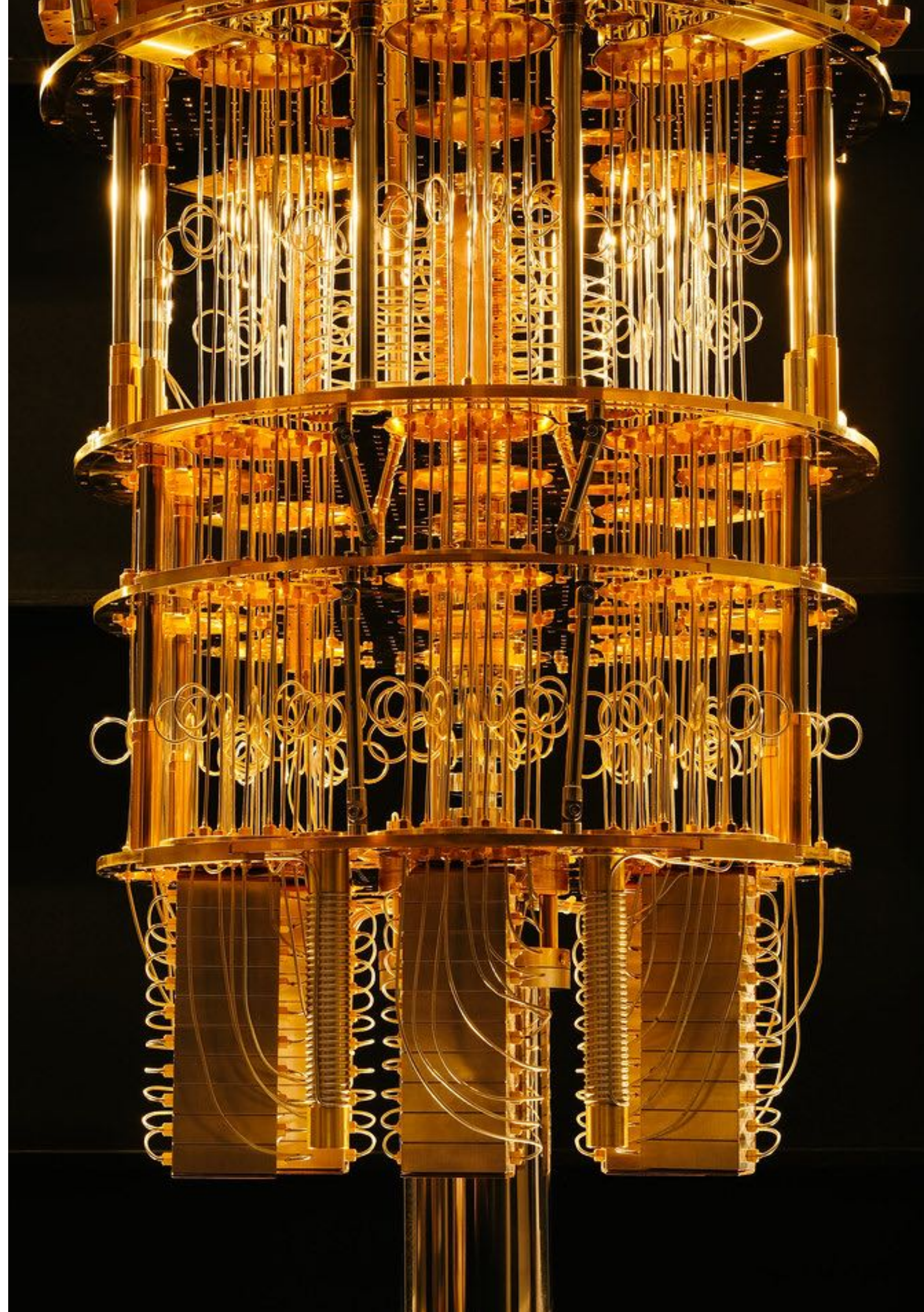
ジョセフソン接合によって、扱いやすい2準位系ができた。
これをトランズモンという。

トランズモンとLC共振器の結合

トランズモンの電荷等を直接読みだそうとすると壊れやすいので、分散シフト読み出しを通常おこなう。



測定系



極低温（mK）の必要性

1. ジョセフソン接合を超伝導温度まで下げたい
アルミの転移温度 ~ 1.2 K
2. 分散読み出しはqubitの状態を変えないように
低いエネルギーを当てる。
熱ノイズが温度に比例

$$P = k_b b T$$

通常の実験は~10 mKでおこなっている

冷やす方法

到達温度	手法
77K	液体窒素
4.2 K	液体ヘリウム4
1 K	液体ヘリウム4の減圧排気
0.3 K	液体ヘリウム3の減圧排気
5 mK	希釈冷凍機
1 μ K	断熱消磁

千円?

数十万?

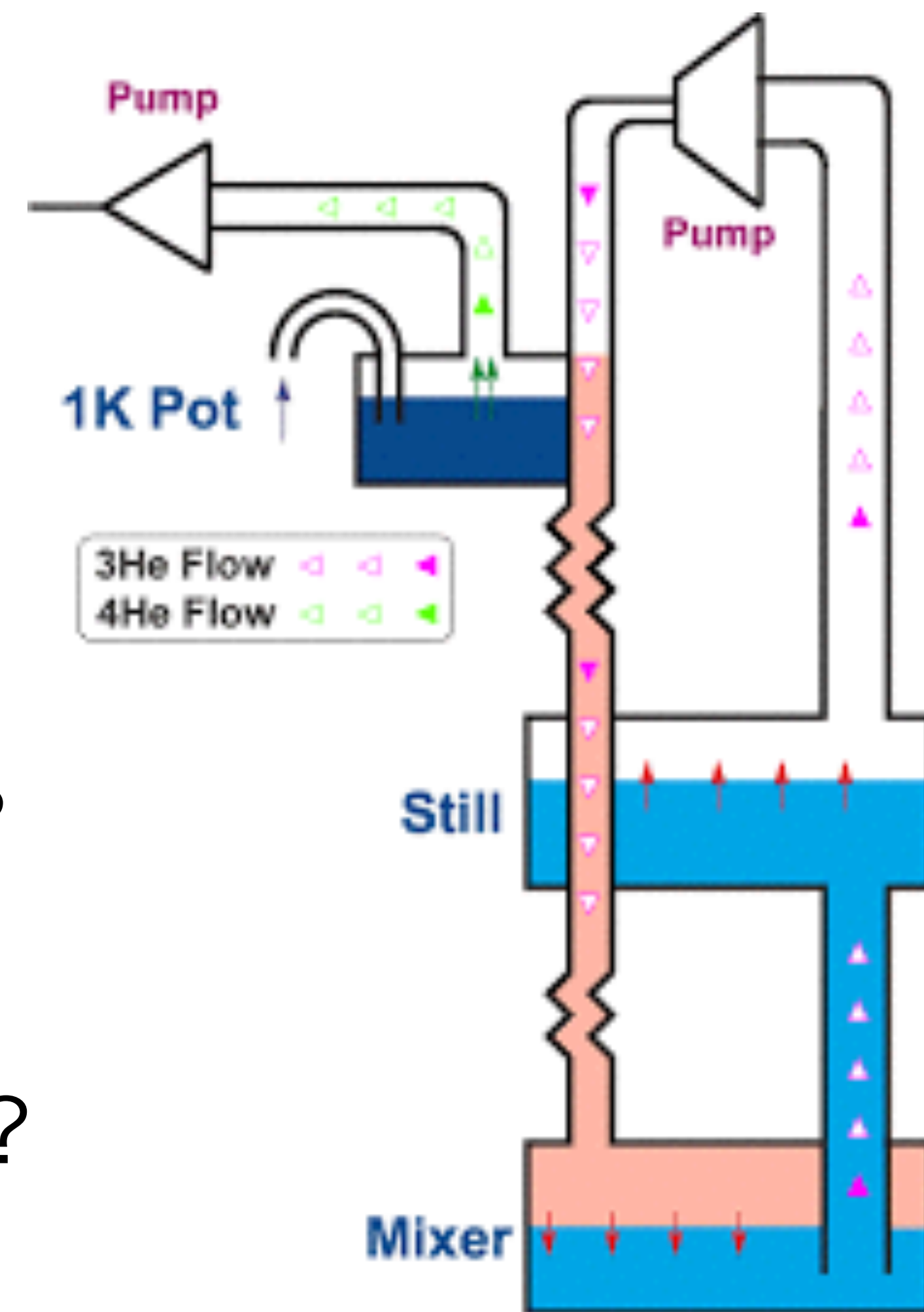
100万円?

1000万円?

1億円?

1000万円?

希釈冷凍機

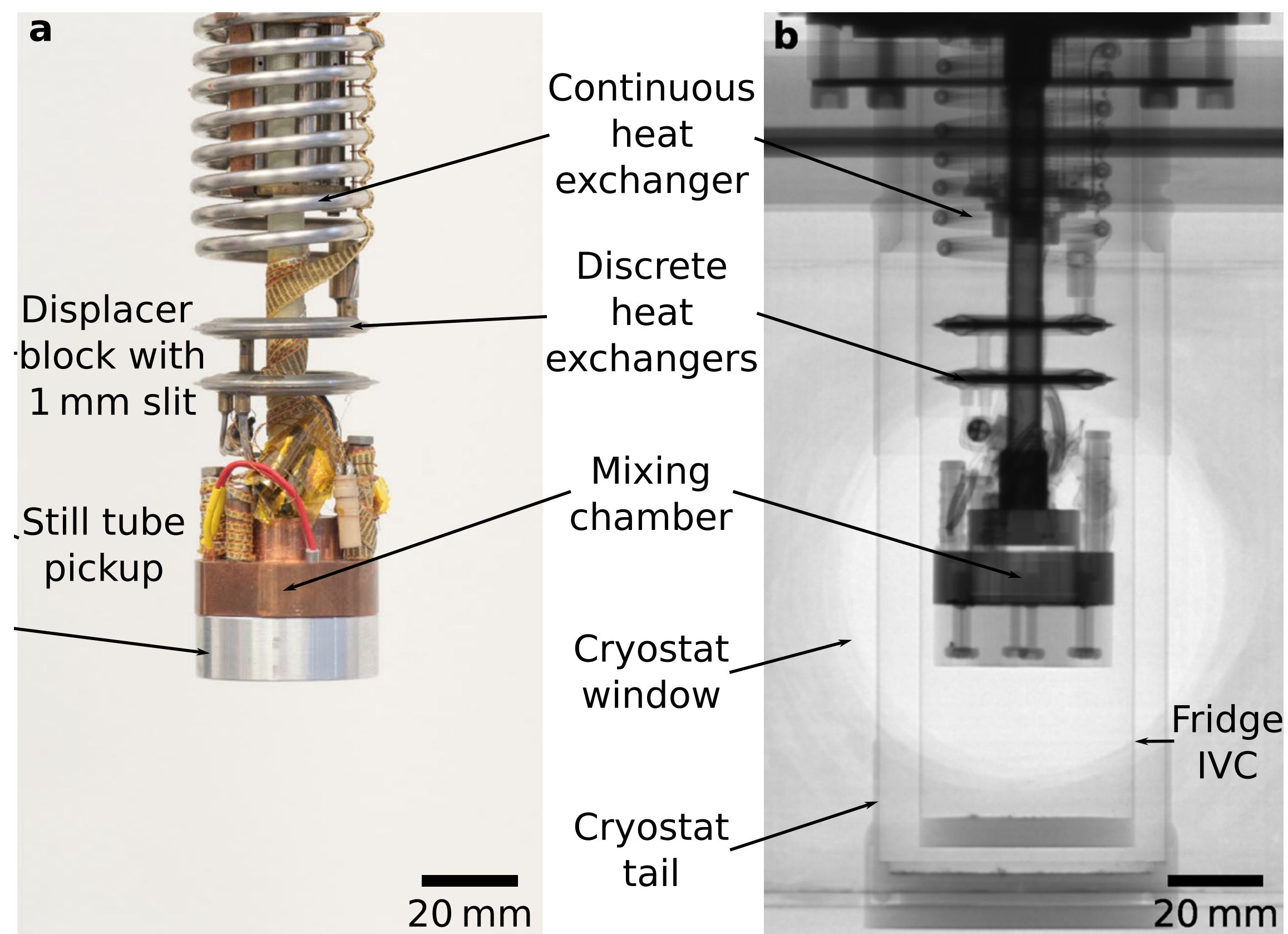


希釈冷凍機

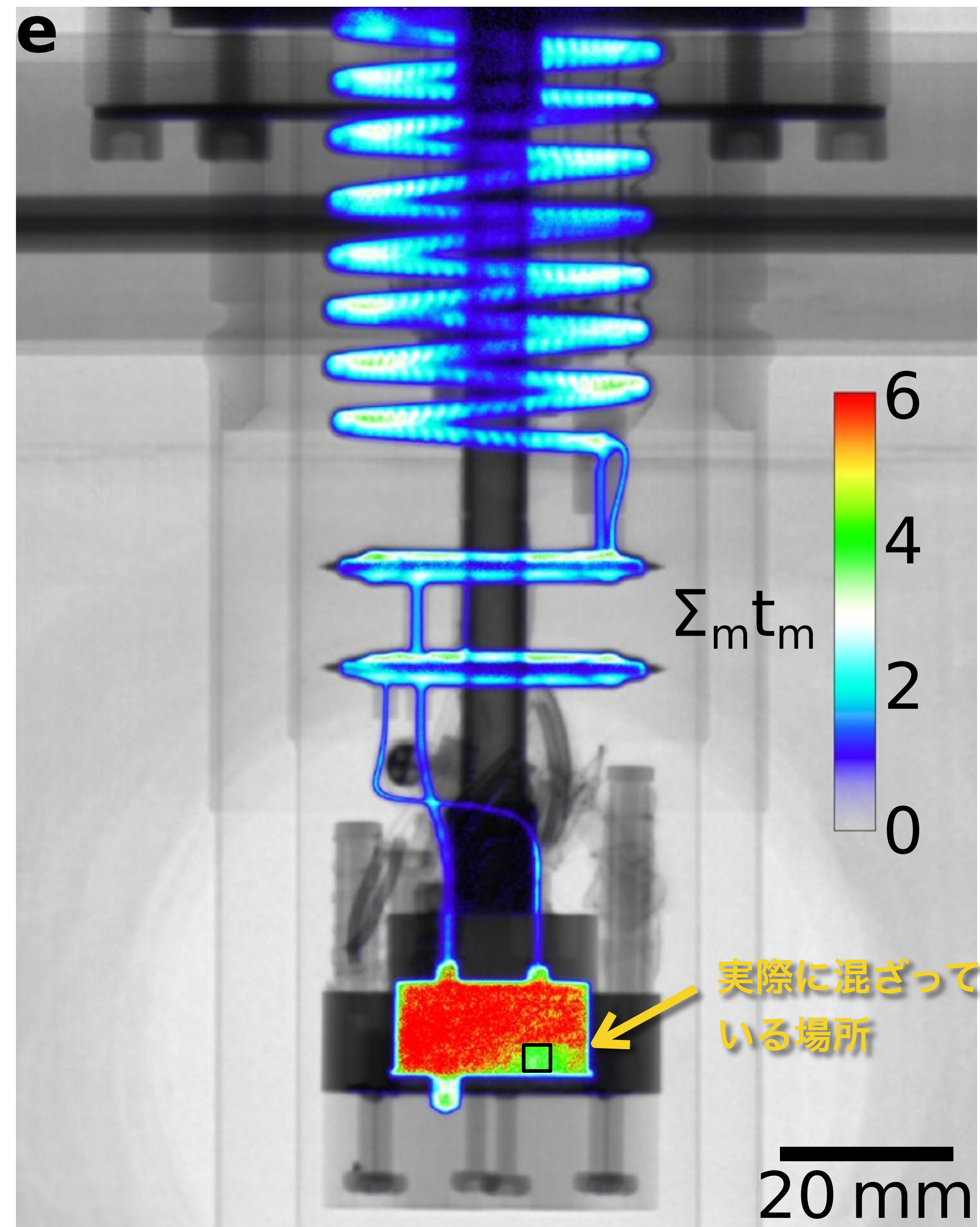
[Scientific Reports](#)

volume

12, Article number: 1130 (2022)



中性子線写真で実写した動作途中の
希釈冷凍機



熱の制御

主に3つ

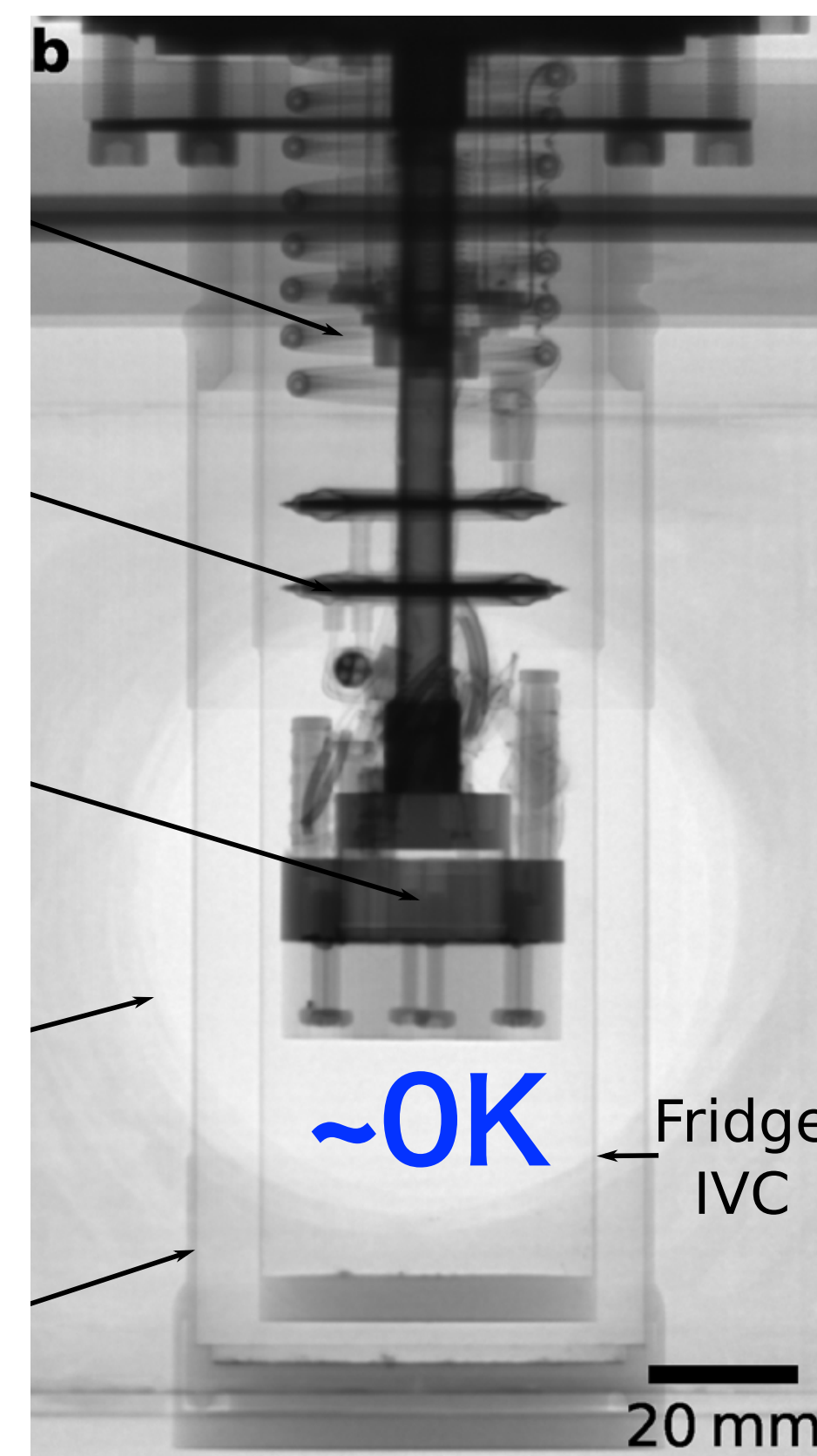
- conductive heat (伝導)
- convecting heat (対流)
- radiative heat (放射)



この状況を作り出す

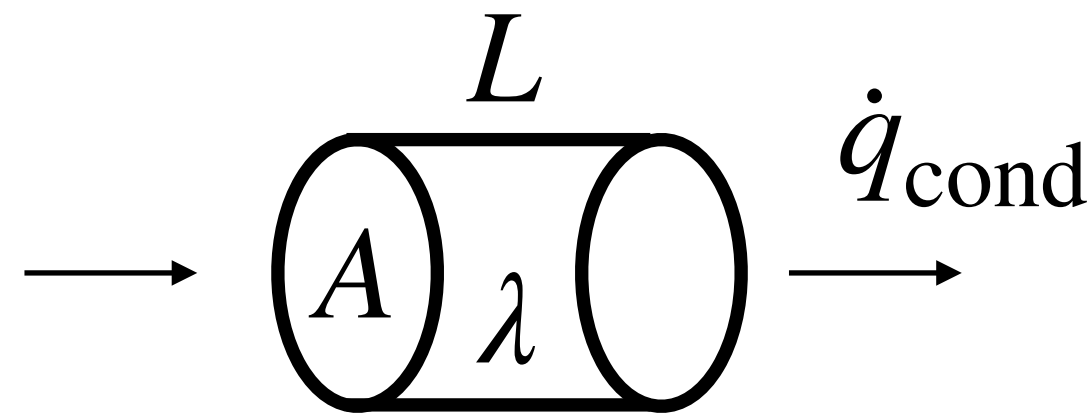
希釈冷凍機の冷凍性能

100-1000 μW



恐ろしい寒暖差

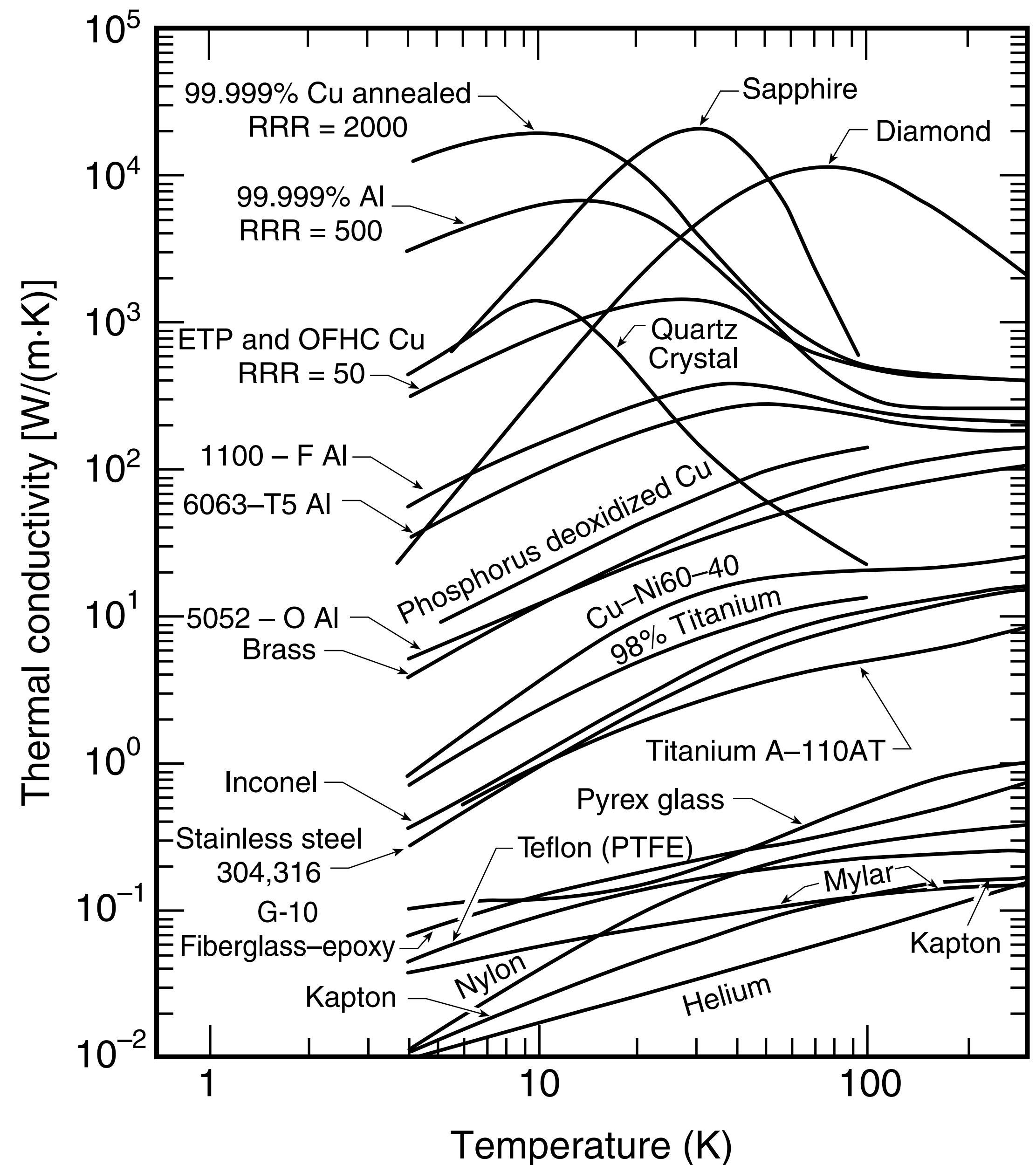
Conductive Heat



$$\dot{q}_{\text{cond}} = A/L \int_{T_1}^{T_2} \lambda(T) dT = A/L \left[\int_{4\text{ K}}^{T_2} \lambda(T) dT - \int_{4\text{ K}}^{T_1} \lambda(T) dT \right]$$

~10 K以上では電子が熱を伝えるので
ほぼ電気伝導度の同じ順番と考えて良い
それ以下ではフォノンによる伝導になる

異なる熱ステージの接続にはステンレスが
良く使われる。



Convecting Heat

流体的振る舞いするとき (高圧)

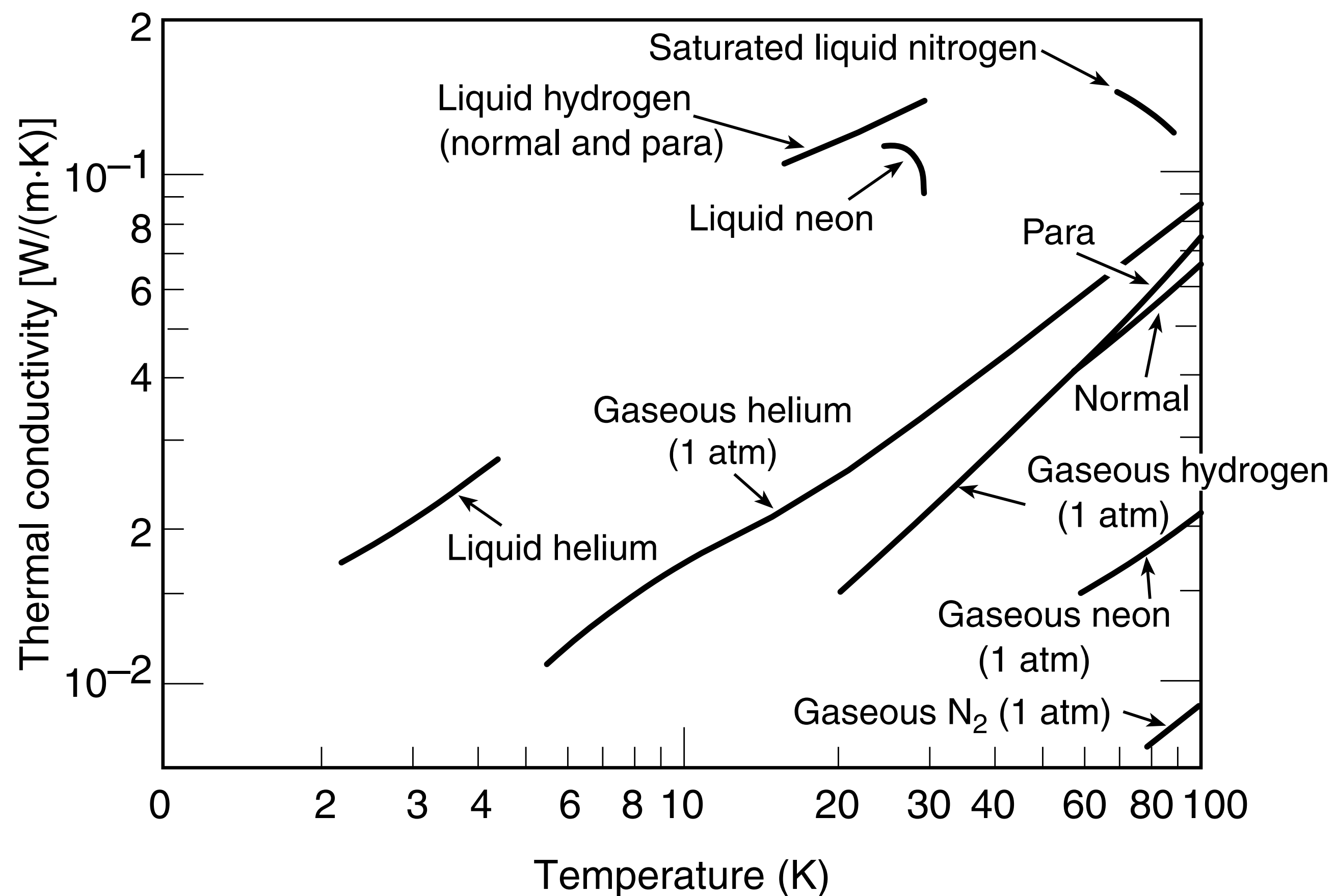
$$\dot{q}_{\text{gas}} = \bar{\lambda} A \Delta T / d$$

分子的振る舞いするとき (低圧)

$$\dot{q}_{\text{gas}} = k a_0 P A_i \Delta T, [\text{watts}]$$

希釈冷凍機は高真空中で動いている

ADMXは 10^{-8} Paくらい



Radiative Heat

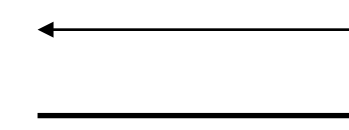
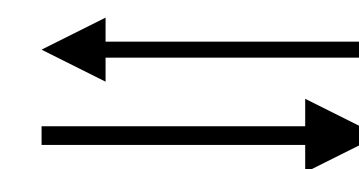
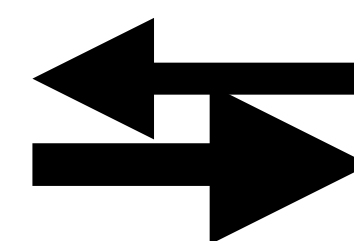
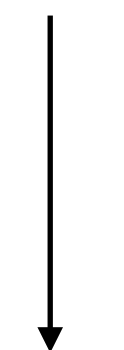
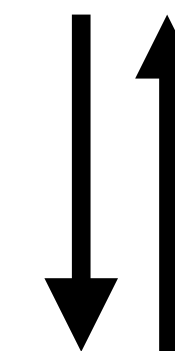
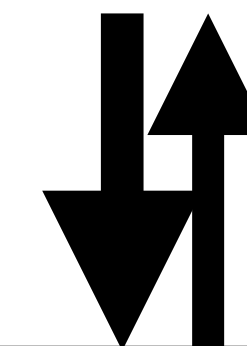
$$\dot{q}_{\text{rad}} = \sigma EA(T_2^4 - T_1^4)$$

A2.2 EMISSIVITY OF TECHNICAL MATERIALS AT A WAVELENGTH OF ABOUT 10 μm (ROOM TEMPERATURE) (SEC. 2.4)

Material	Emissivity		
	Polished	Highly oxidized	Common condition
<i>Metallic</i>			
Ag	0.01		
Cu	0.02	0.6	
Au	0.02		
Al	0.03	0.3	
Brass	0.03	0.6	
Soft-solder			0.03
Nb, crystalline, bulk			0.04
Lead	0.05		
Ta	0.06		
Ni	0.06		
Cr	0.07		
Stainless steel			0.07
Ti			0.09
Tin (gray), single crystal			0.6
<i>Nonmetallic</i>			
IMI 7031 varnish			0.9
Phenolic lacquer			0.9
Plastic tape			0.9
Glass			0.9



バッフル



シールド

冷たい

実際の様子

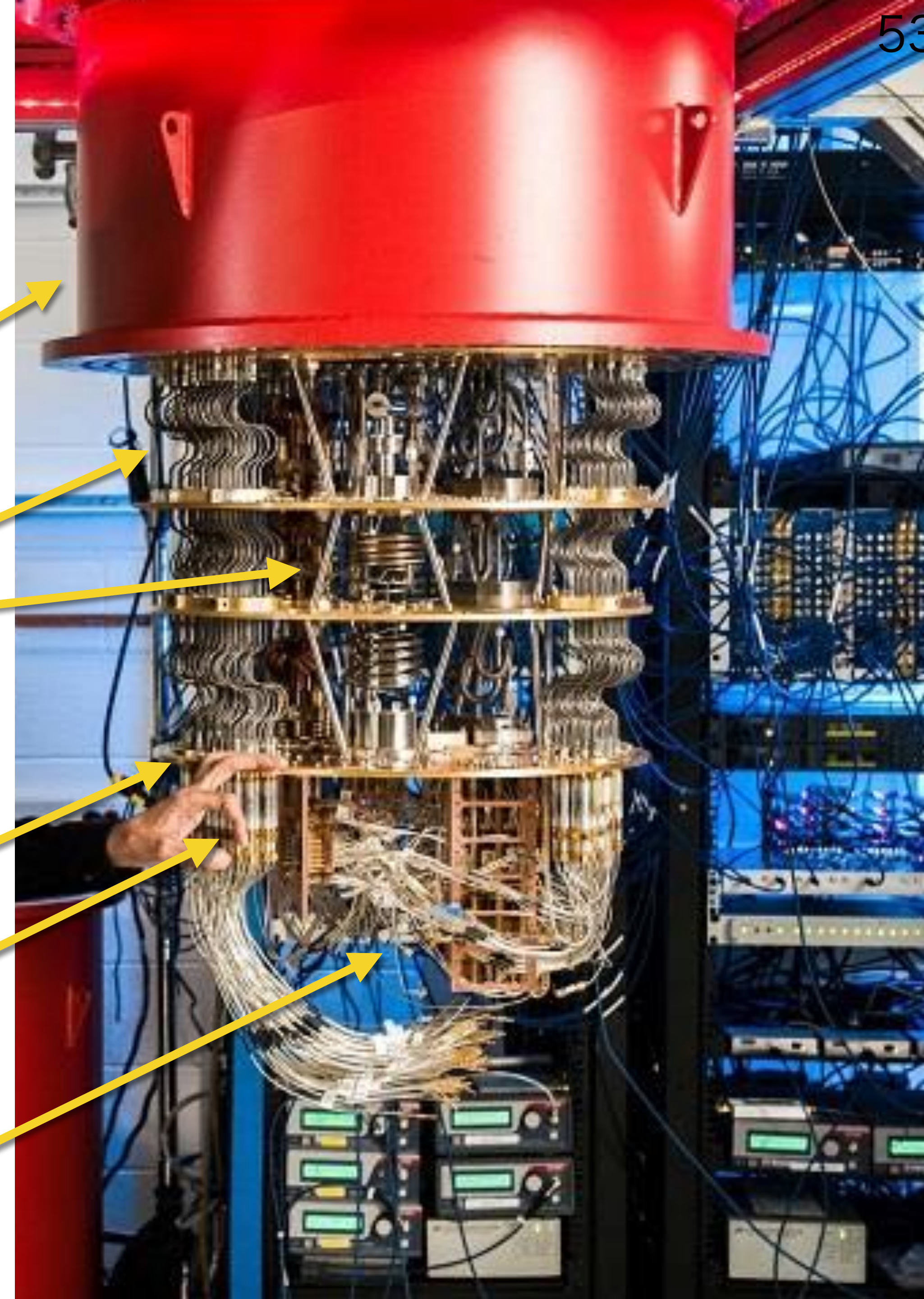
radiative shields

ステンレス
& 長い (くねくねさせる)

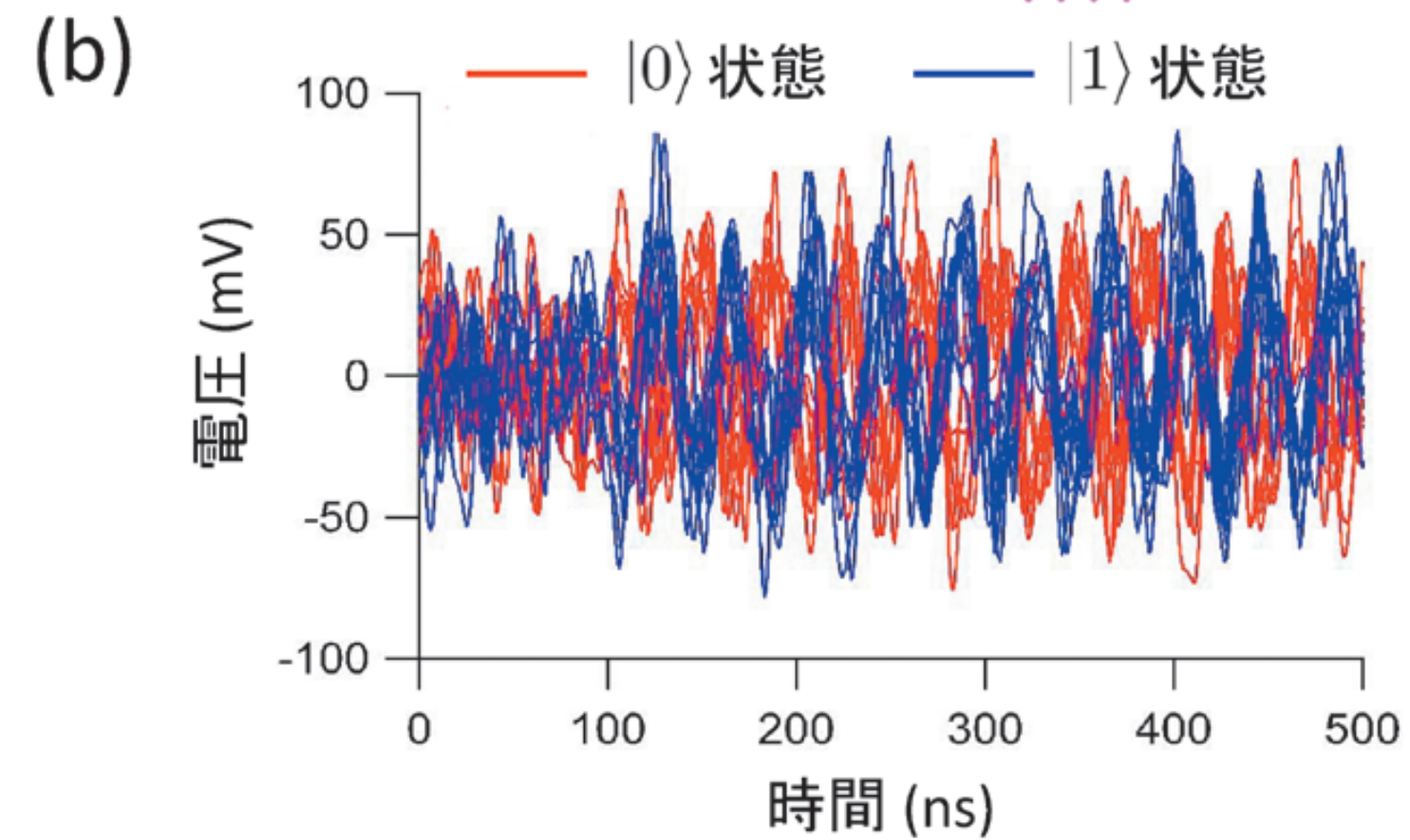
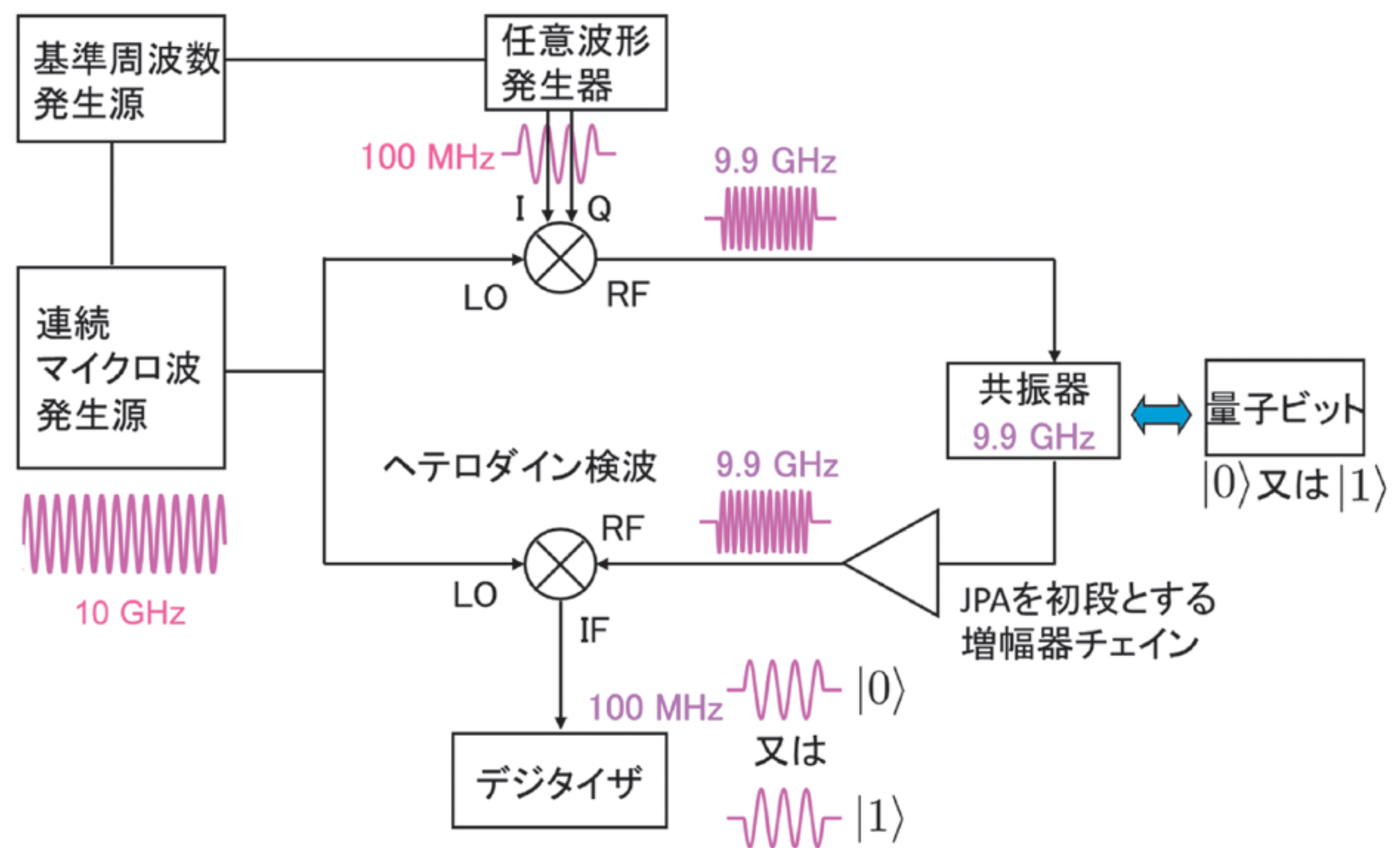
金メッキ or 銅

フィルター

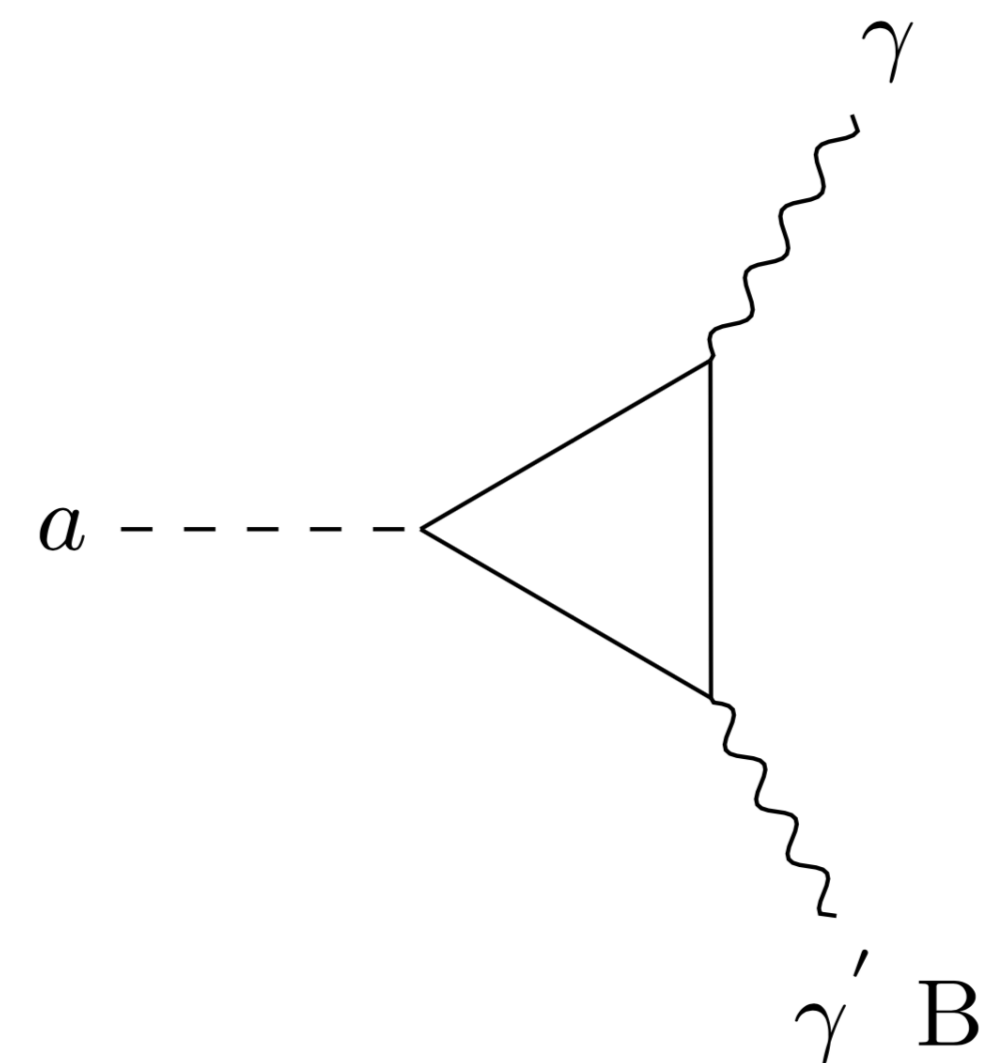
信号線は超伝導



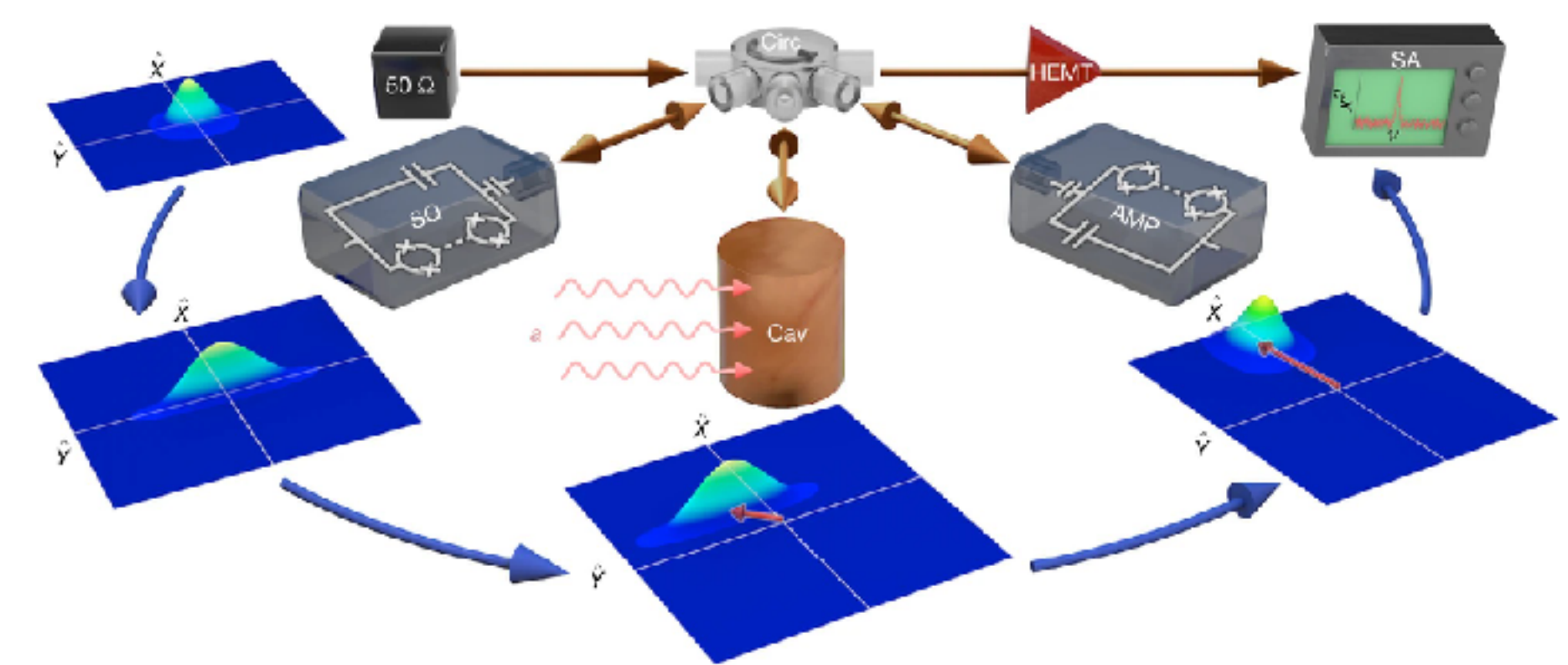
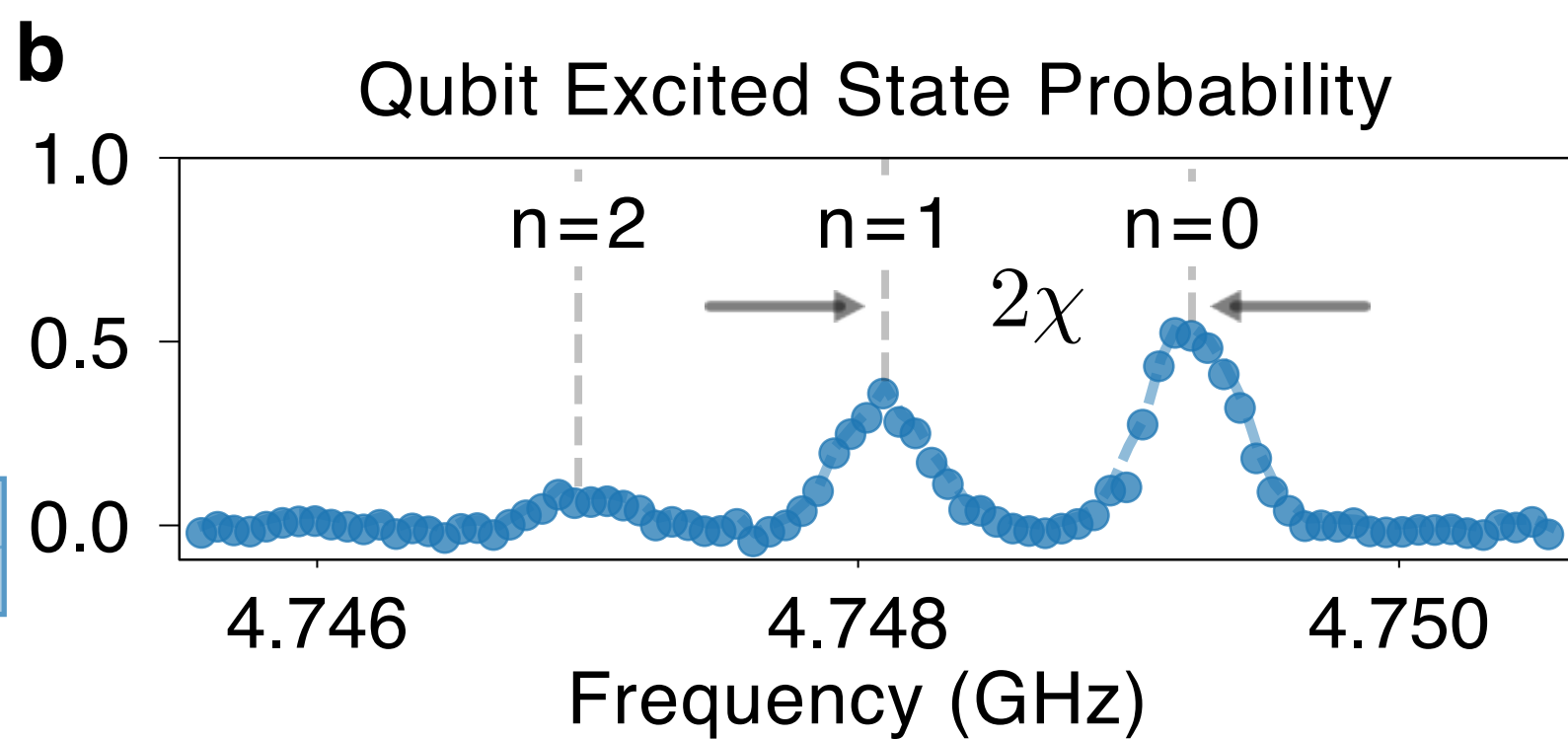
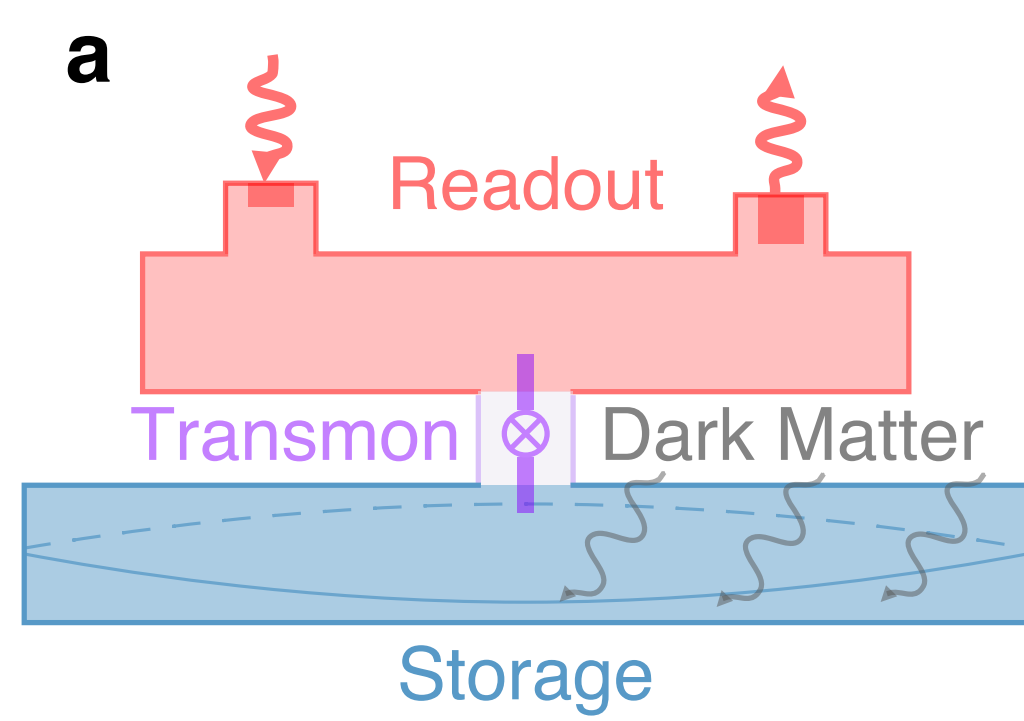
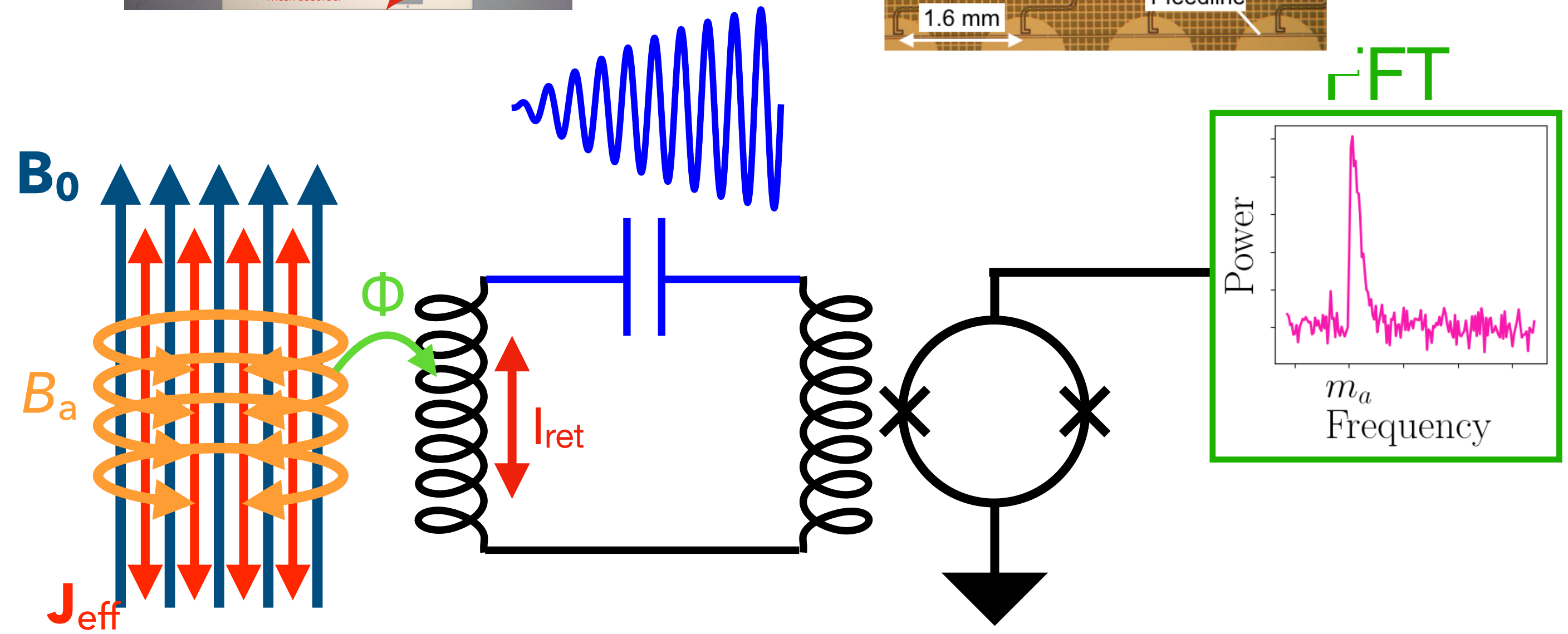
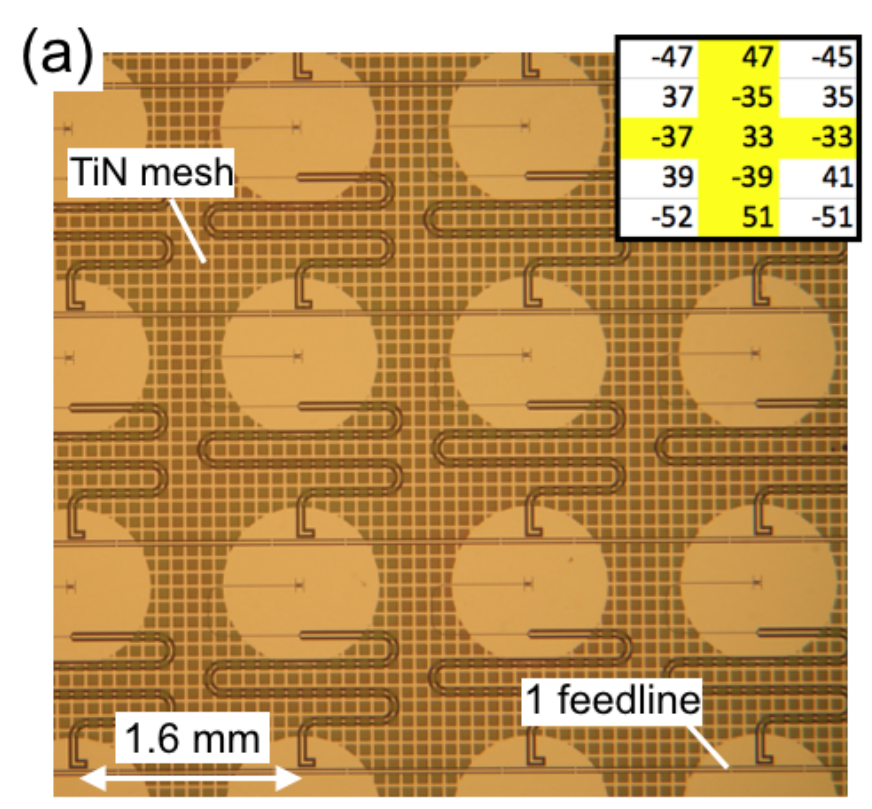
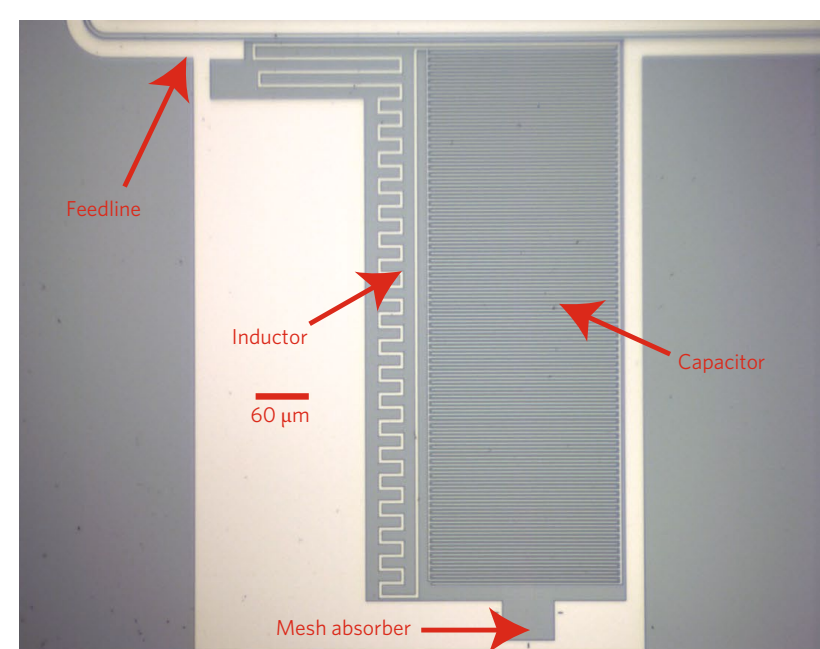
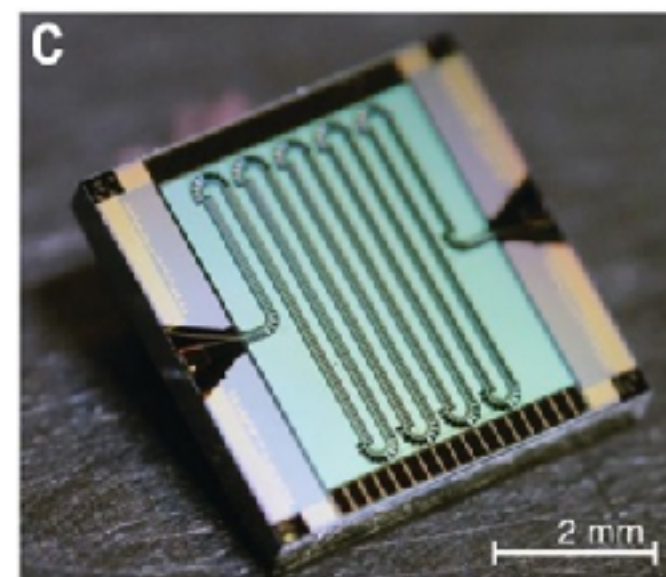
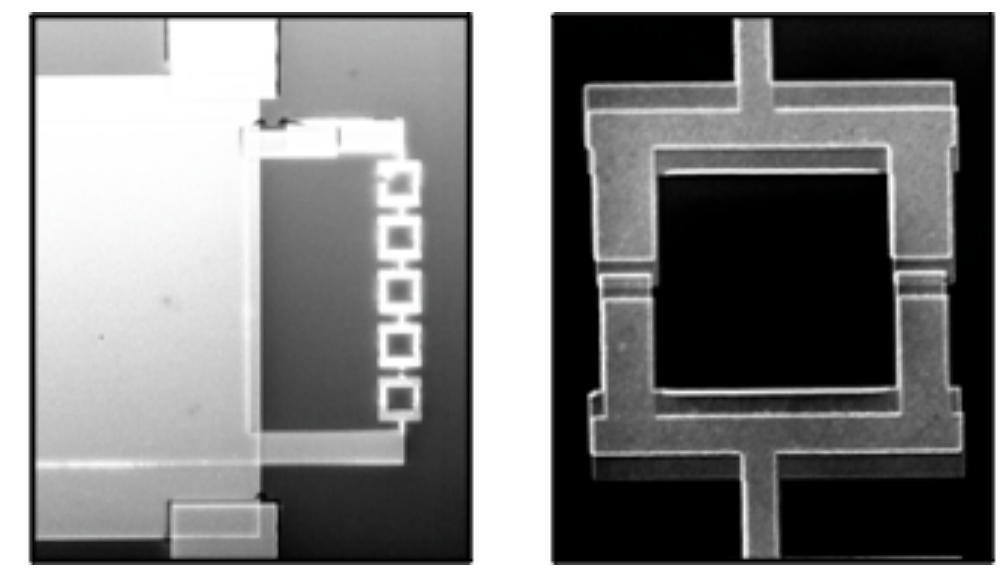
測定系



物理への応用例

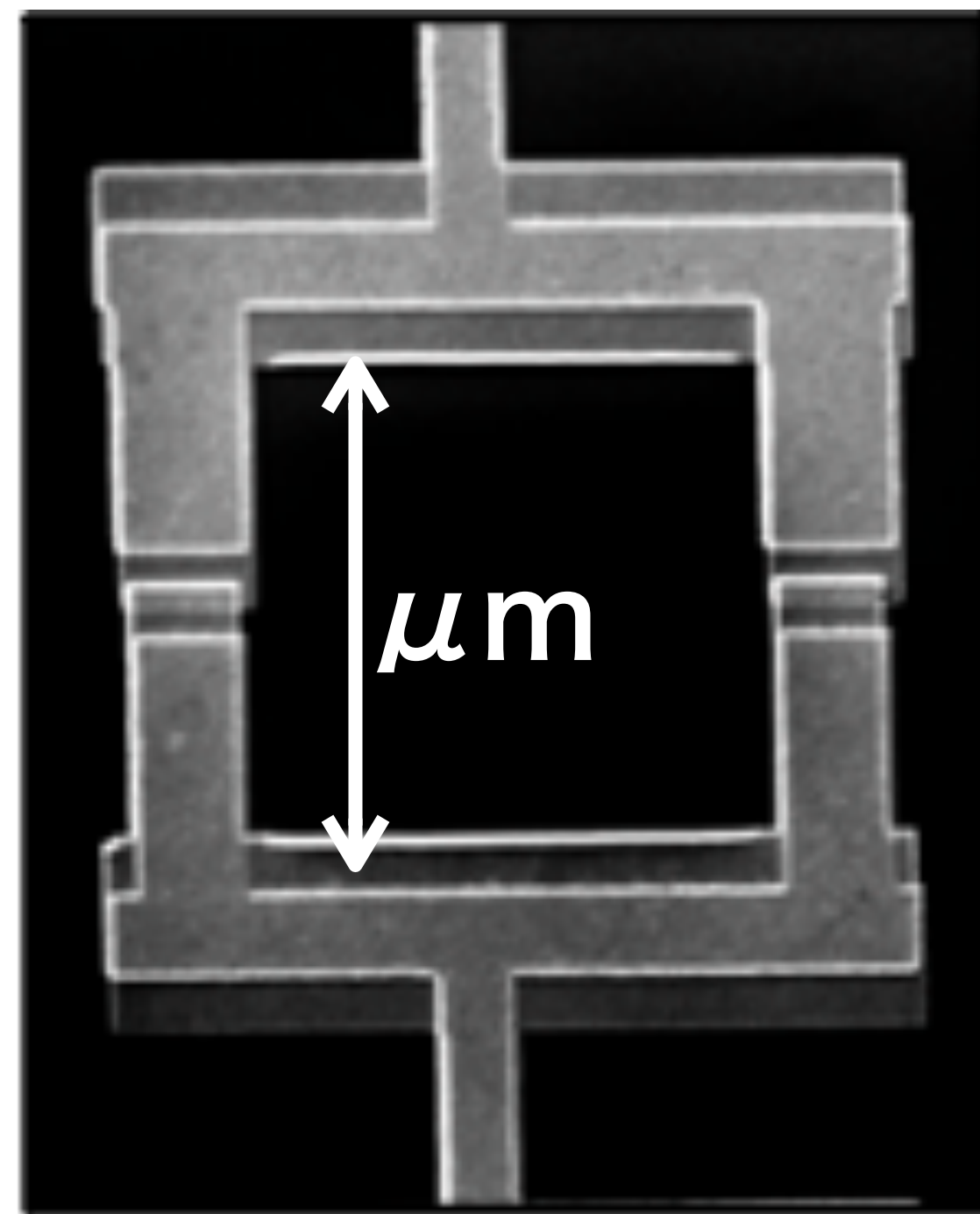


大量にある



こつ？

重大な弱点: 量子デバイスは有効体積が小さすぎる



例: SQUIDは超高感度磁場センサーだが
そのループに入る磁束にしか感度がない。

だいたいの素粒子実験は有効体積が物を言う

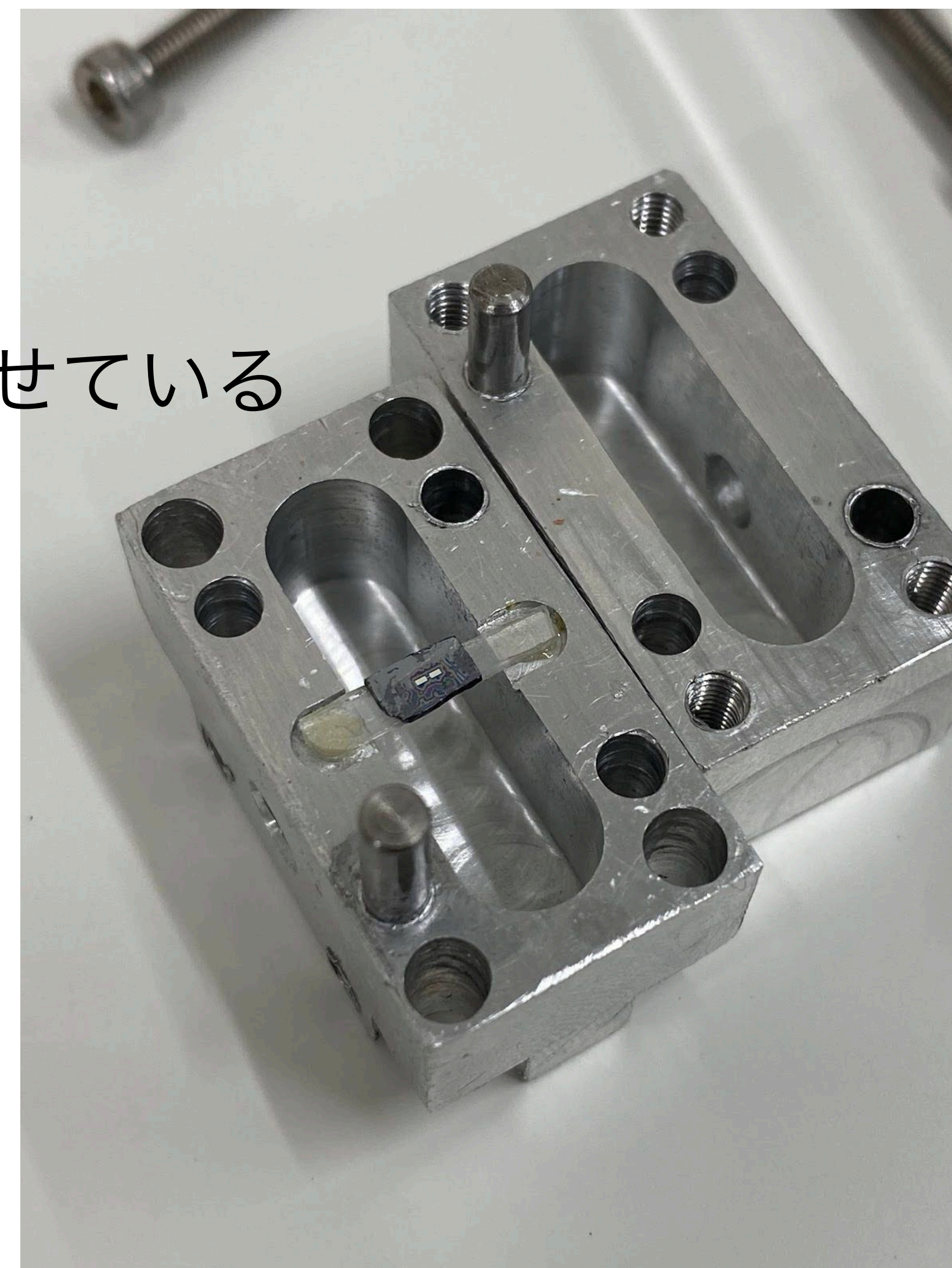
→ **マクロなスケールの応答を反映させる必要がある**

(もちろん小さくても良い実験もある)

共振器はマクロな世界とミクロな世界をつなぐ



既にcmスケール
 10^4 倍有効体積を増やしている



ジョセフ
ソン接合

